

# Thermally Managed Z-scan Measurements of Amorphous TiO<sub>2</sub> Films

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# Outline

Introduction: amorphous  $\text{TiO}_2$  films

Standard z-scan

Thermally managed z-scan

Conclusions and Discussion

# Introduction

## Titanium Dioxide

Wide Bandgap:

3.2 eV (387 nm)

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High index:

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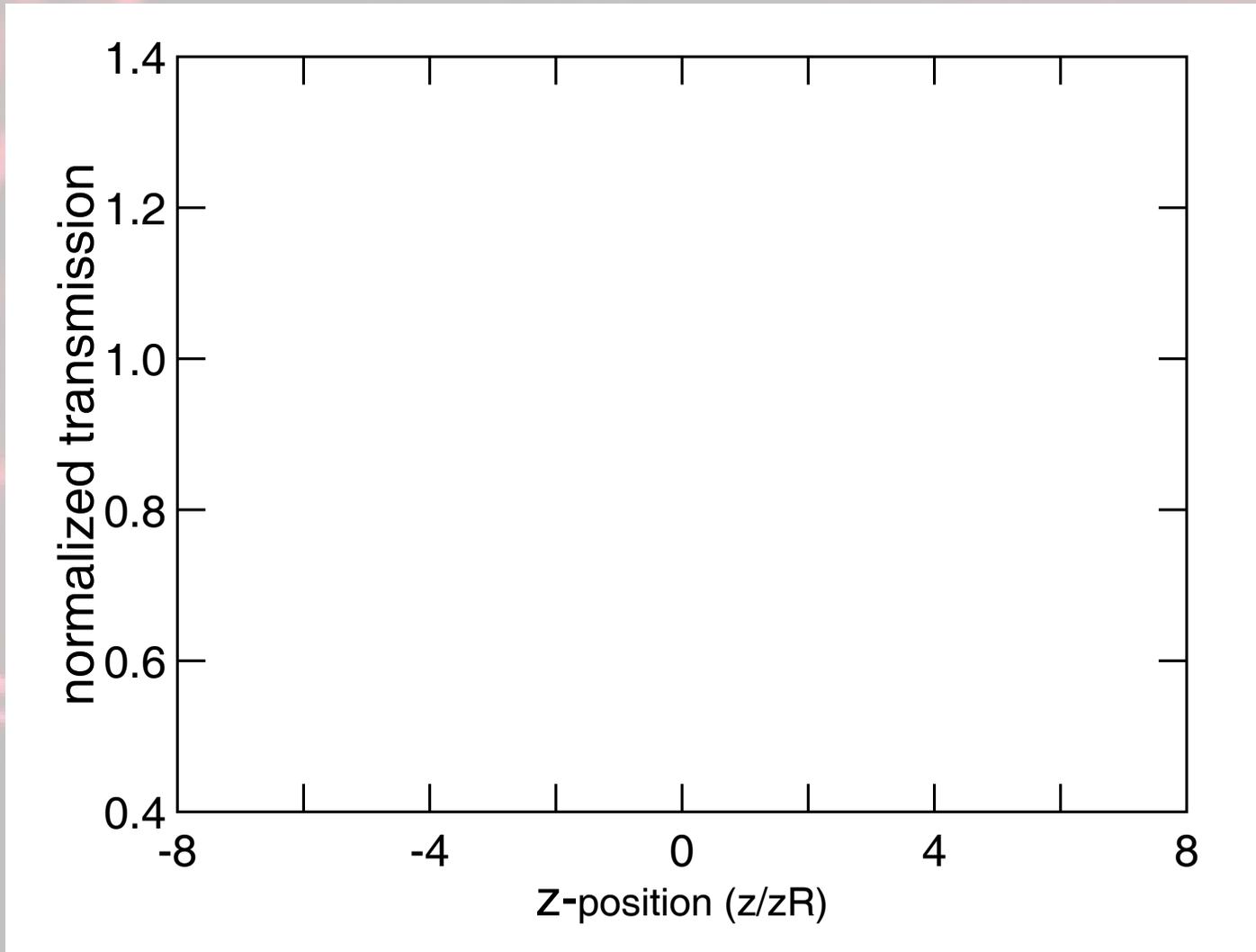
Low two-photon absorption

# Introduction

What is the nonlinearity for  $\text{TiO}_2$  near 800 nm?

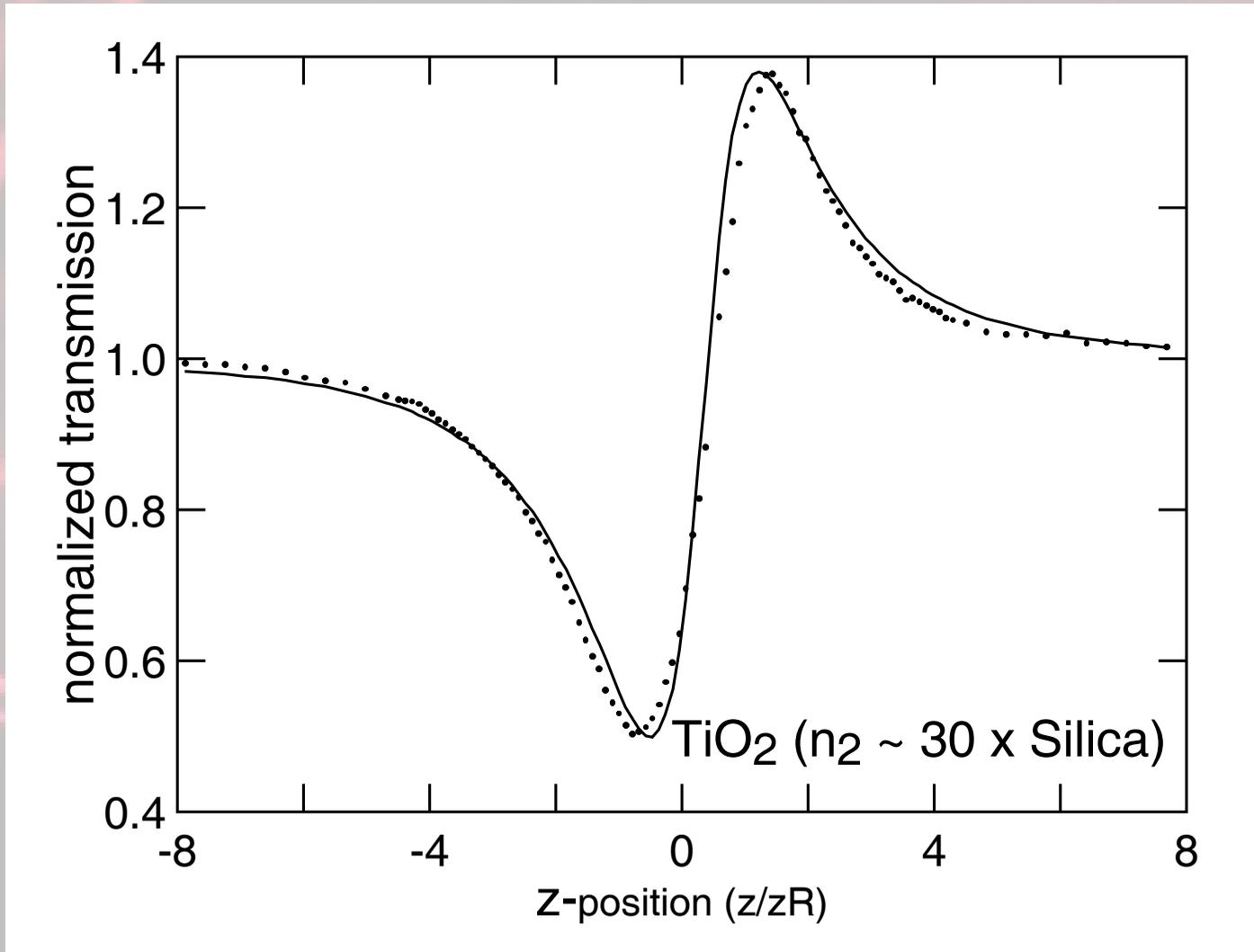
# Introduction

## Z-Scan of Bulk Rutile



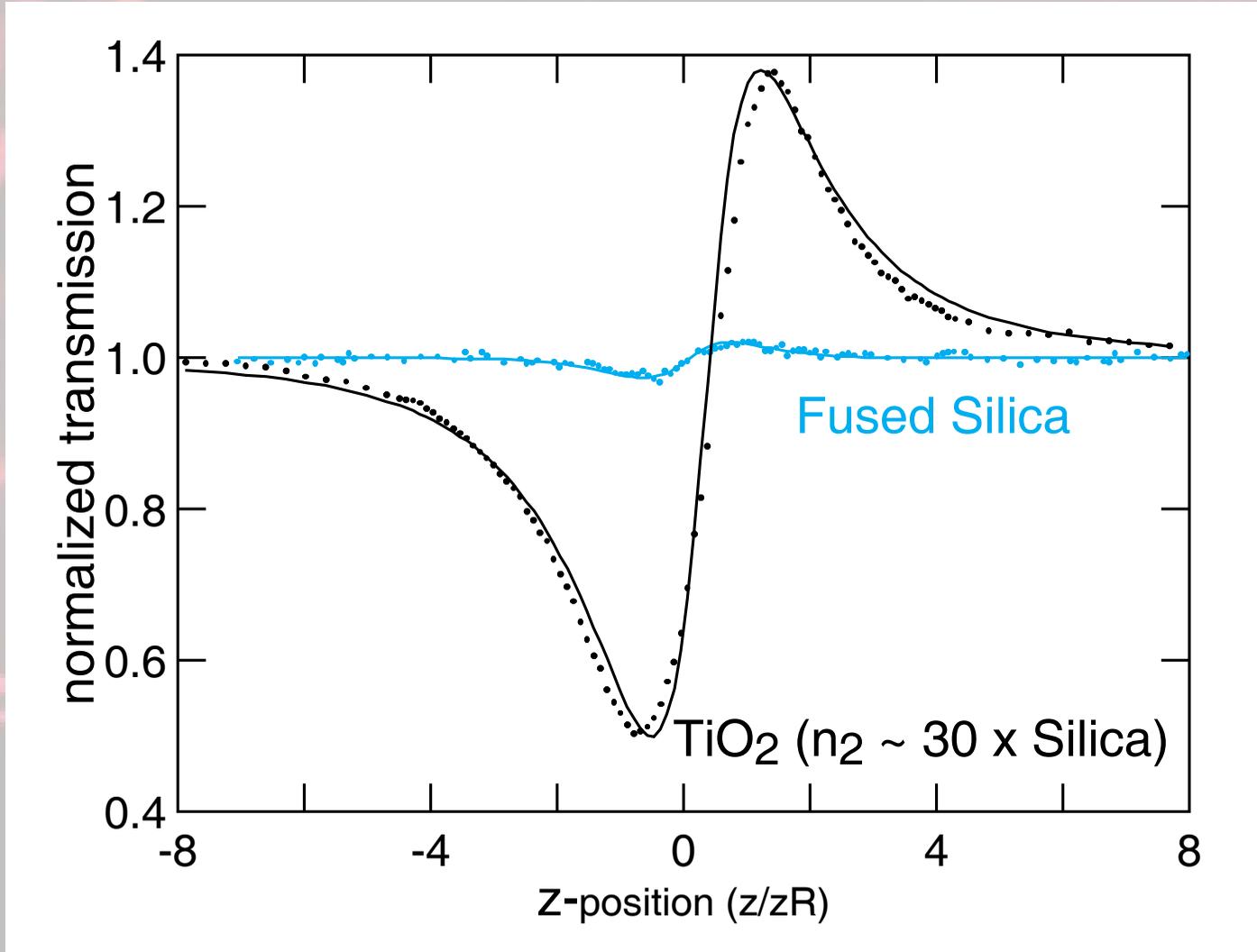
# Introduction

## Z-Scan of Bulk Rutile



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## Z-Scan of Bulk Rutile



# Introduction

How should we optimize our thin films?

# Introduction

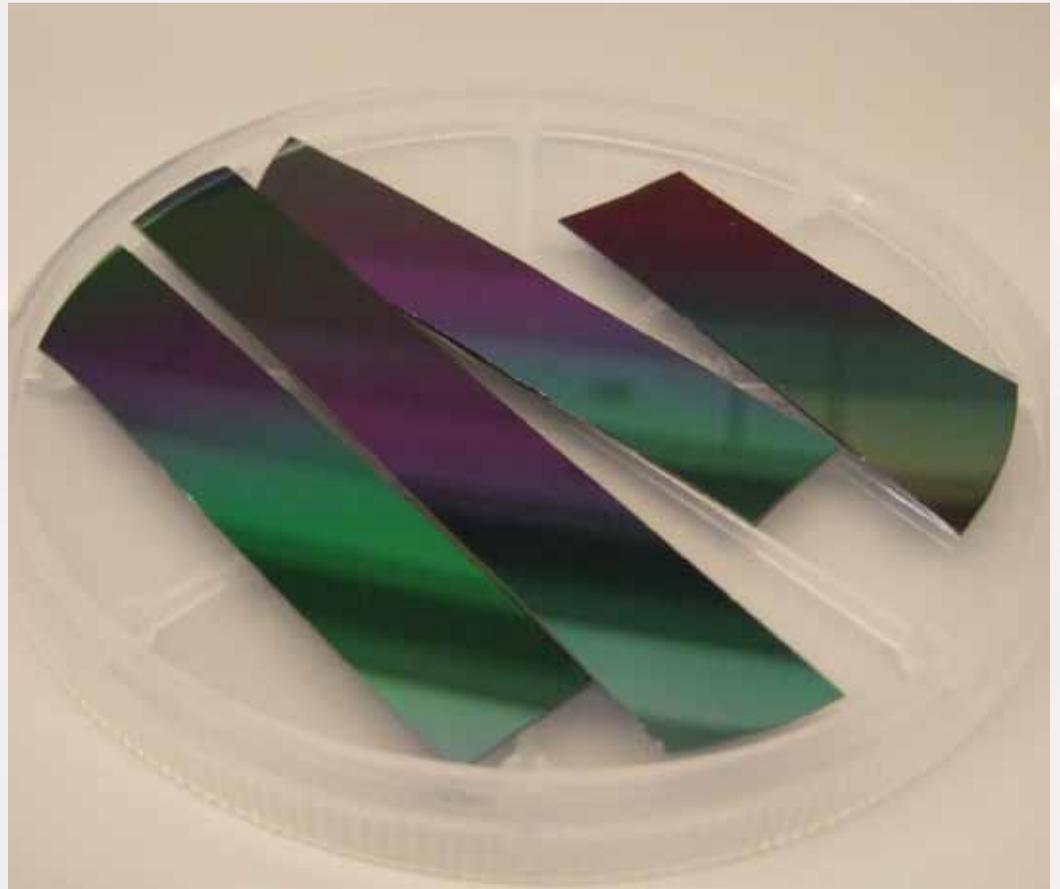
## Optimization of thin films

### Crystalline Phases:

Amorphous

Anatase

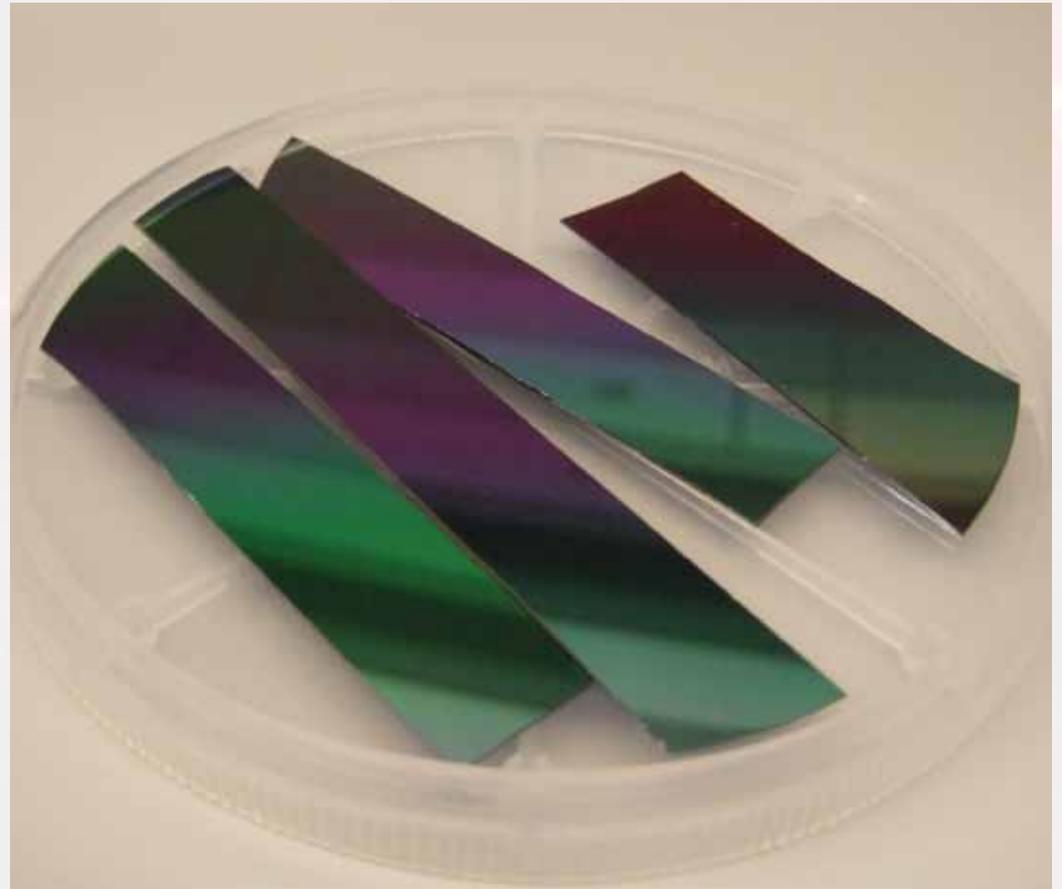
Rutile



# Introduction

Optimization of thin films

Refractive Index



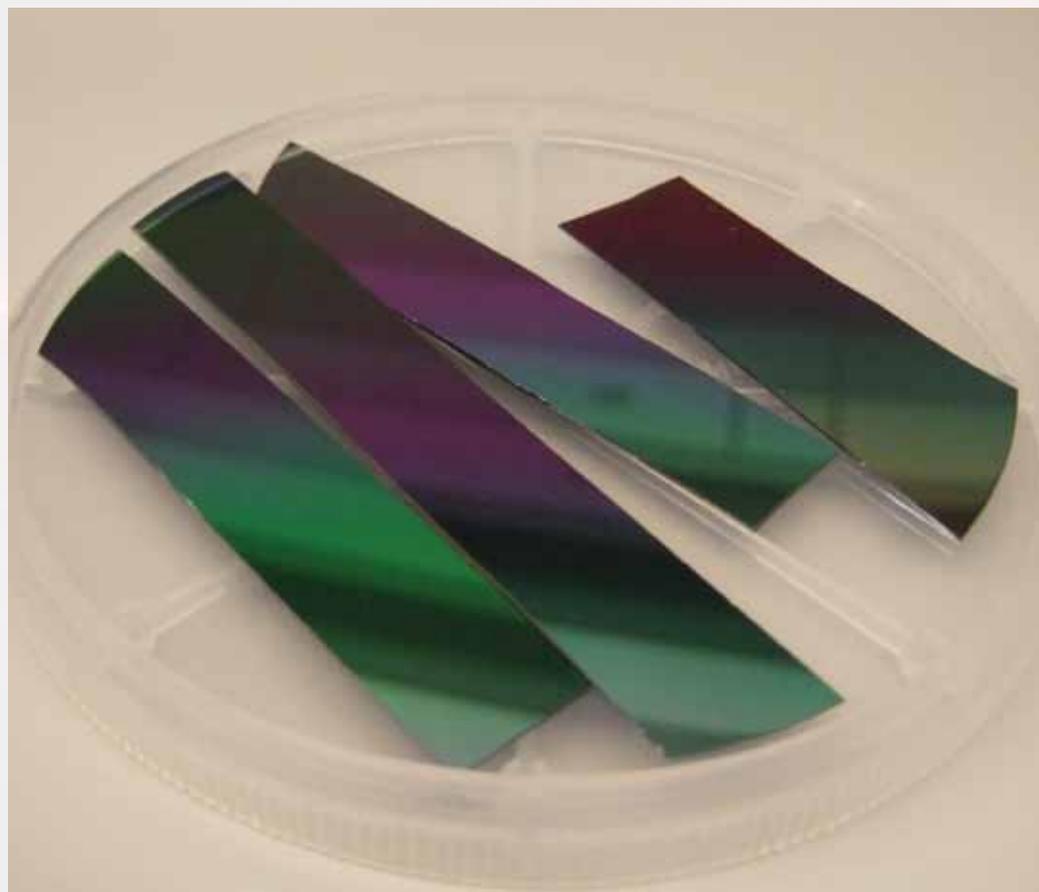
# Introduction

## Optimization of thin films

### Refractive Index

Amorphous: 2.35

Anatase: 2.45



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## Optimization of thin films

### Refractive Index

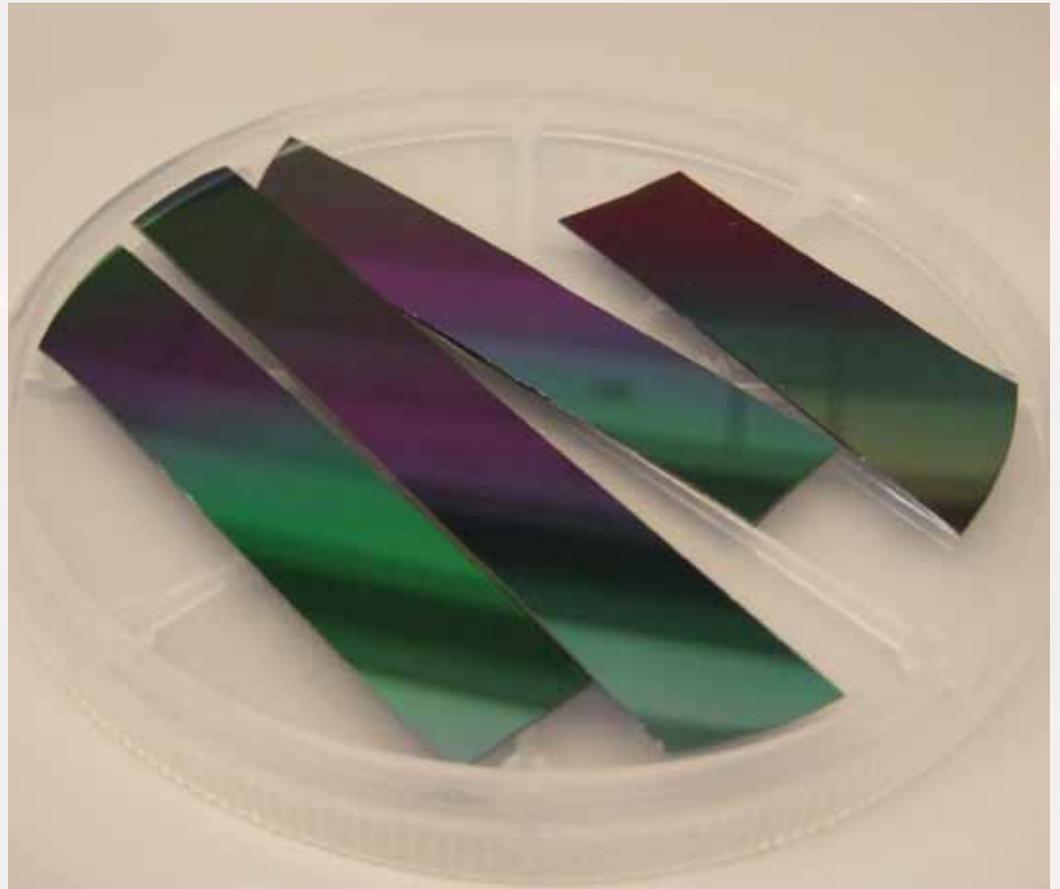
Amorphous: 2.35

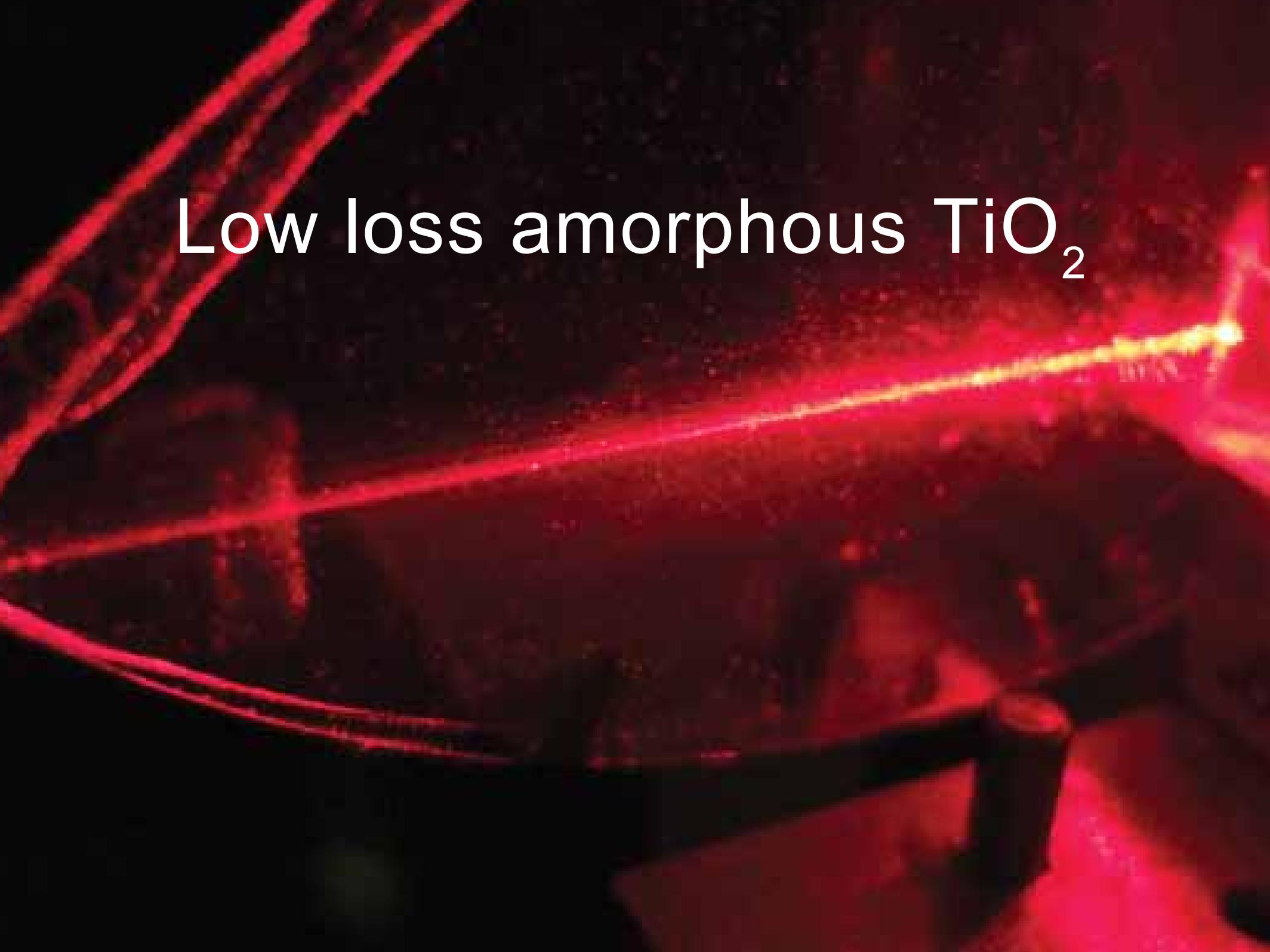
Anatase: 2.45

### Guiding Losses

Amorphous: 1 dB/cm

Anatase: 5 dB/cm





Low loss amorphous  $\text{TiO}_2$

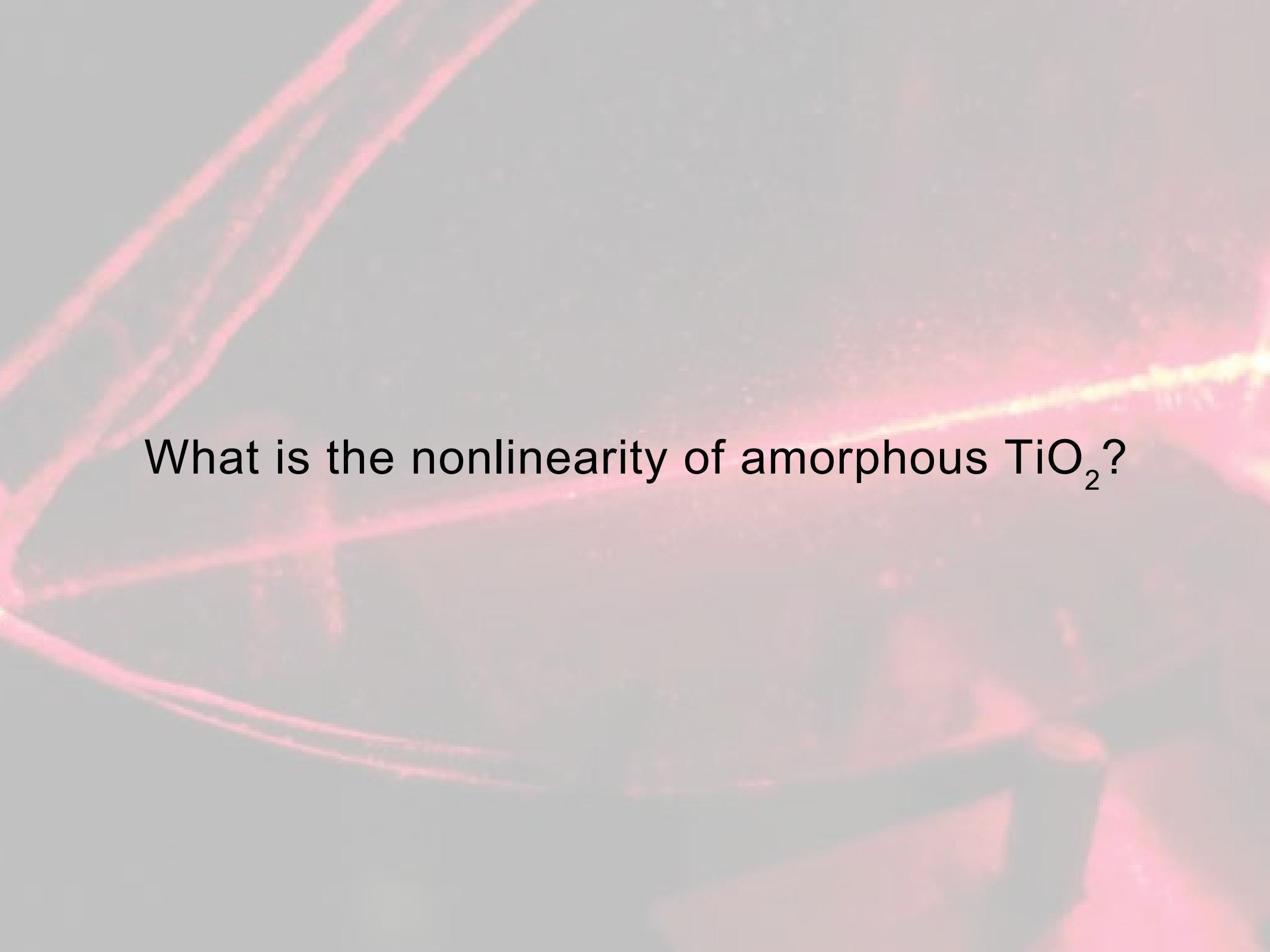
# Low loss amorphous TiO<sub>2</sub>

Deposition Method: Reactive Sputtering

Thickness: 2.2 micron

Substrate: Fused Silica (500 micron)

Guiding Losses: ~1 dB/cm



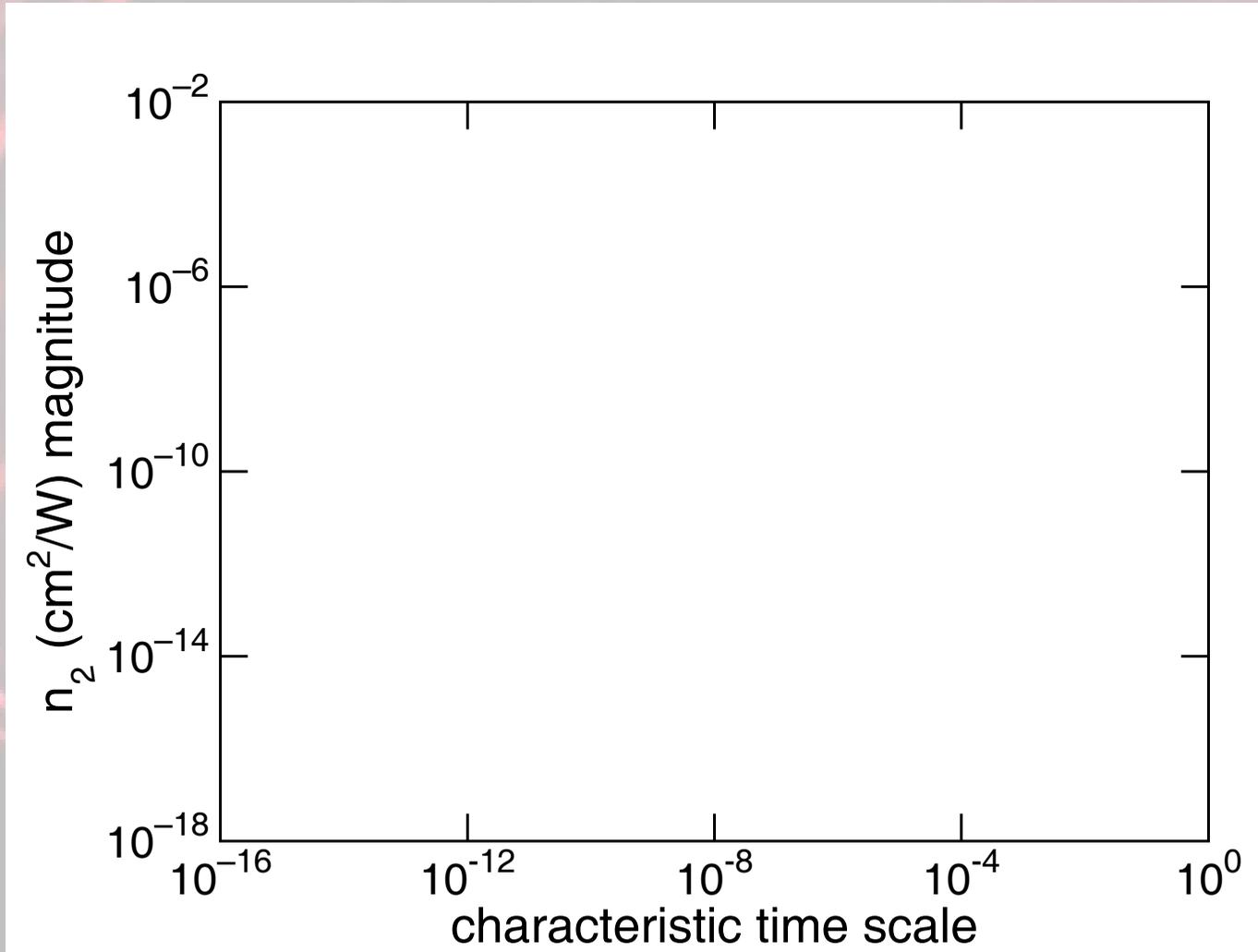
What is the nonlinearity of amorphous  $\text{TiO}_2$ ?

What is the nonlinearity of amorphous  $\text{TiO}_2$ ?

Are there thermal effects?

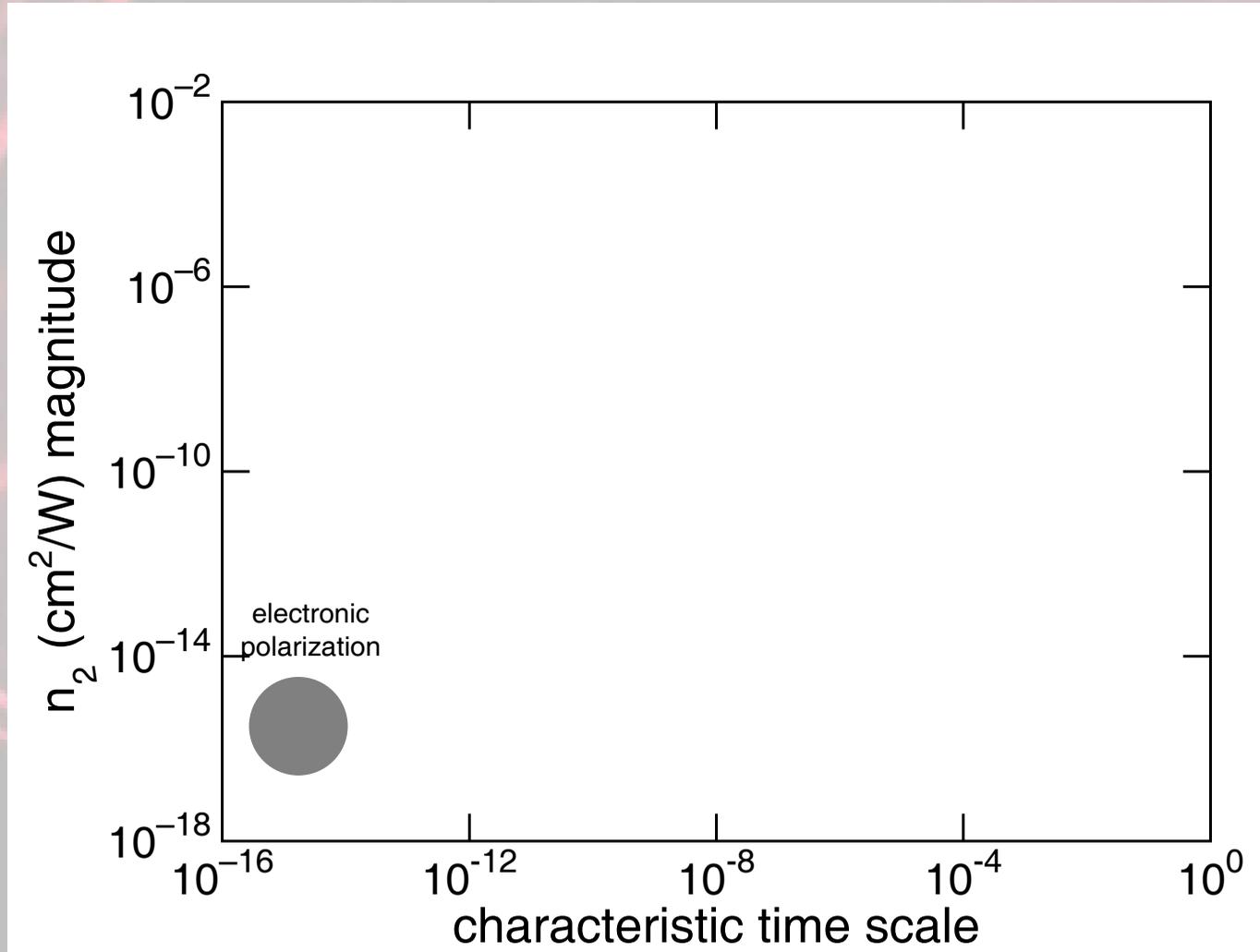
# Introduction

## Typical nonlinear time scales



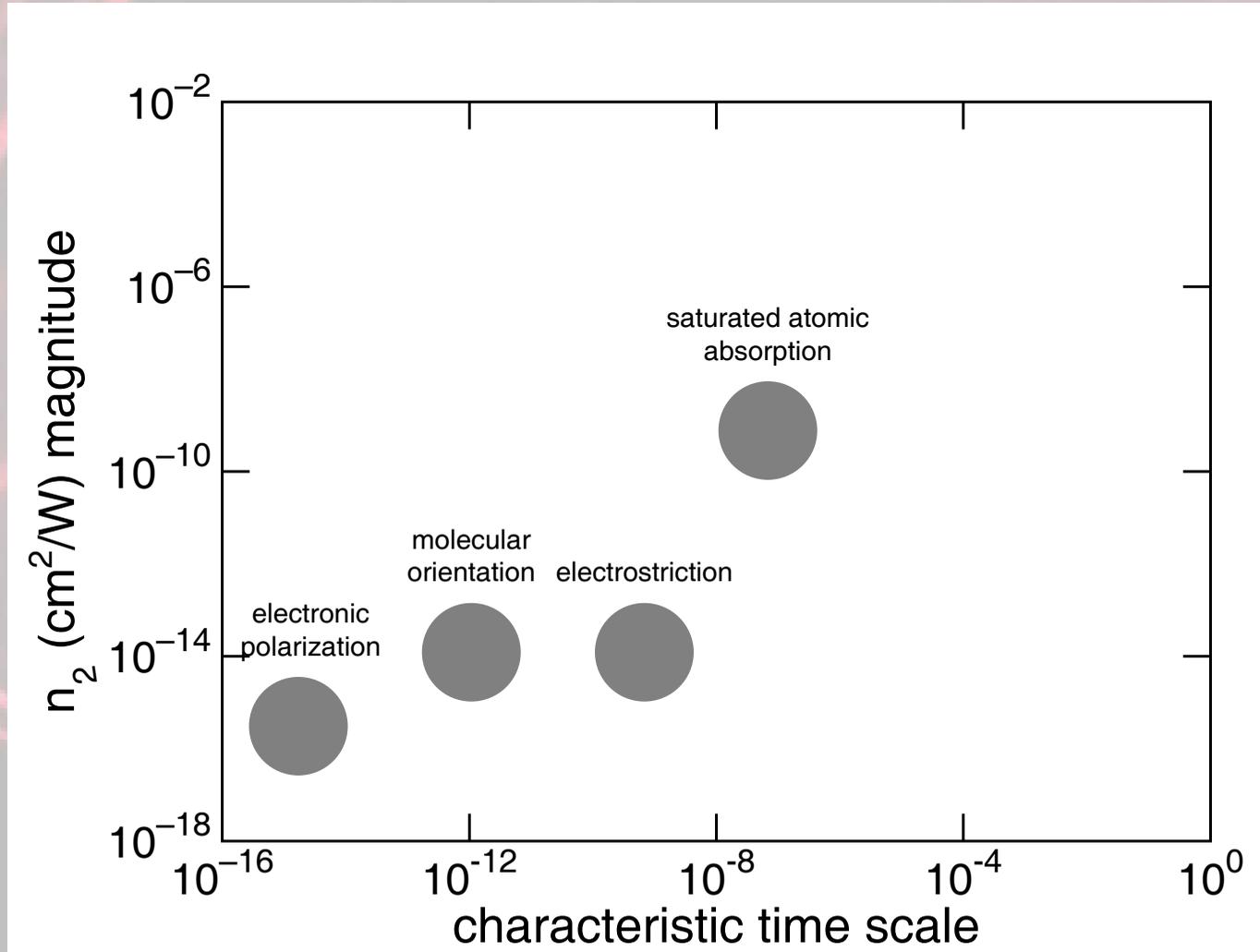
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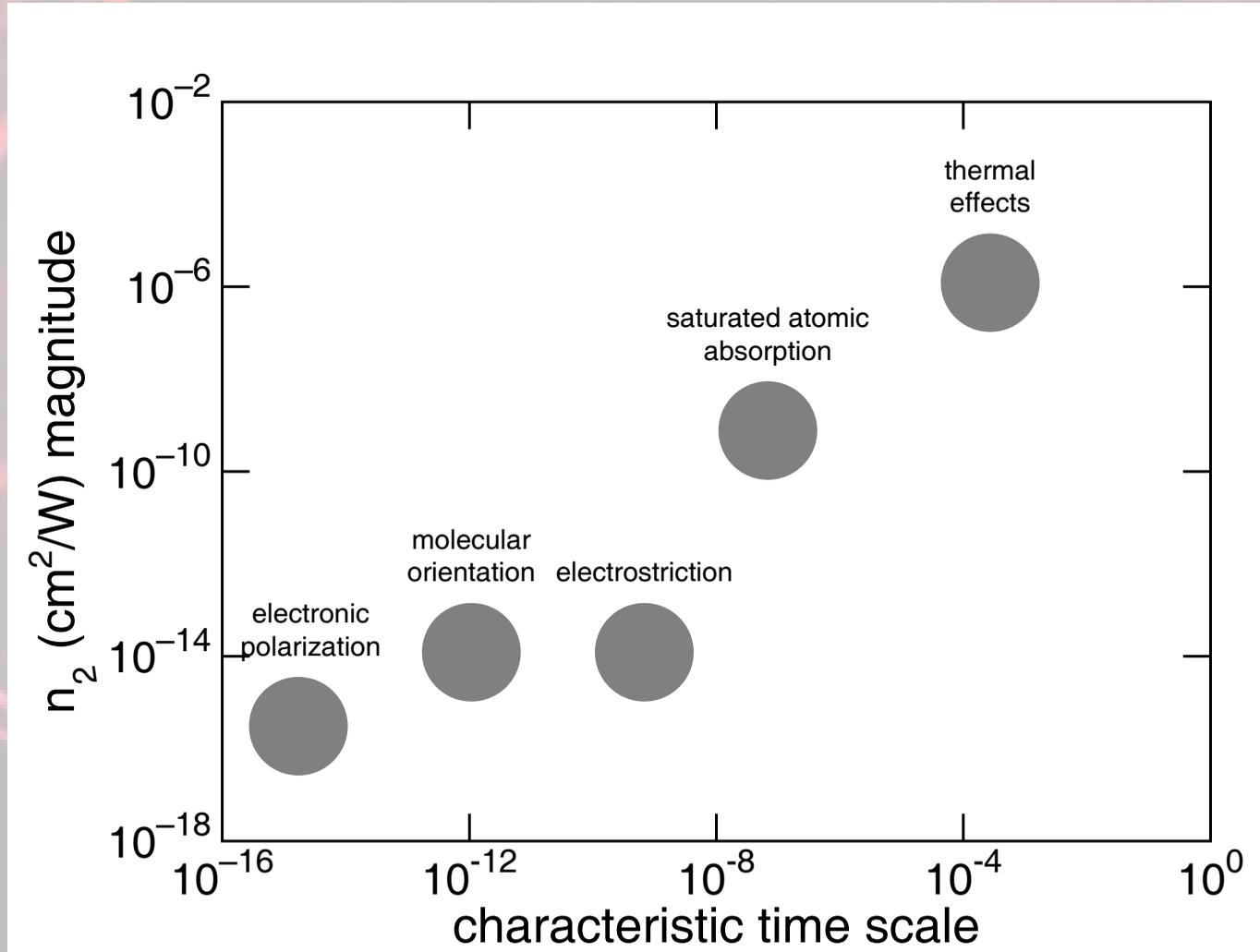
# Introduction

## Typical nonlinear time scales



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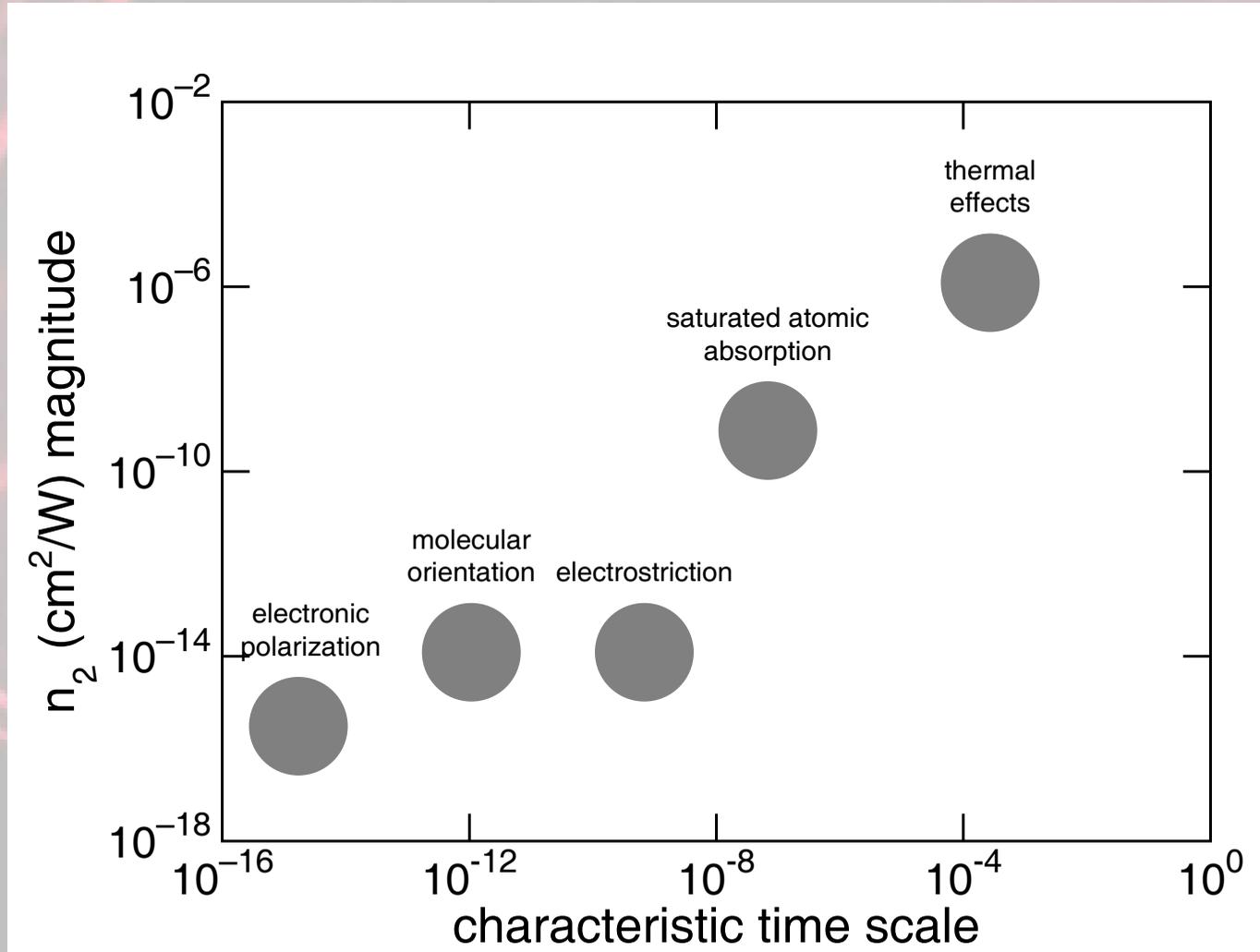
# Introduction

## Laser Specifications

Type:	Amplified Ti:Sapphire (CPA)
Center $\lambda$ :	800 nm
Pulse Duration:	100 fs
Repetition Rate:	10kHz - 250kHz

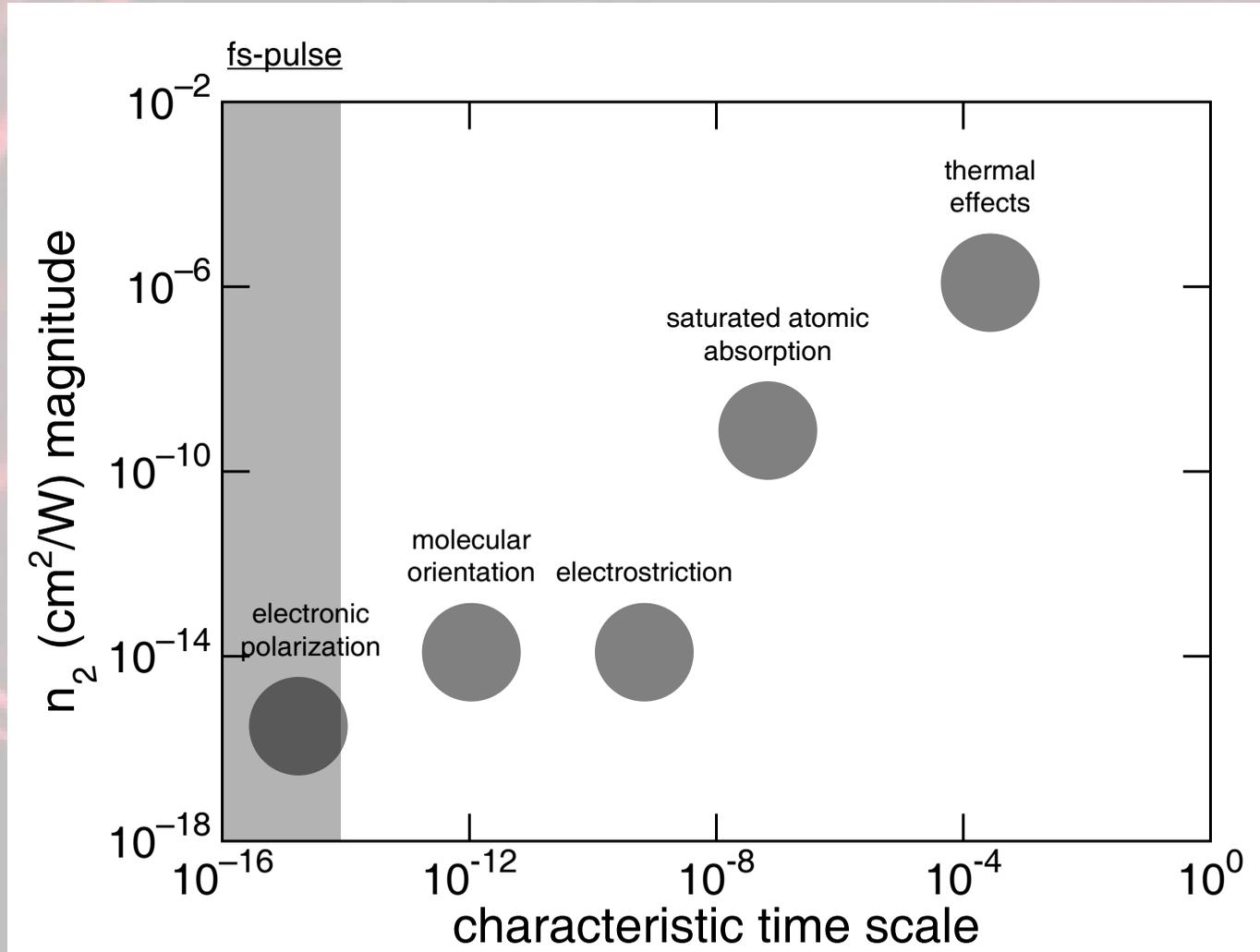
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## Typical nonlinear time scales



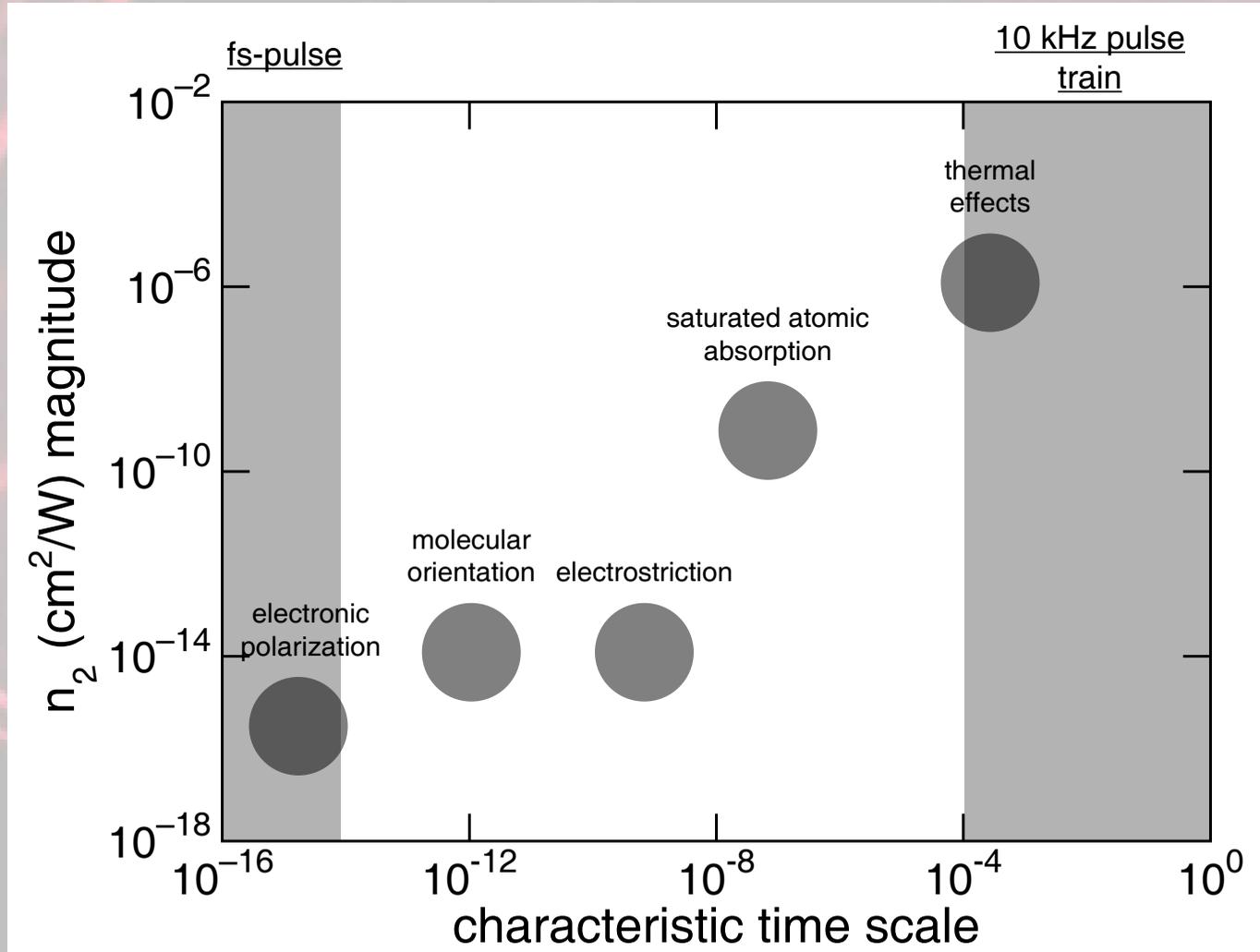
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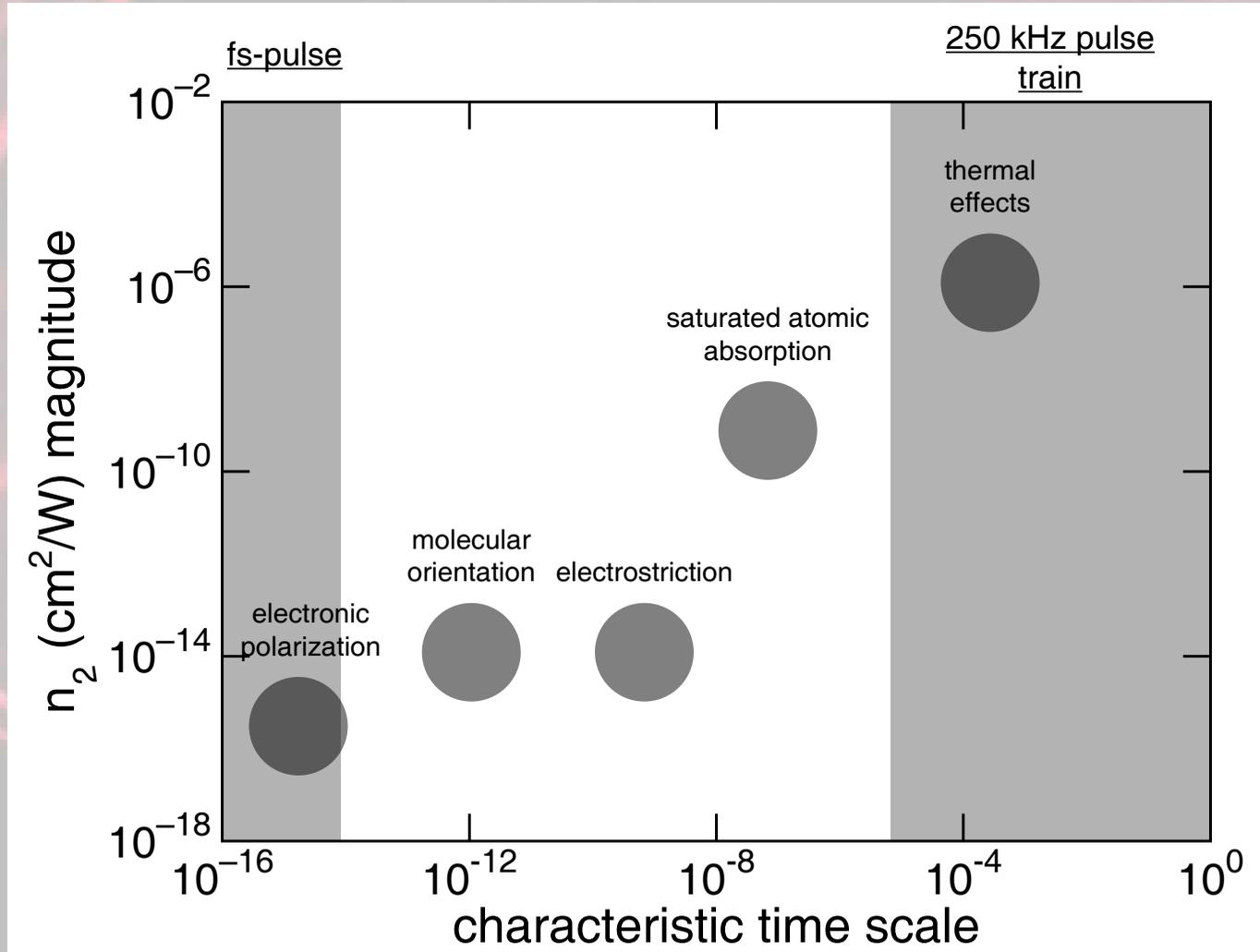
# Introduction

## Typical nonlinear time scales



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# Outline

Introduction: amorphous  $\text{TiO}_2$  films

Standard z-scan

Thermally managed z-scan

Conclusions and Discussion

# Standard z-scan

## Laser Parameters

$w_0$  (measured):      37 micron

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zR (from fitting):	2.1 mm
Approximate M <sup>2</sup> :	1.8

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## Laser Parameters

w0 (measured):	37 micron
zR (from fitting):	2.1 mm
Approximate M <sup>2</sup> :	1.8
Repetition Rate:	10 kHz
Pulse Duration:	100 fs
Max Power:	18 mW
Max Fluence:	0.08 J/cm <sup>2</sup>
S parameter:	0.016

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What power should we use?

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Reported Damage Threshold:  $0.55 \text{ J/cm}^2$

Yao, J. et al. Thin Solid Films 516, 1237-1241 (2008).

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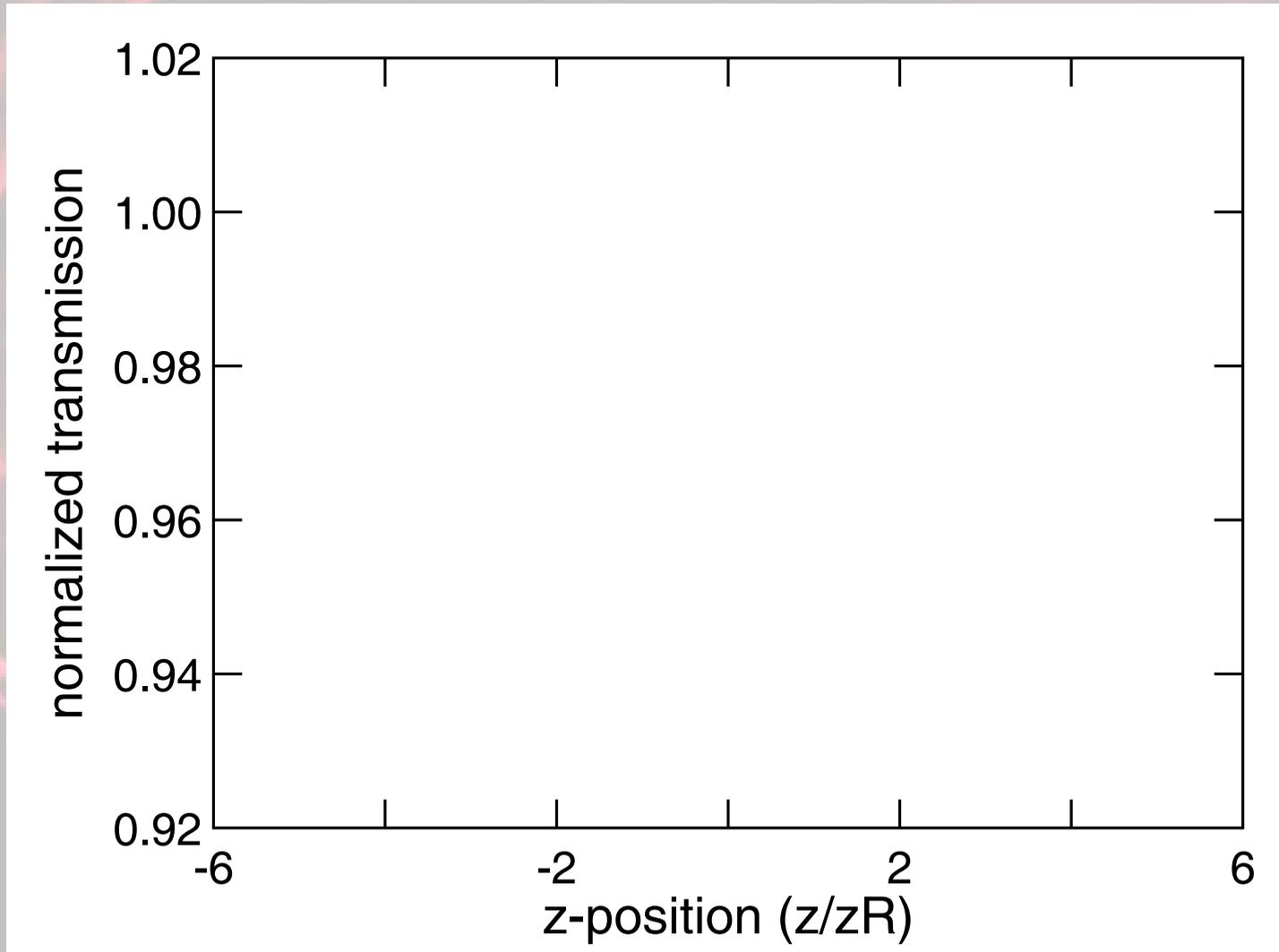
Our Maximum Fluence:  $0.08 \text{ J/cm}^2$

Low Power Used:  $0.002 \text{ J/cm}^2$

Yao, J. et al. Thin Solid Films 516, 1237-1241 (2008).

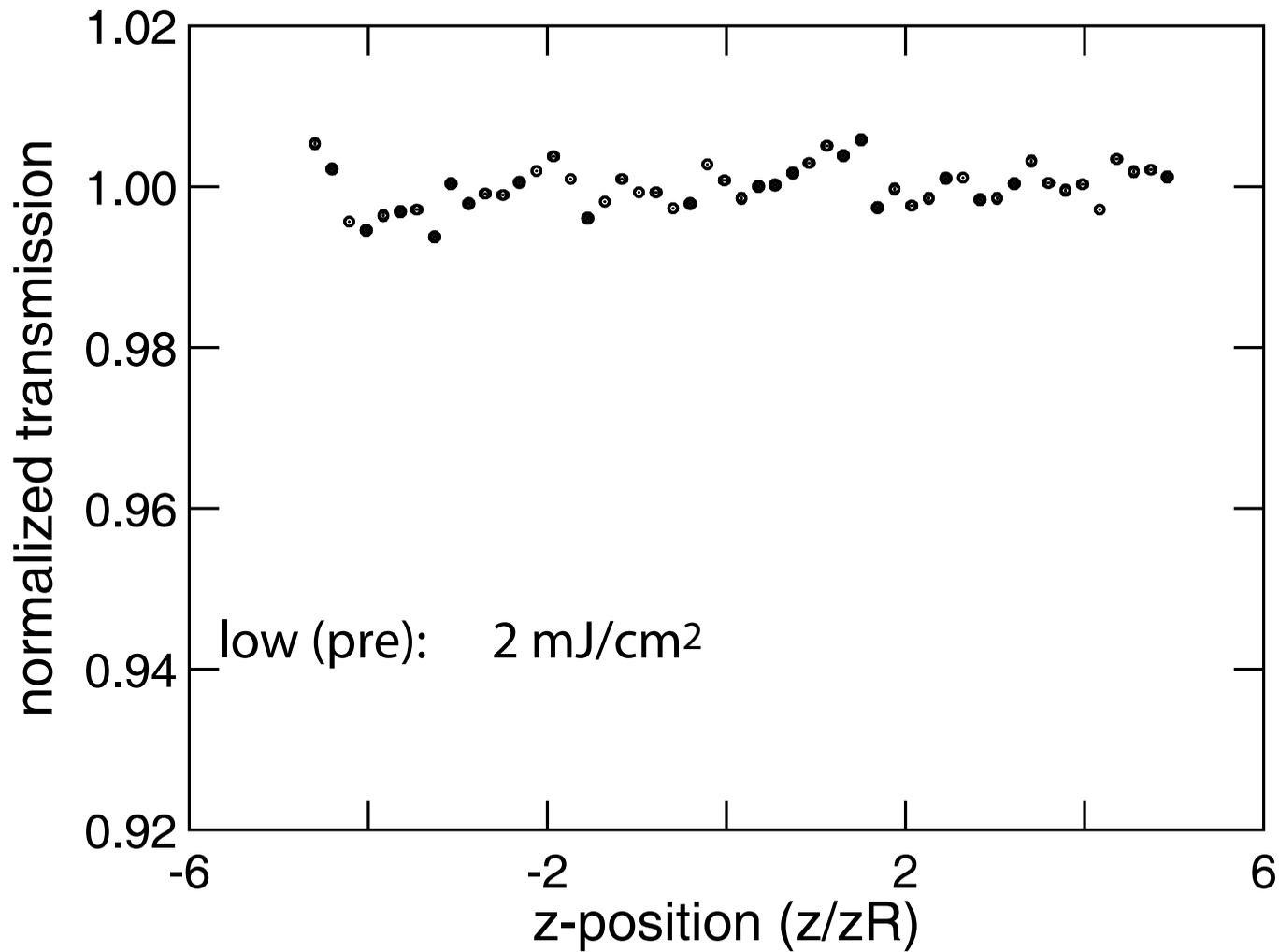
# Standard z-scan

Open Aperture



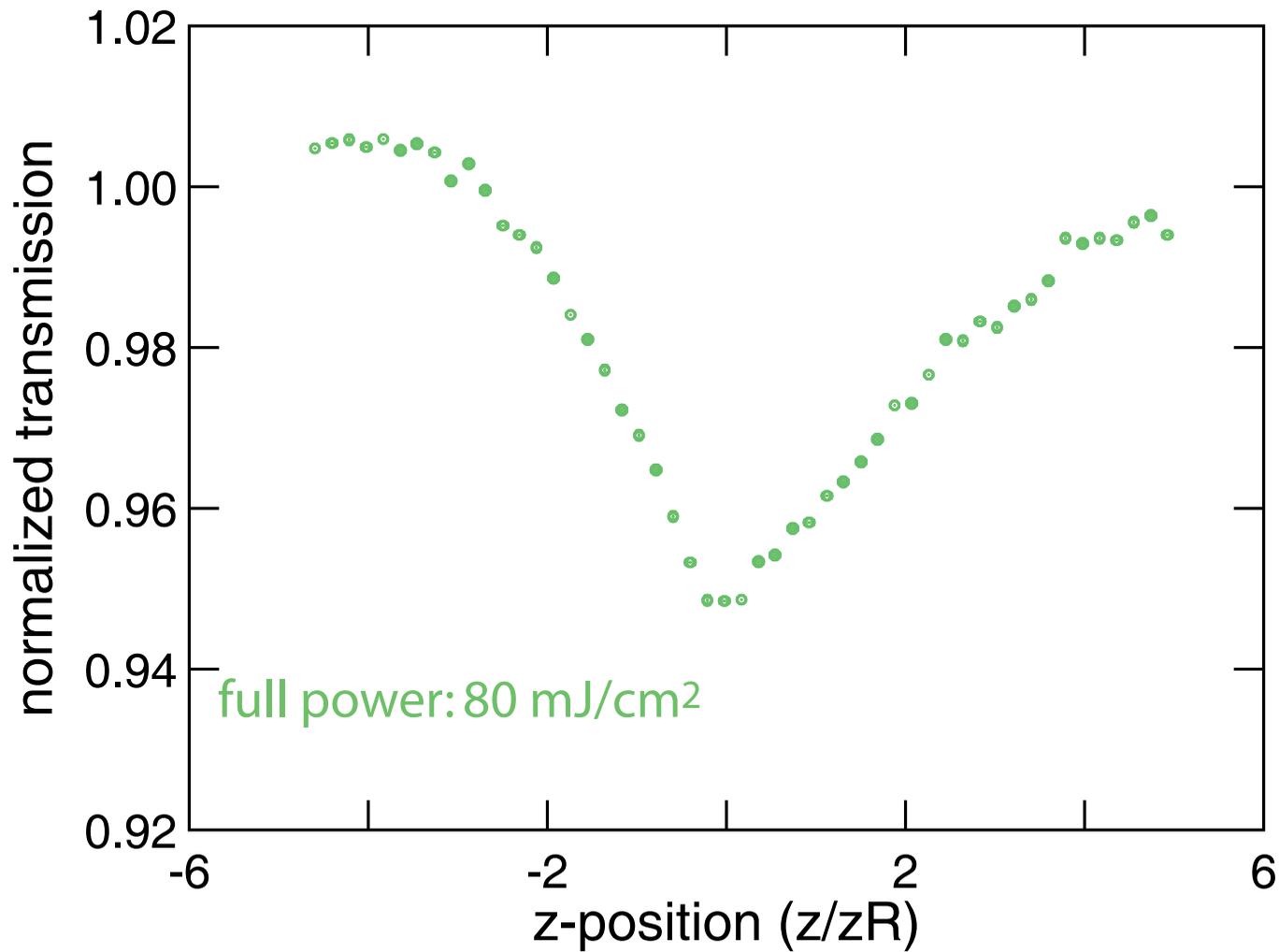
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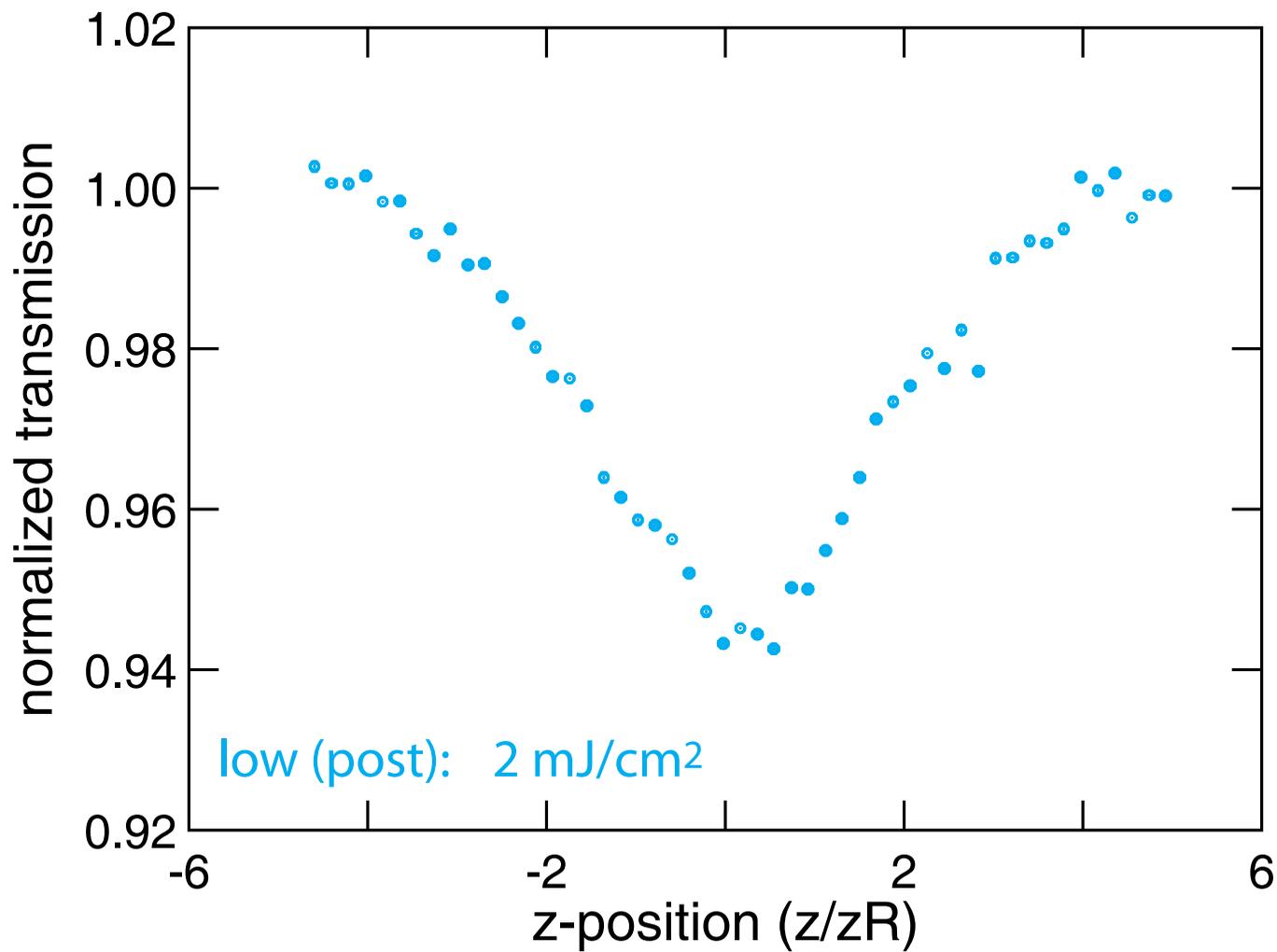
# Standard z-scan

Open Aperture



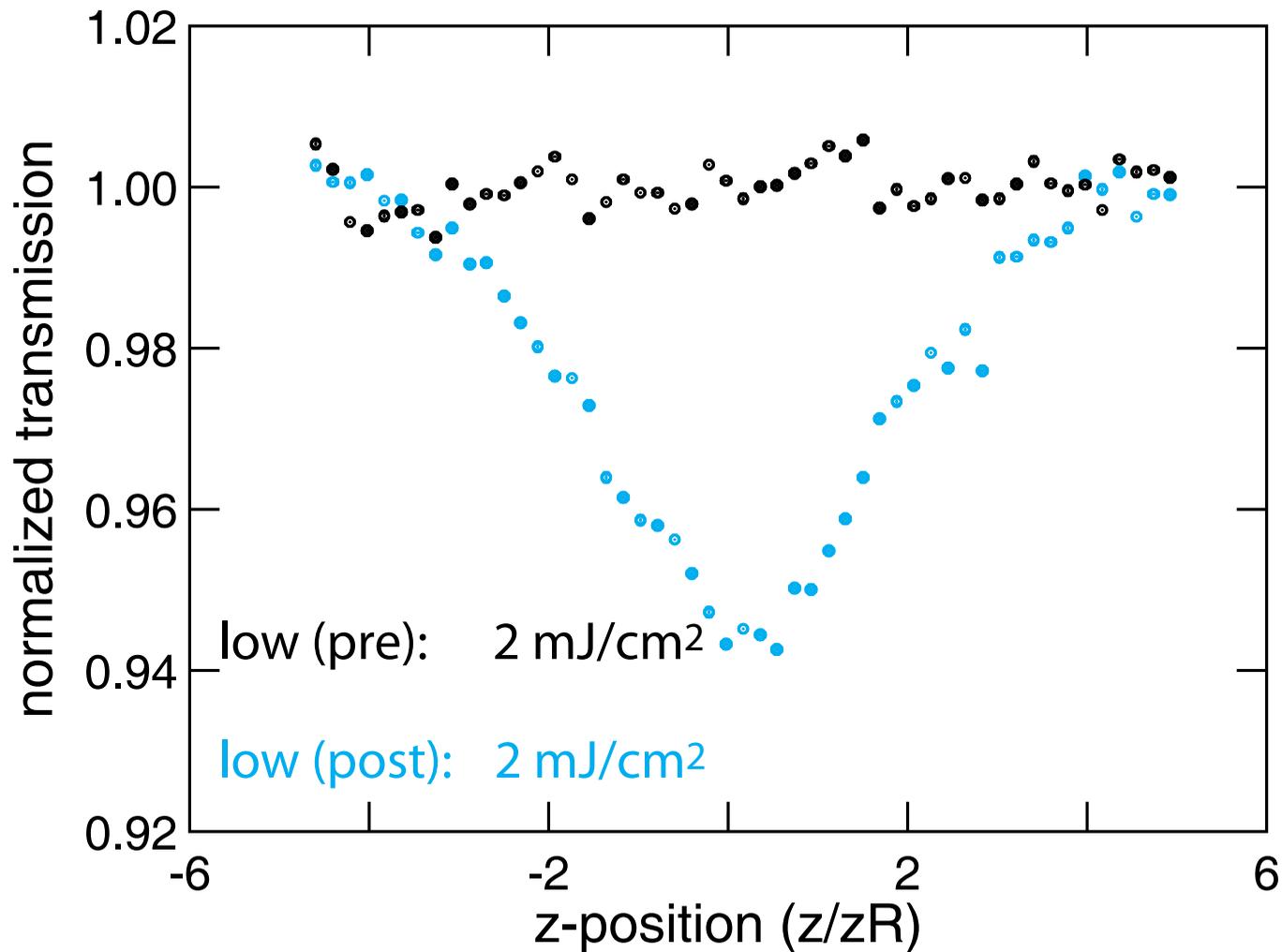
# Standard z-scan

Open Aperture



# Standard z-scan

Sample has been changed

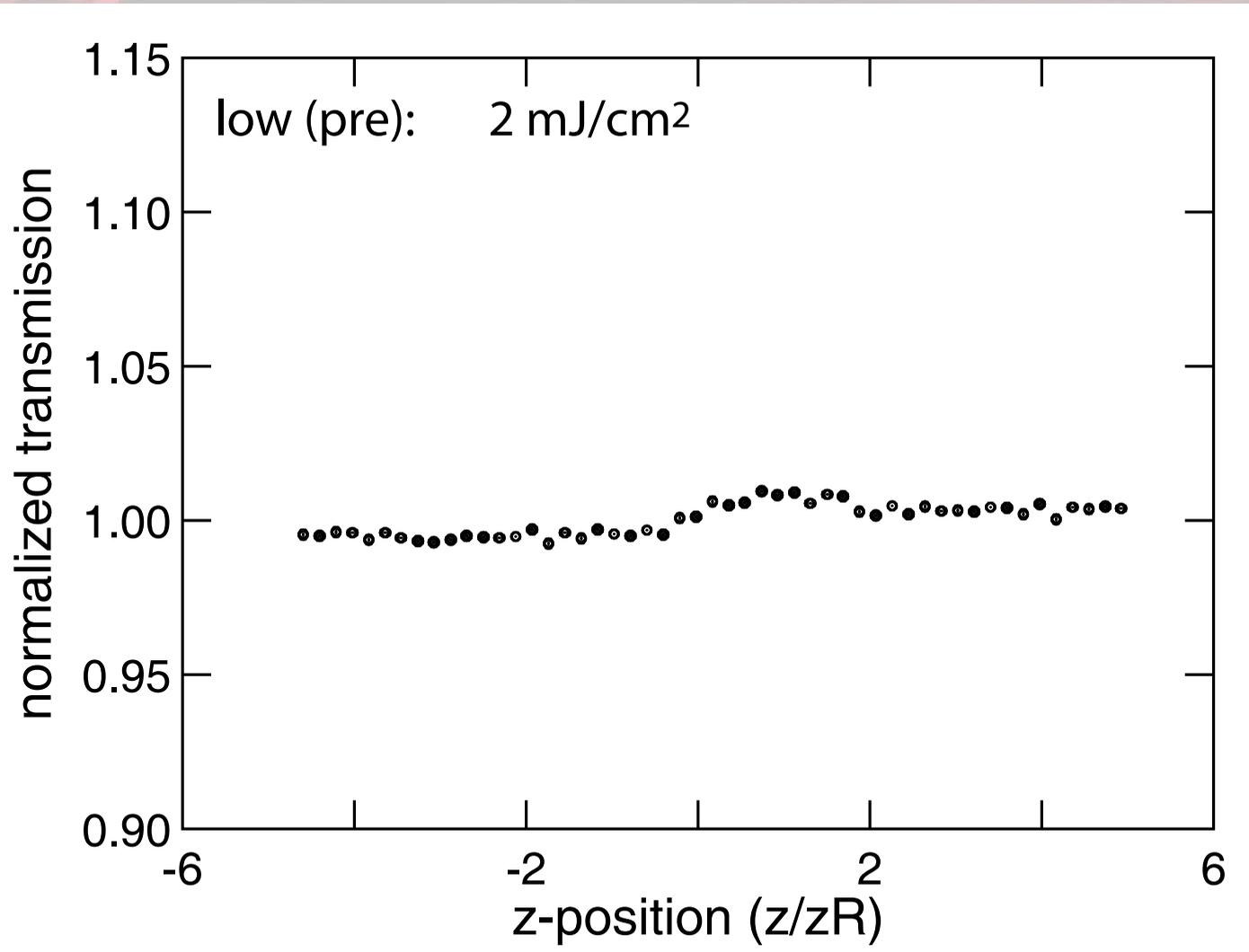


# Standard z-scan

What about the closed aperture?

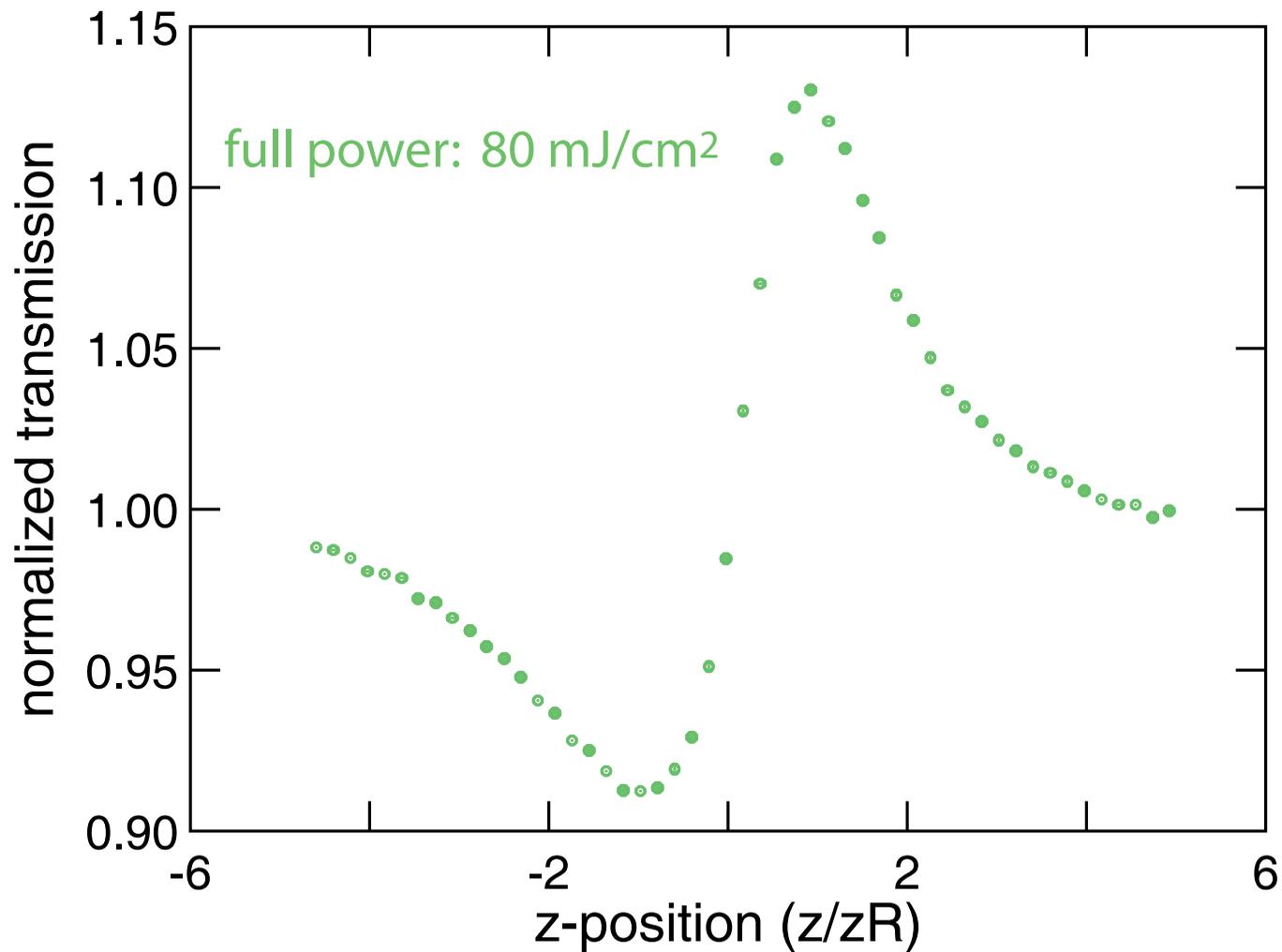
# Standard z-scan

Closed Aperture (CA/OA)



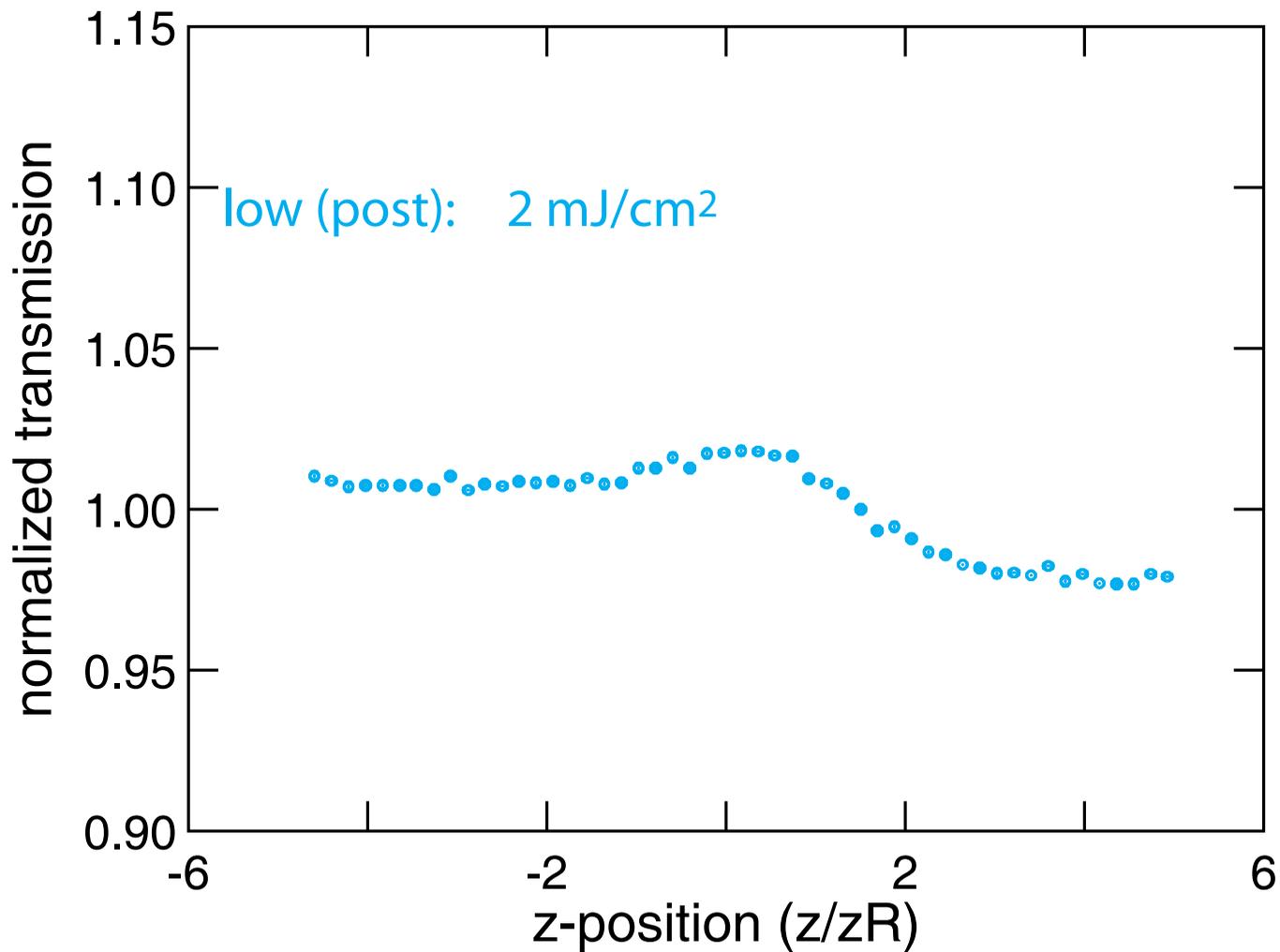
# Standard z-scan

Closed Aperture (CA/OA)



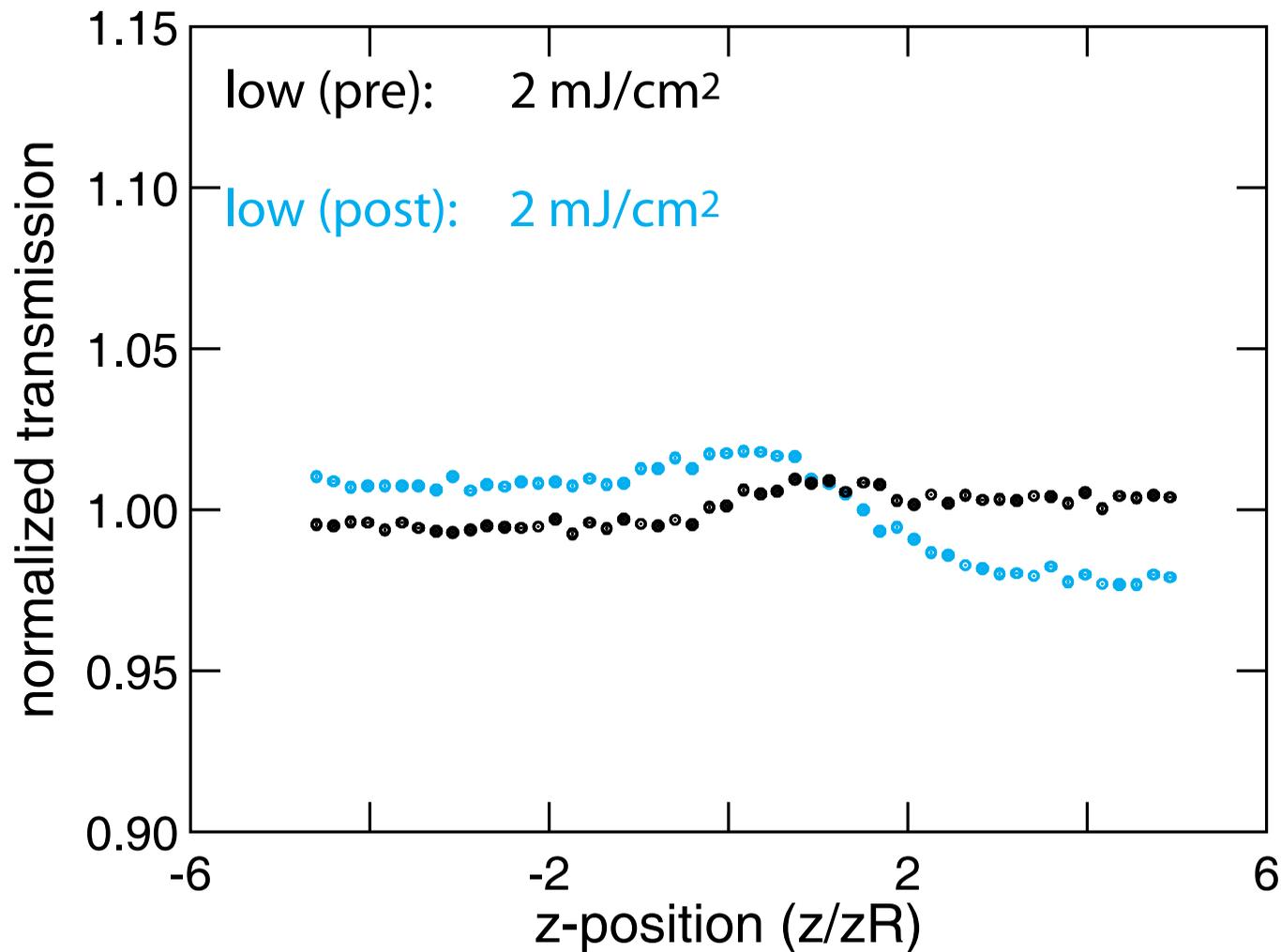
# Standard z-scan

Closed Aperture (CA/OA)



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Sample has been changed

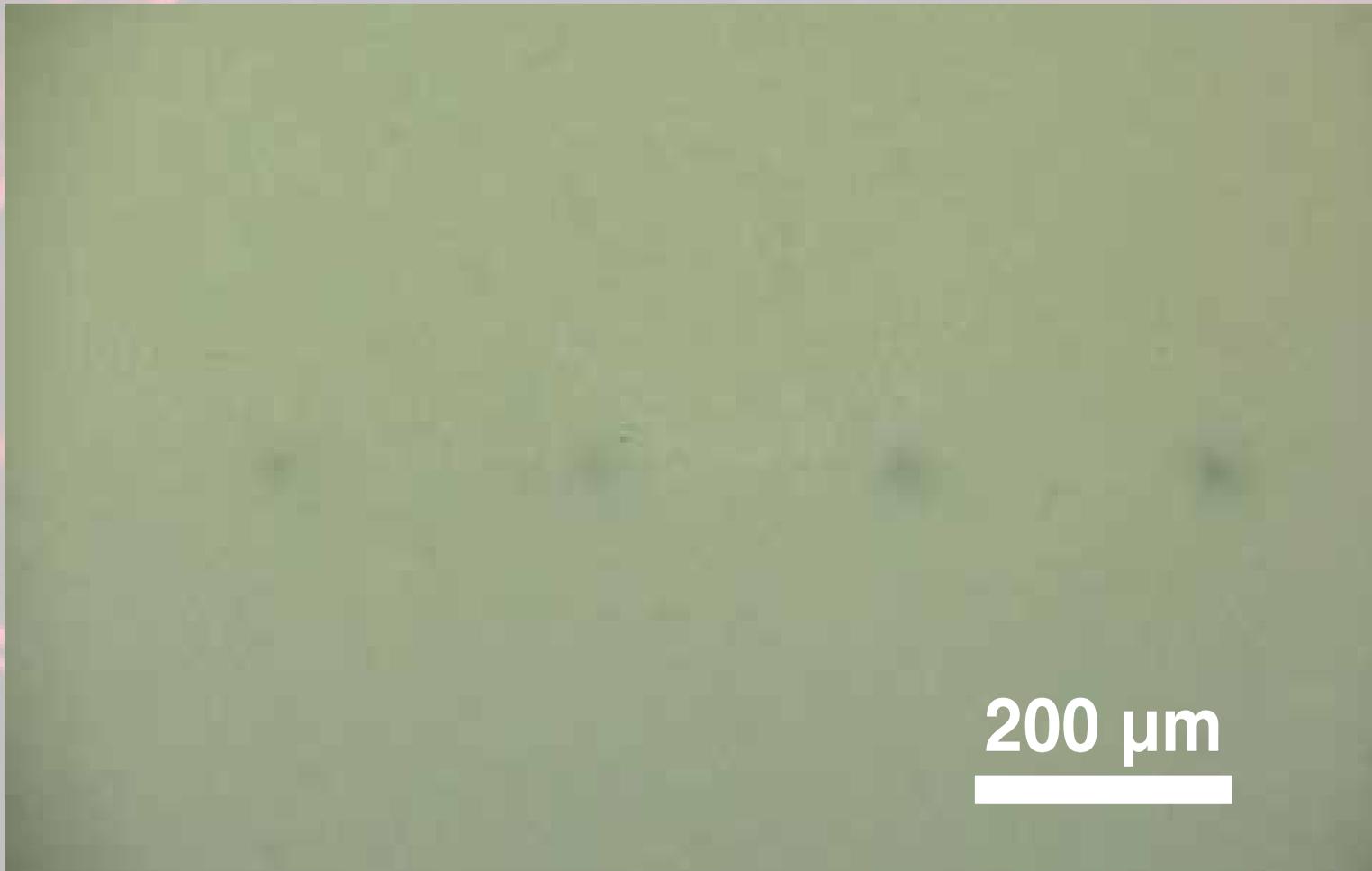


# Standard z-scan

What does the sample look like after?

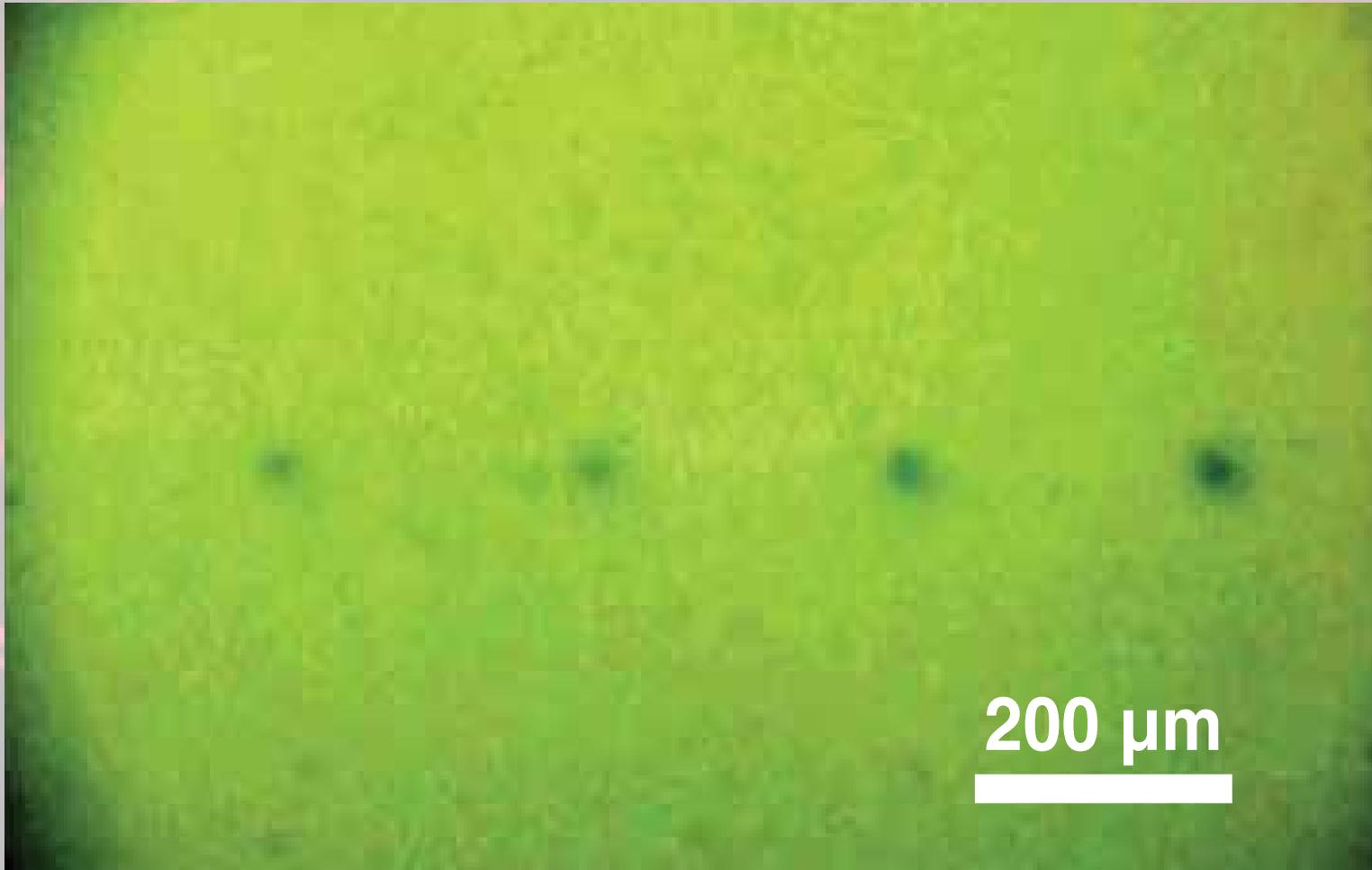
# Standard z-scan

Optical microscopy



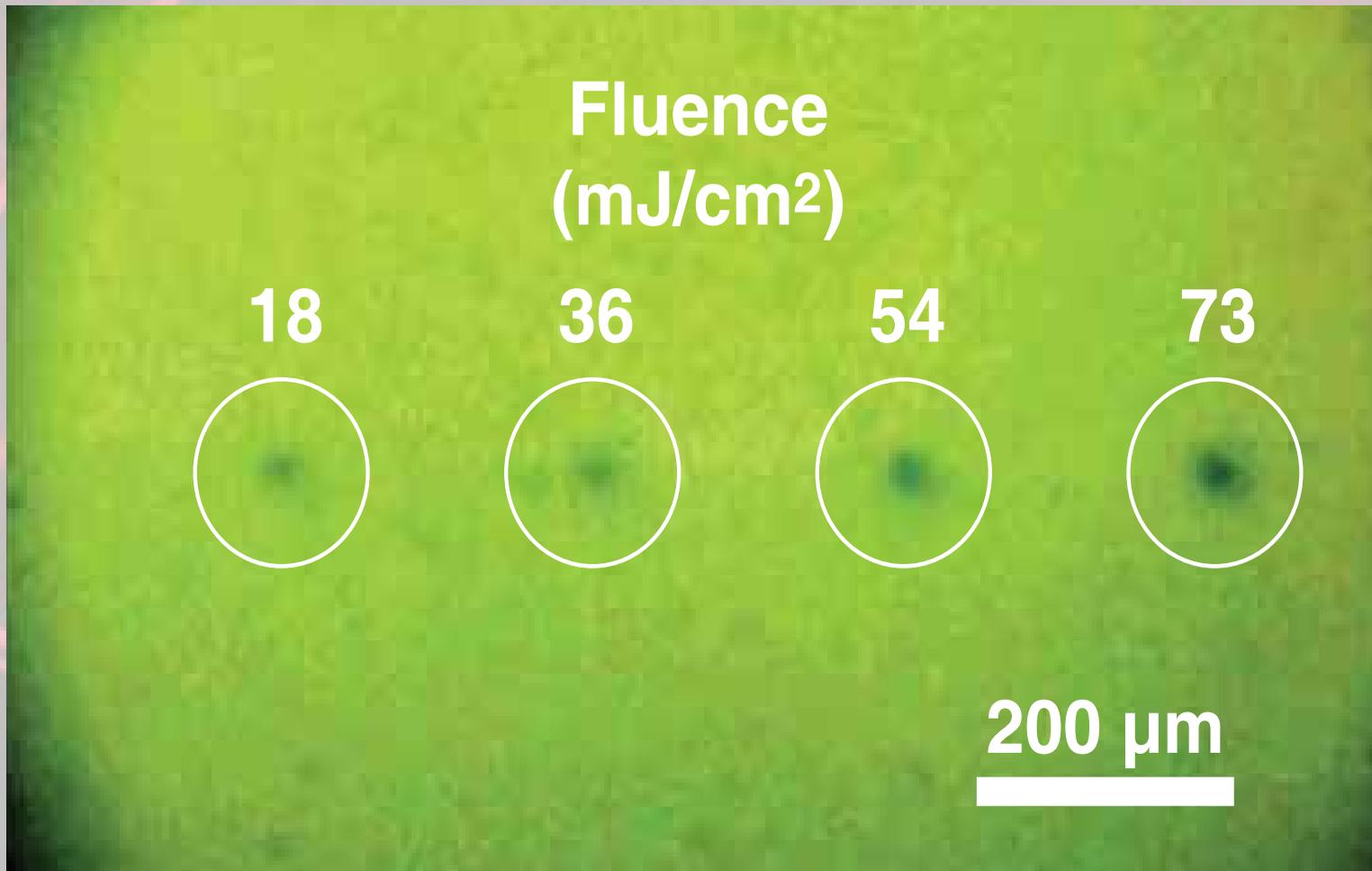
# Standard z-scan

Optical microscopy (enhanced)



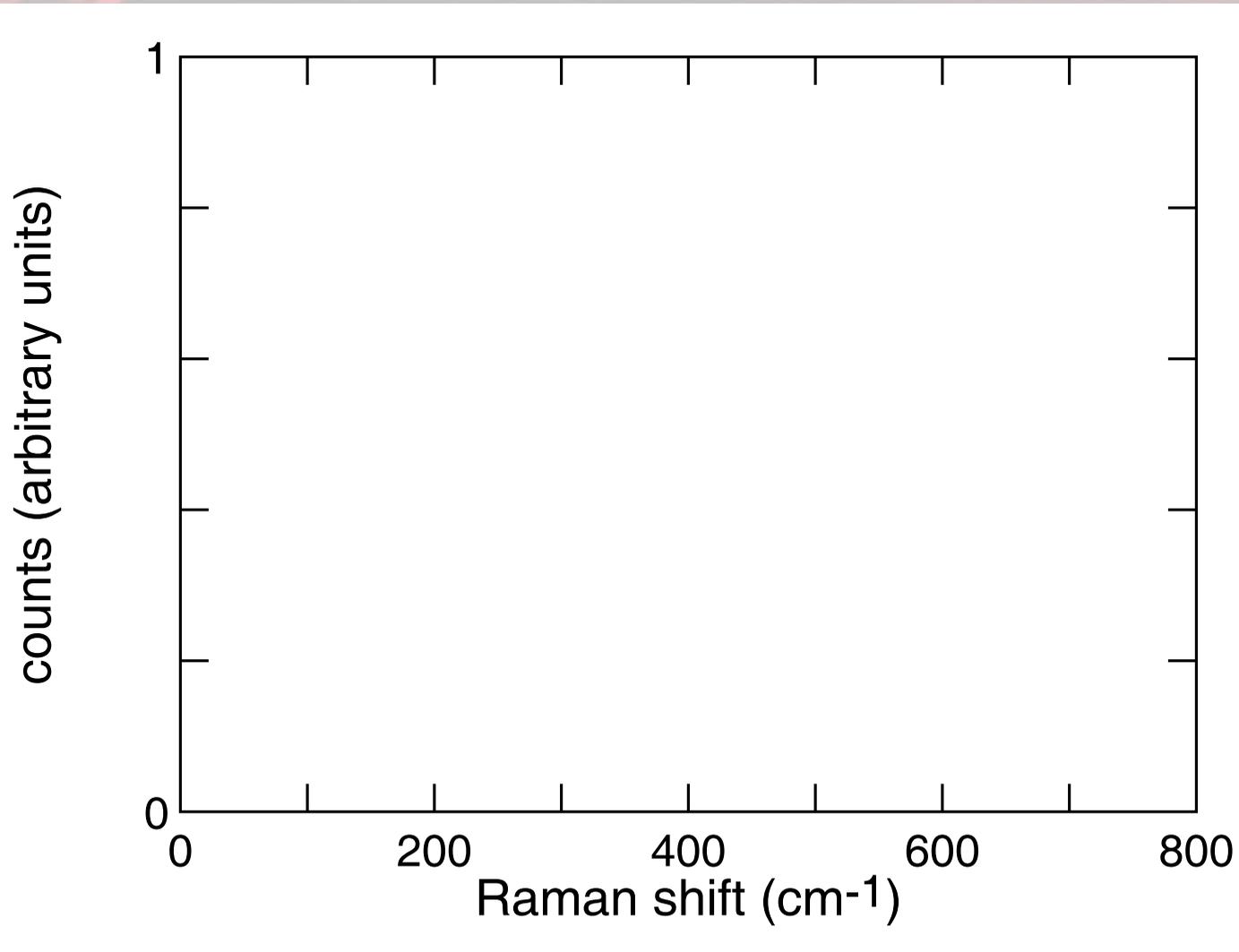
# Standard z-scan

Optical microscopy (enhanced)



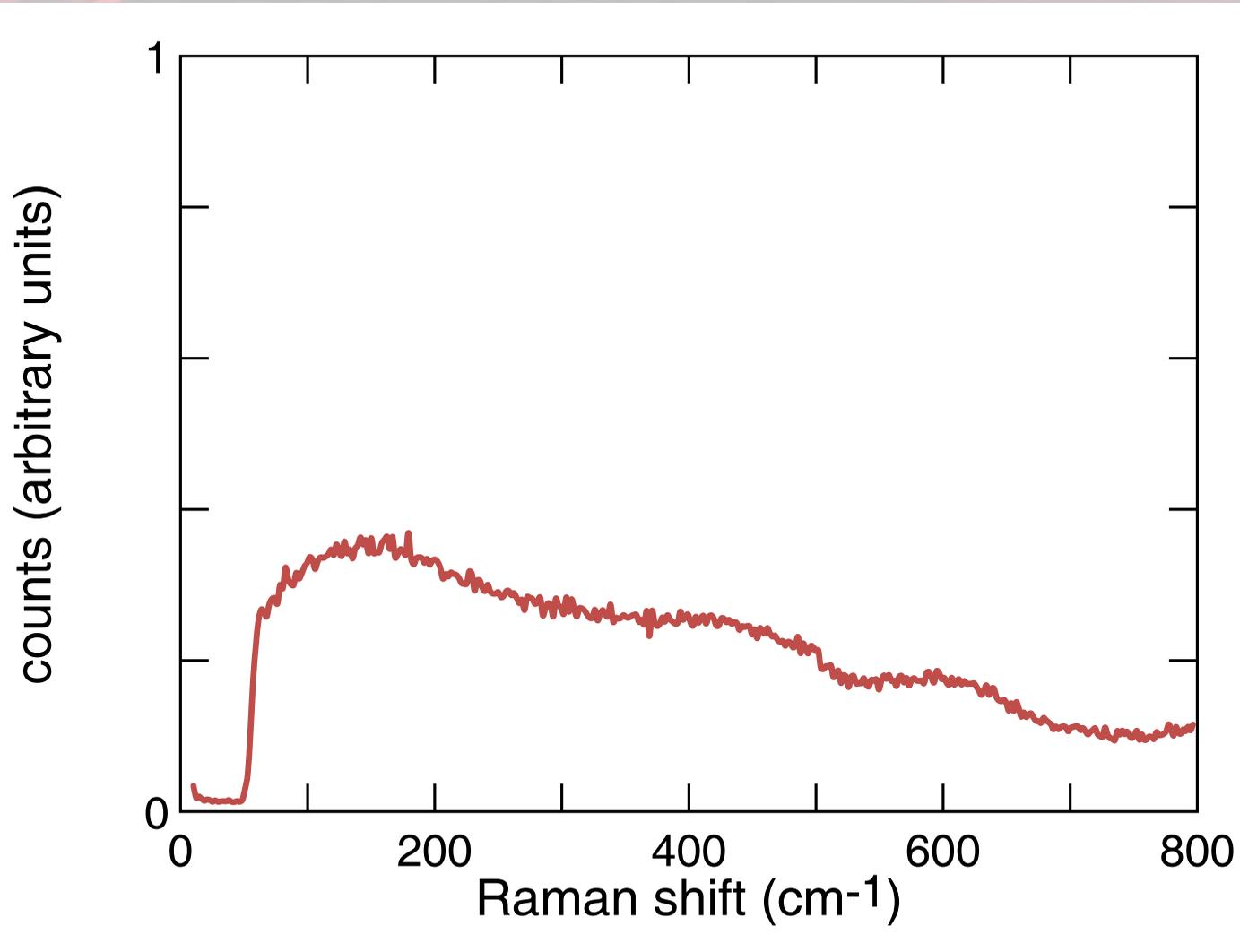
# Standard z-scan

Raman



# Standard z-scan

No Peaks

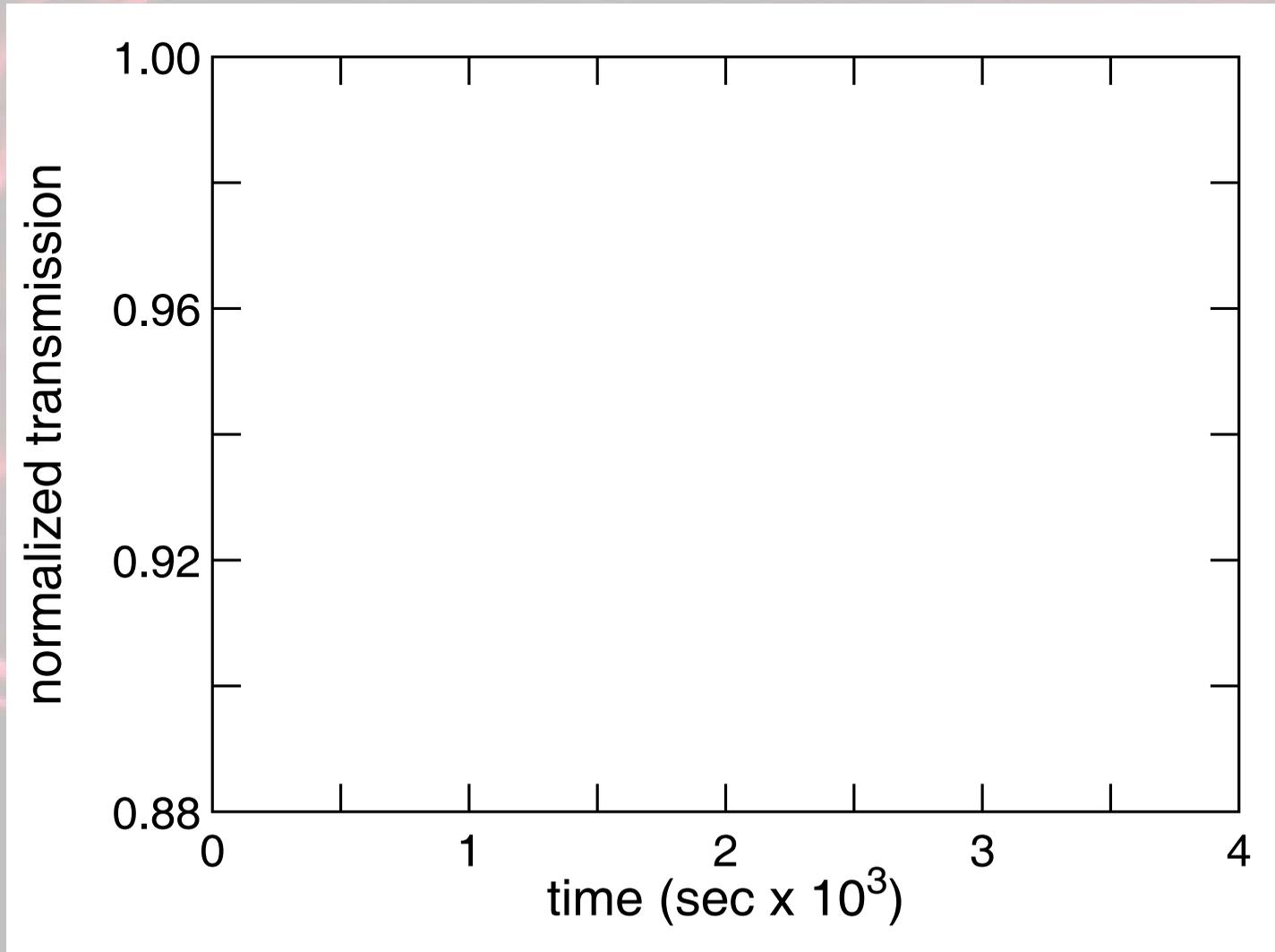


# Standard z-scan

What is the time scale of the darkening?

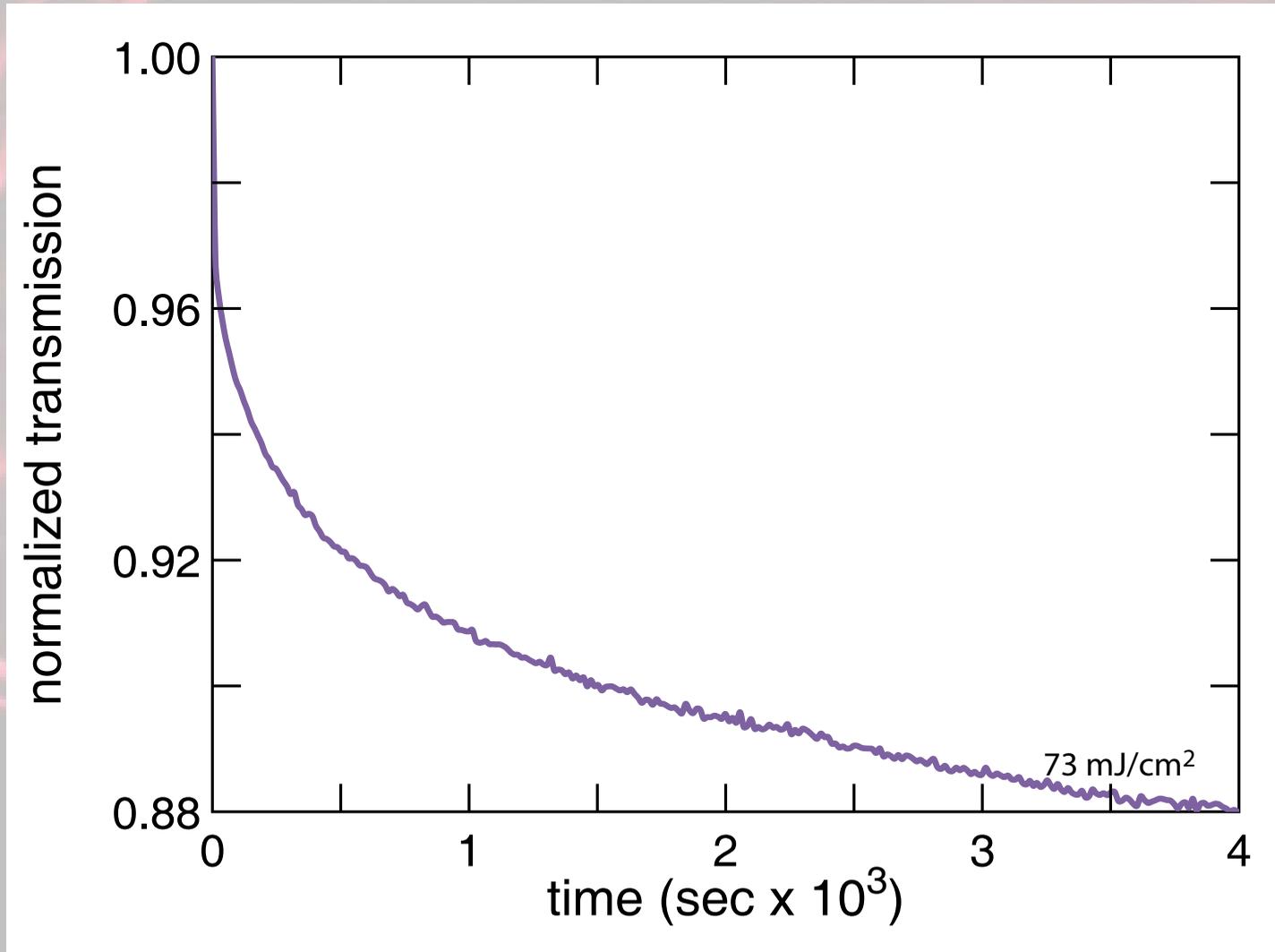
# Standard z-scan

Timed Exposure (Open Aperture)



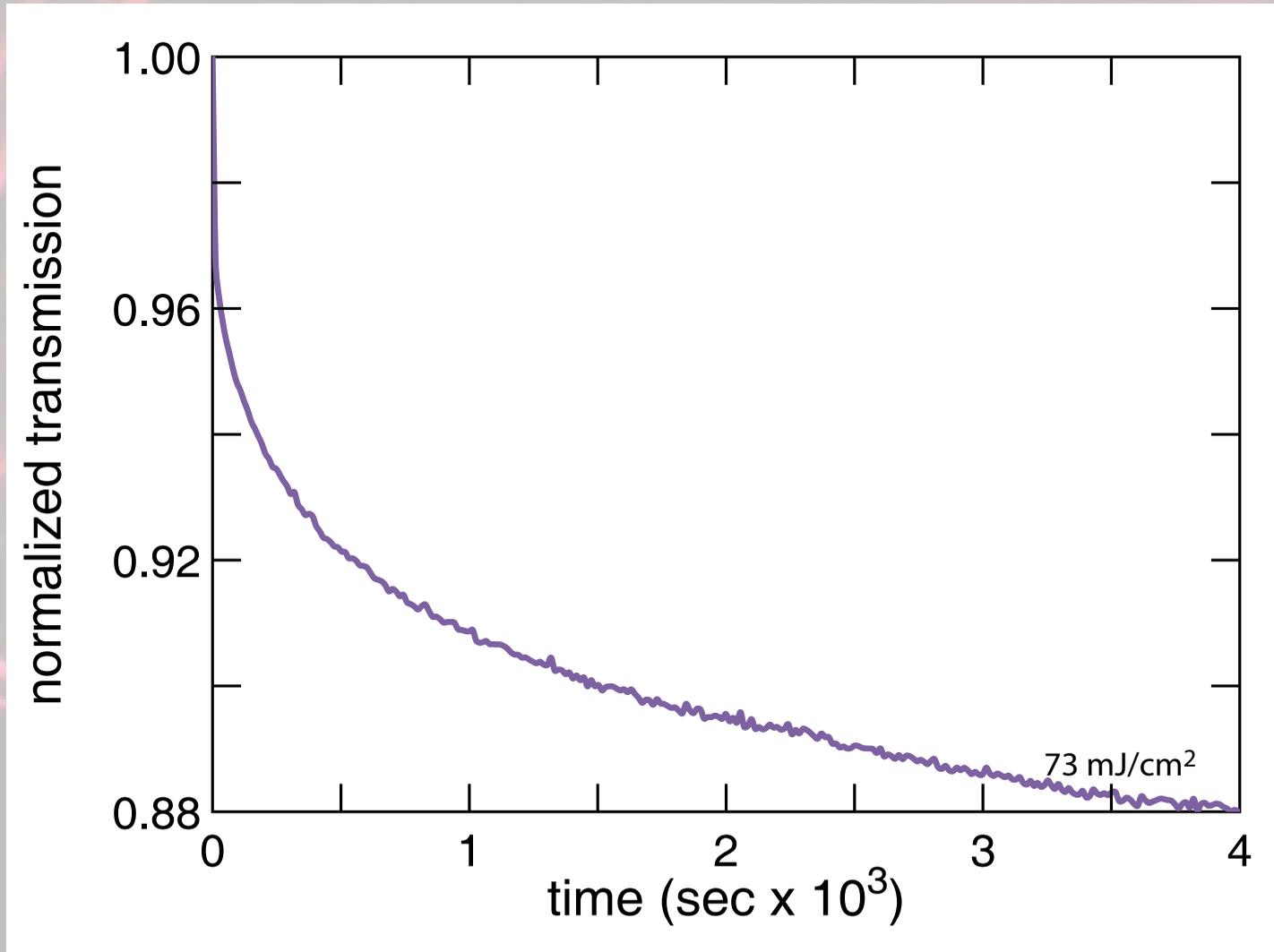
# Standard z-scan

Timed Exposure (Open Aperture)



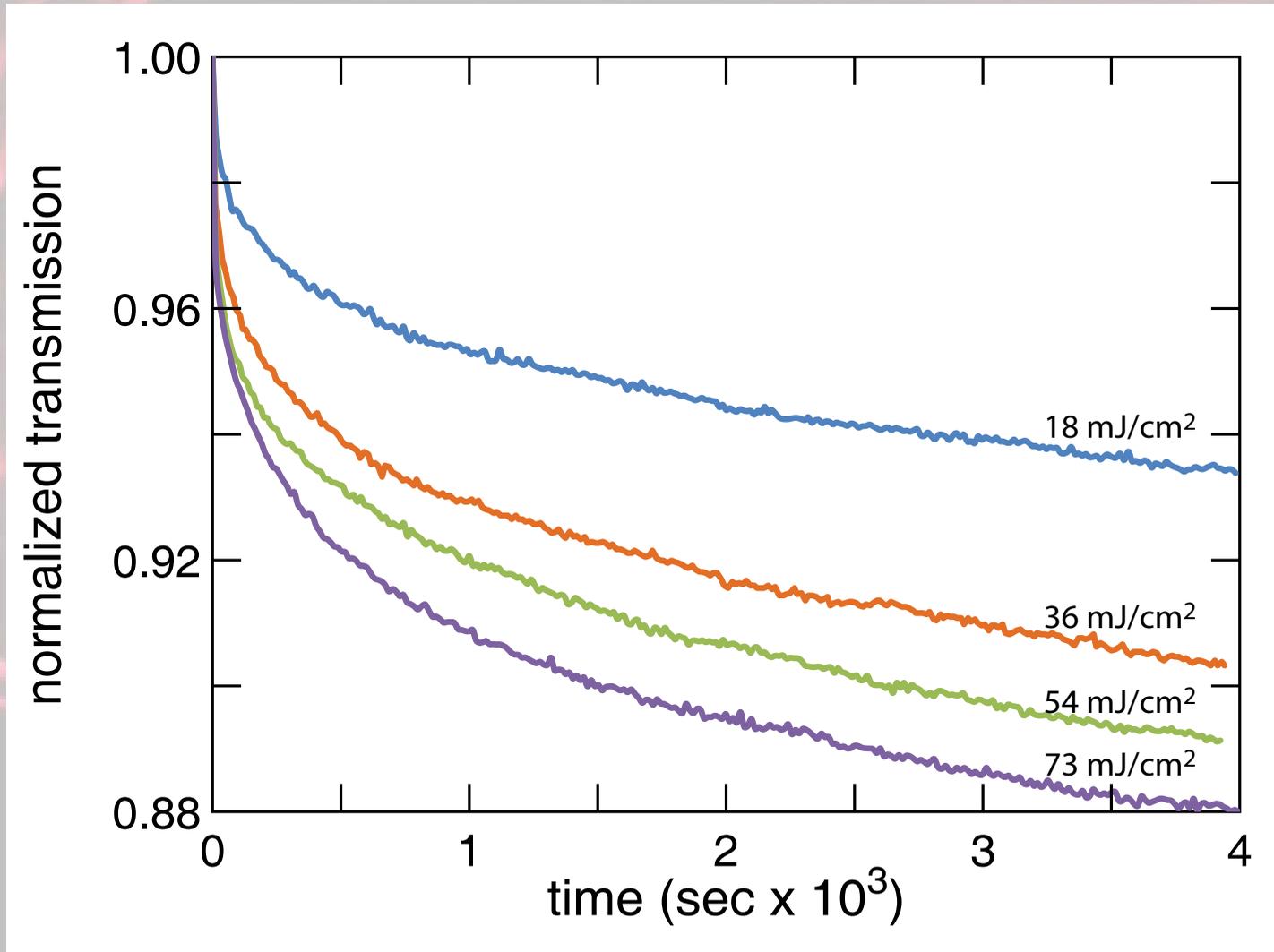
# Standard z-scan

Not stabilized over > 1 hour



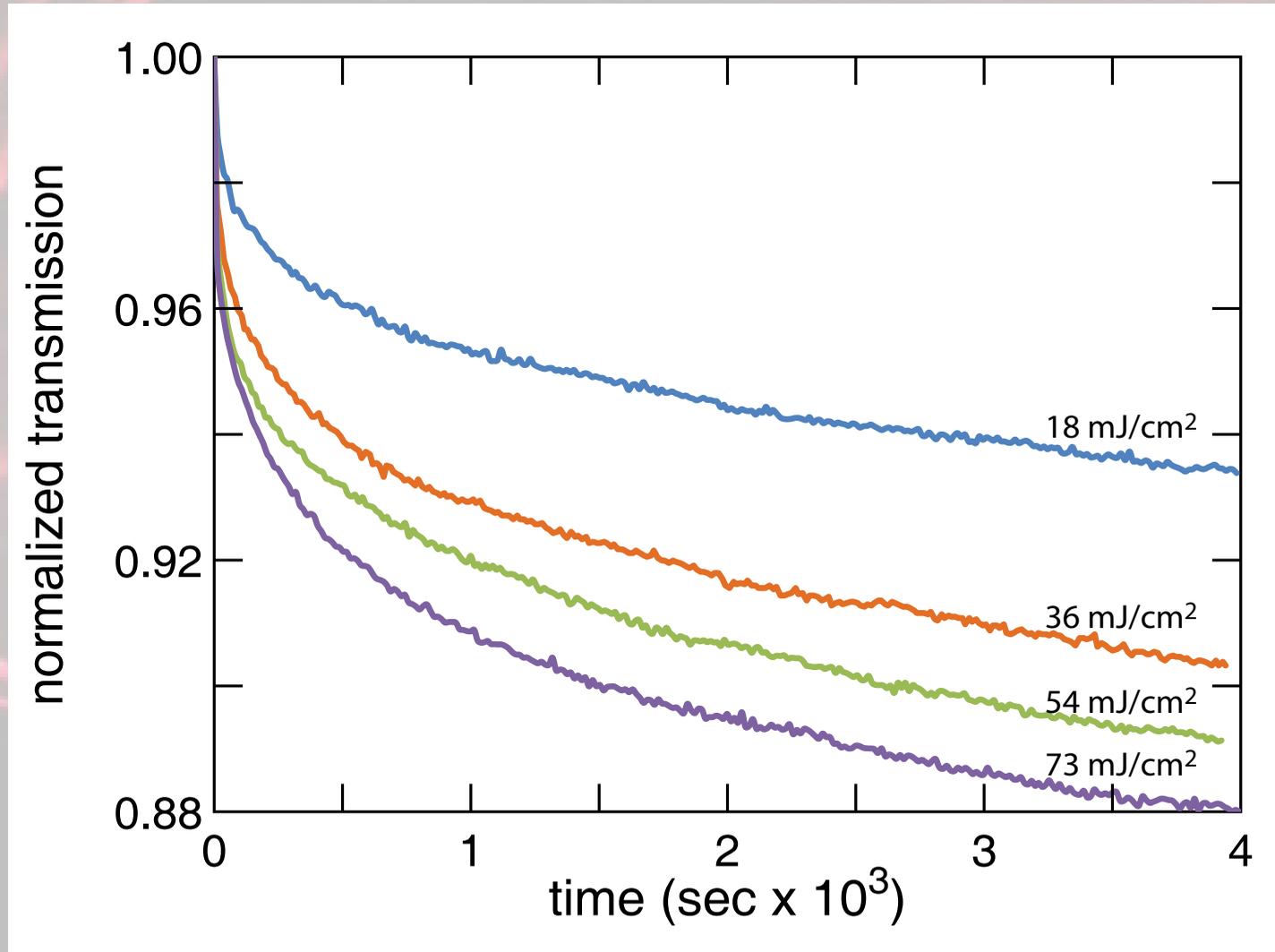
# Standard z-scan

## Even Low Power Decreases



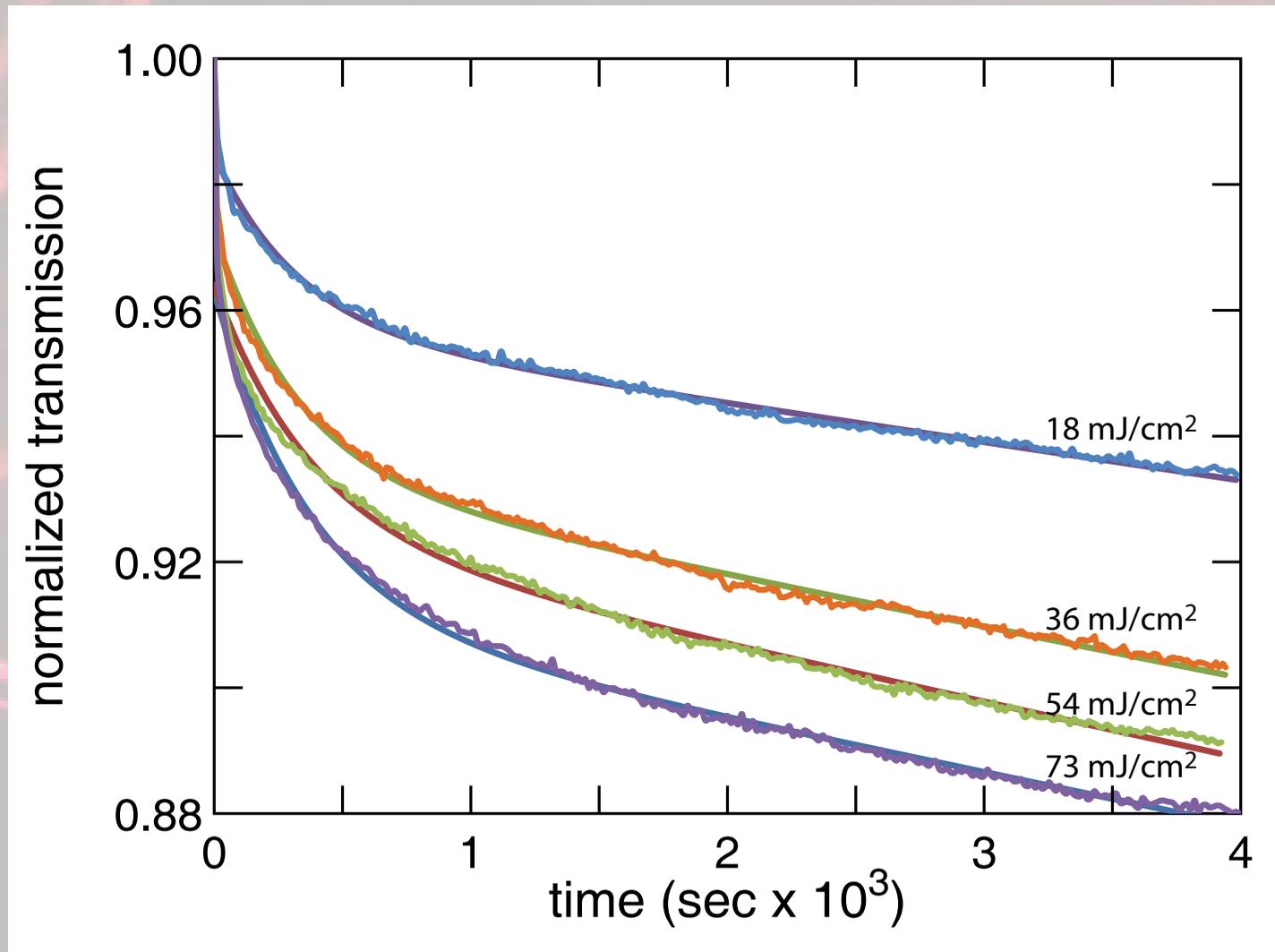
# Standard z-scan

Empirical Fit:  $A_1(P)\exp(-t/\tau_1) + A_2(P)\exp(-t/\tau_2)$



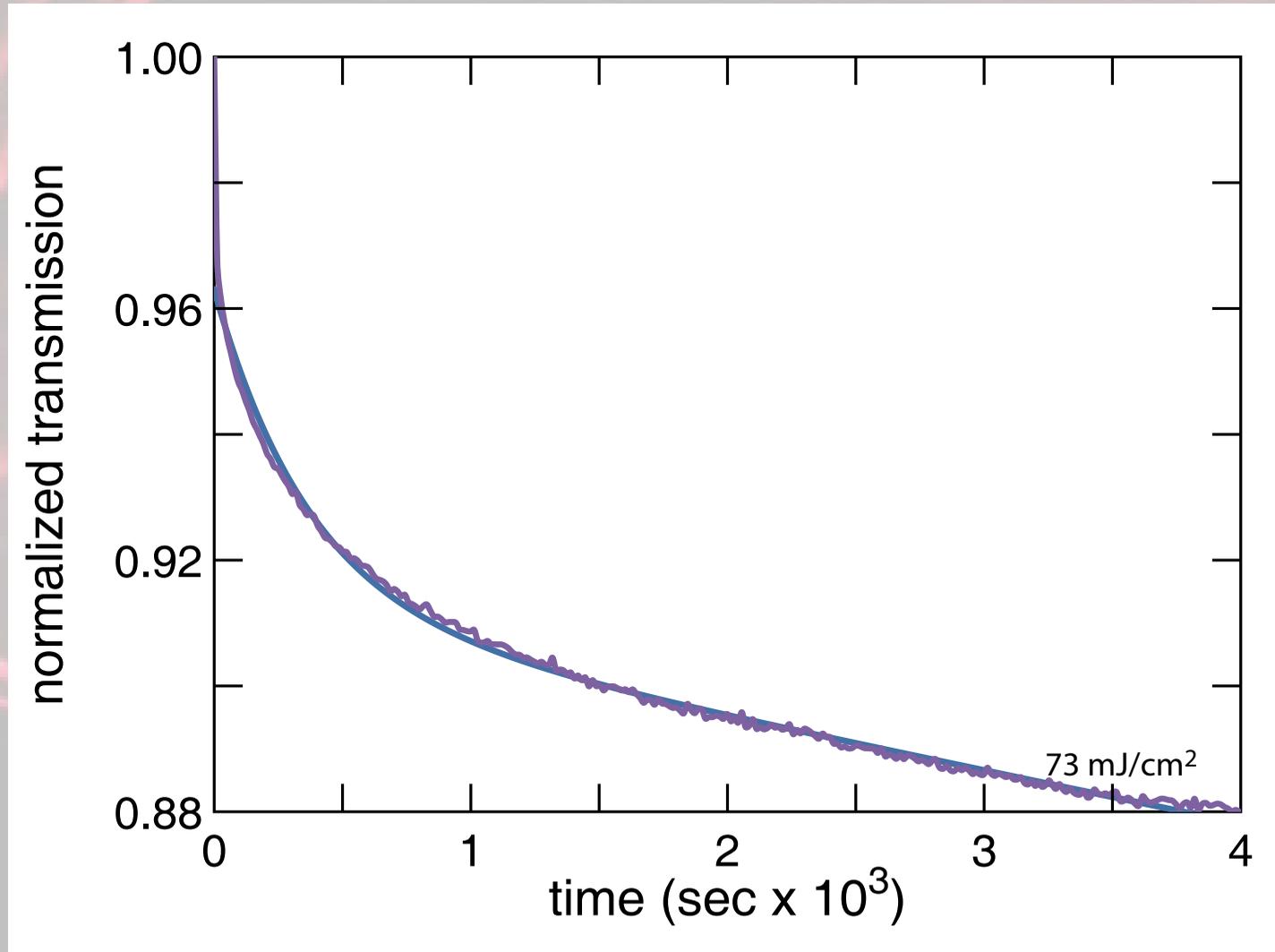
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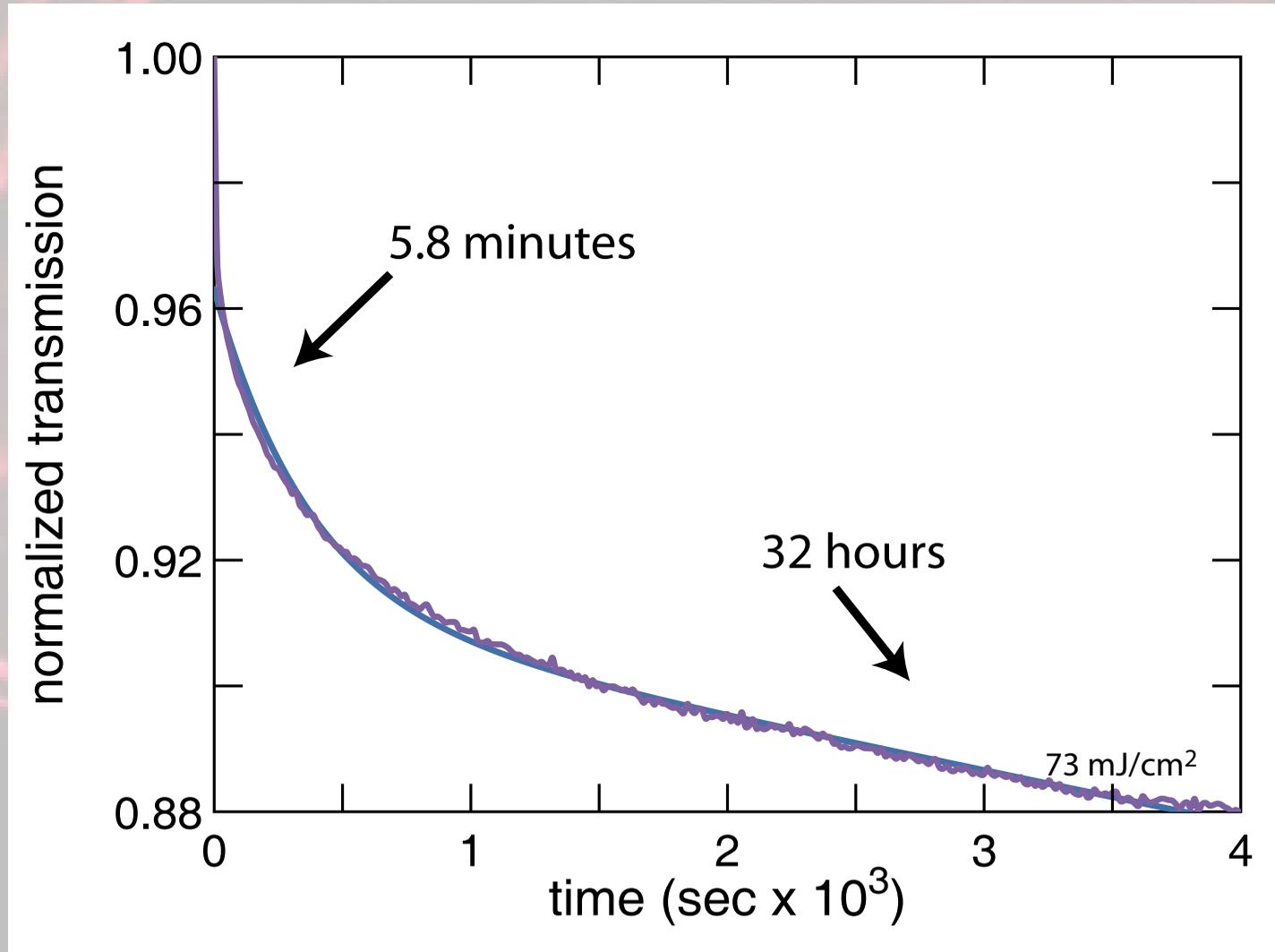
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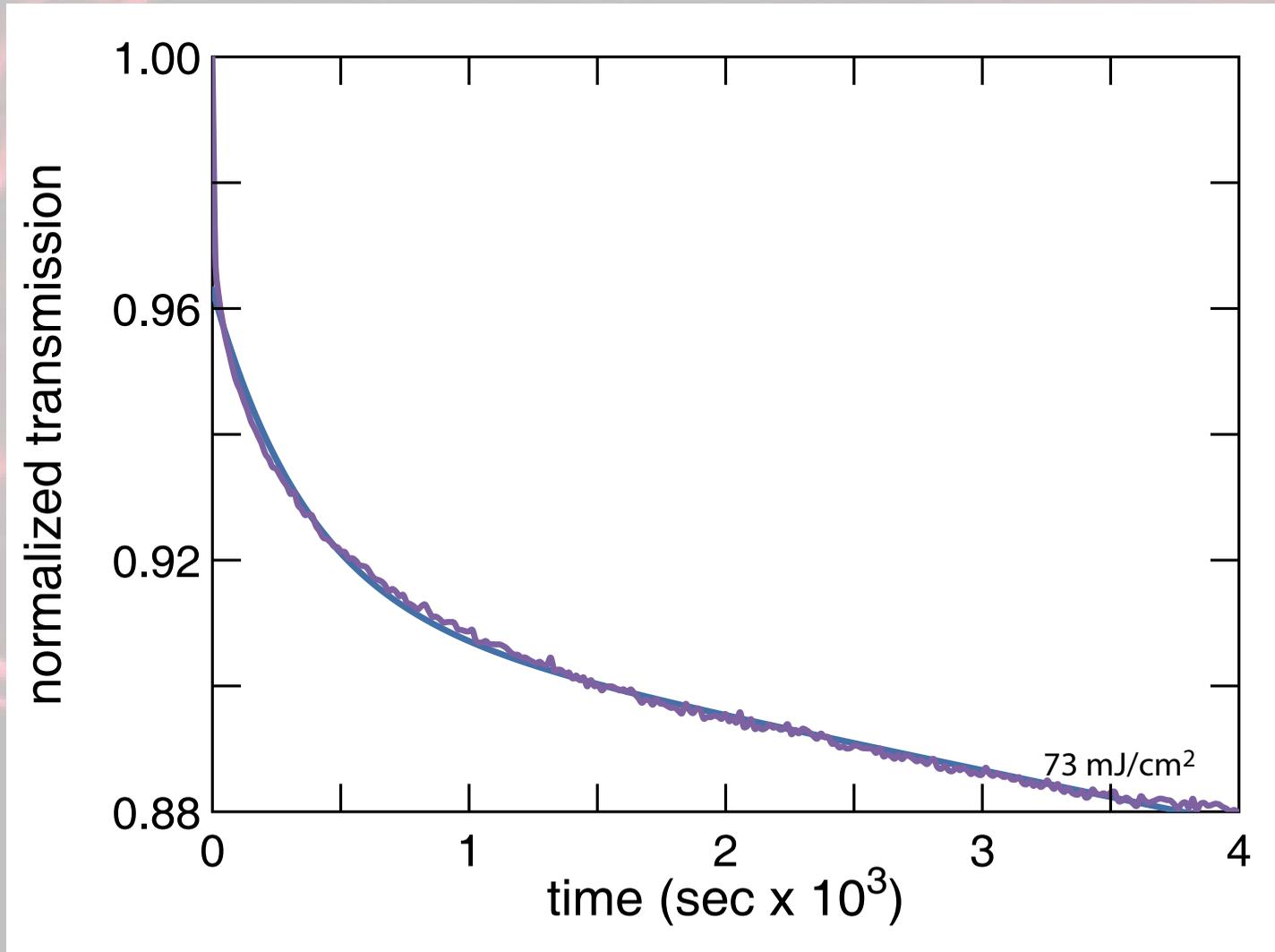


# Standard z-scan

Can we still measure the film?

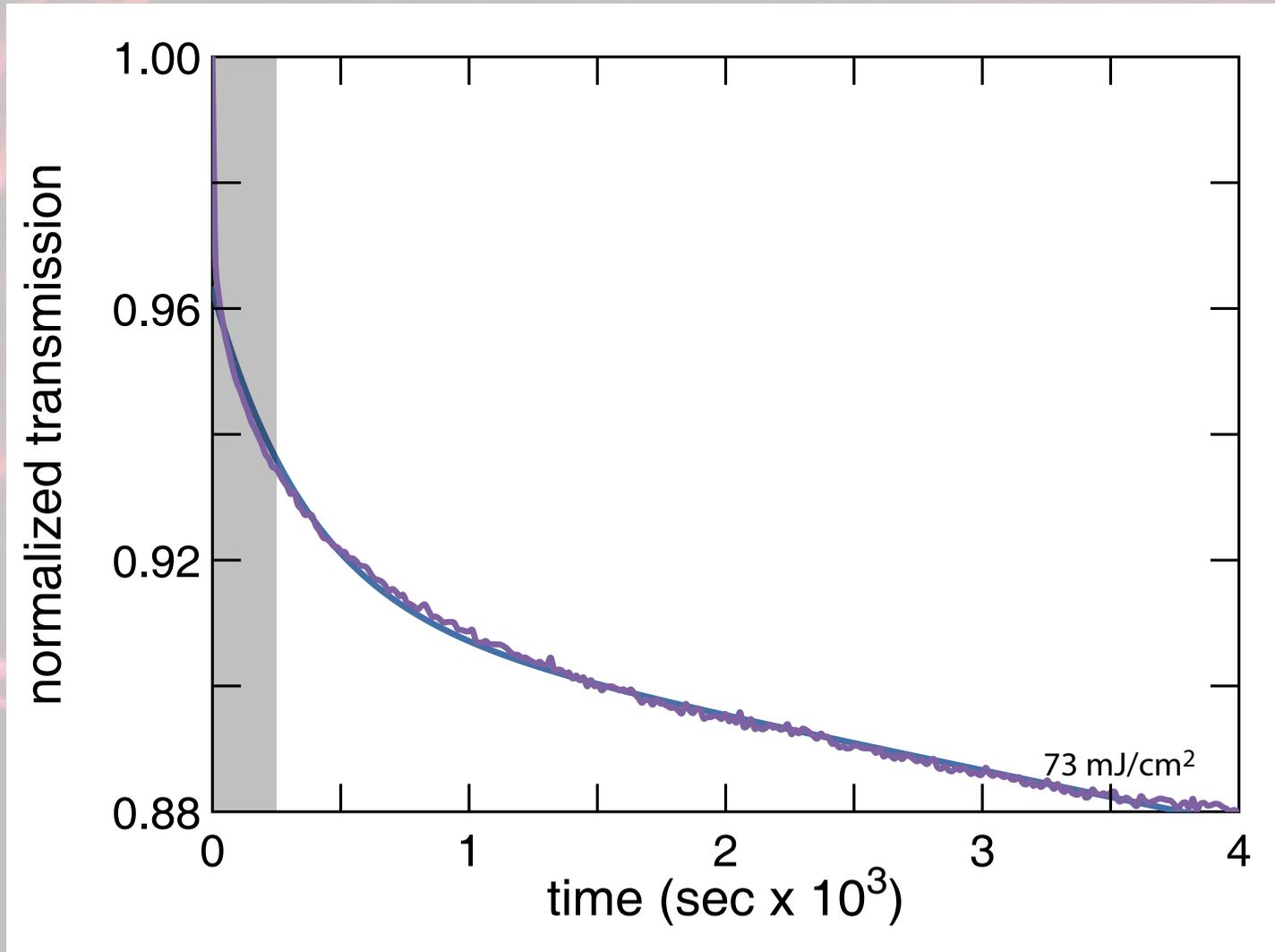
# Standard z-scan

Minimize Darkening



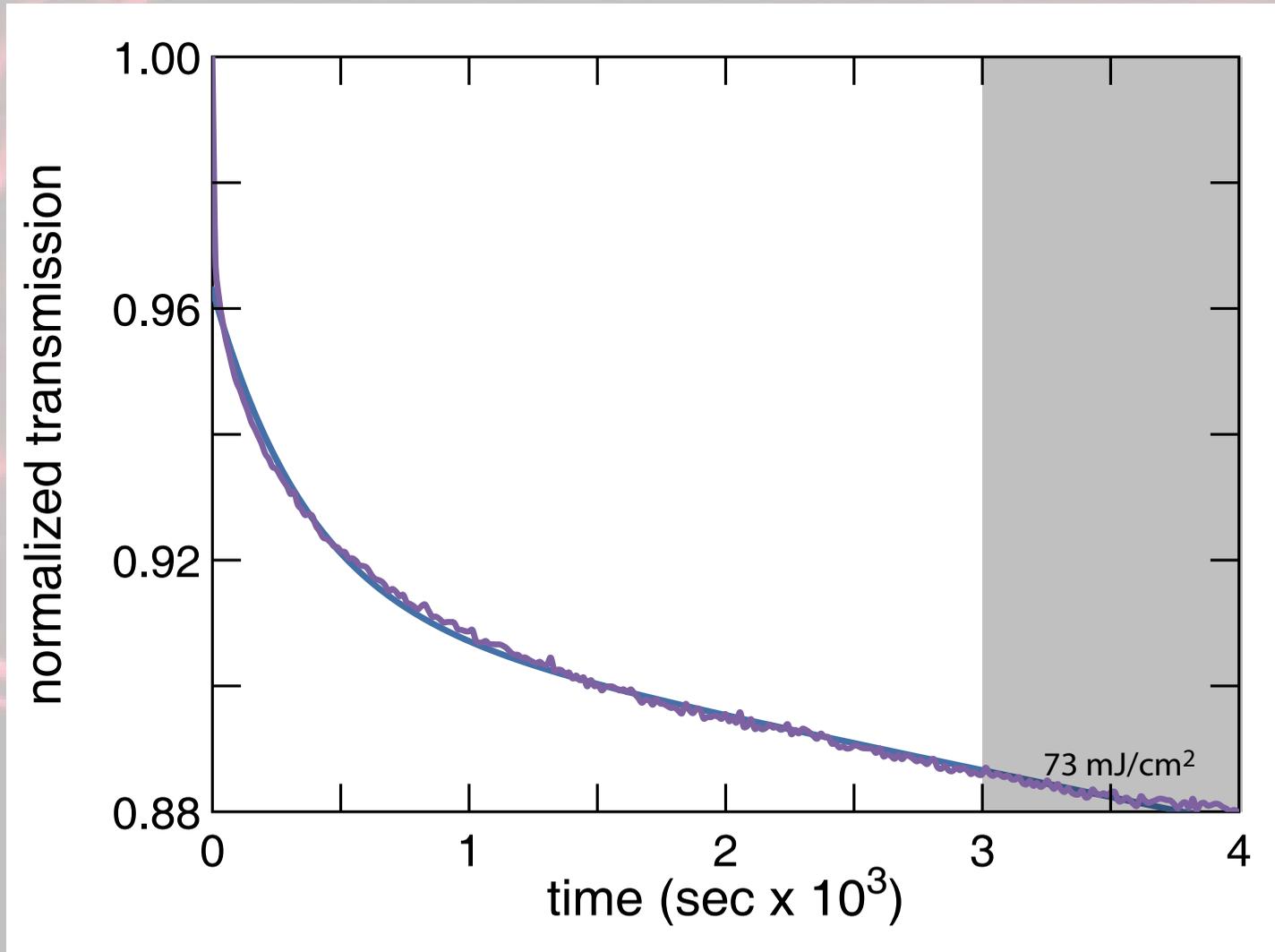
# Standard z-scan

Minimize Darkening



# Standard z-scan

Allow for darkening



# Standard z-scan

Comparison:

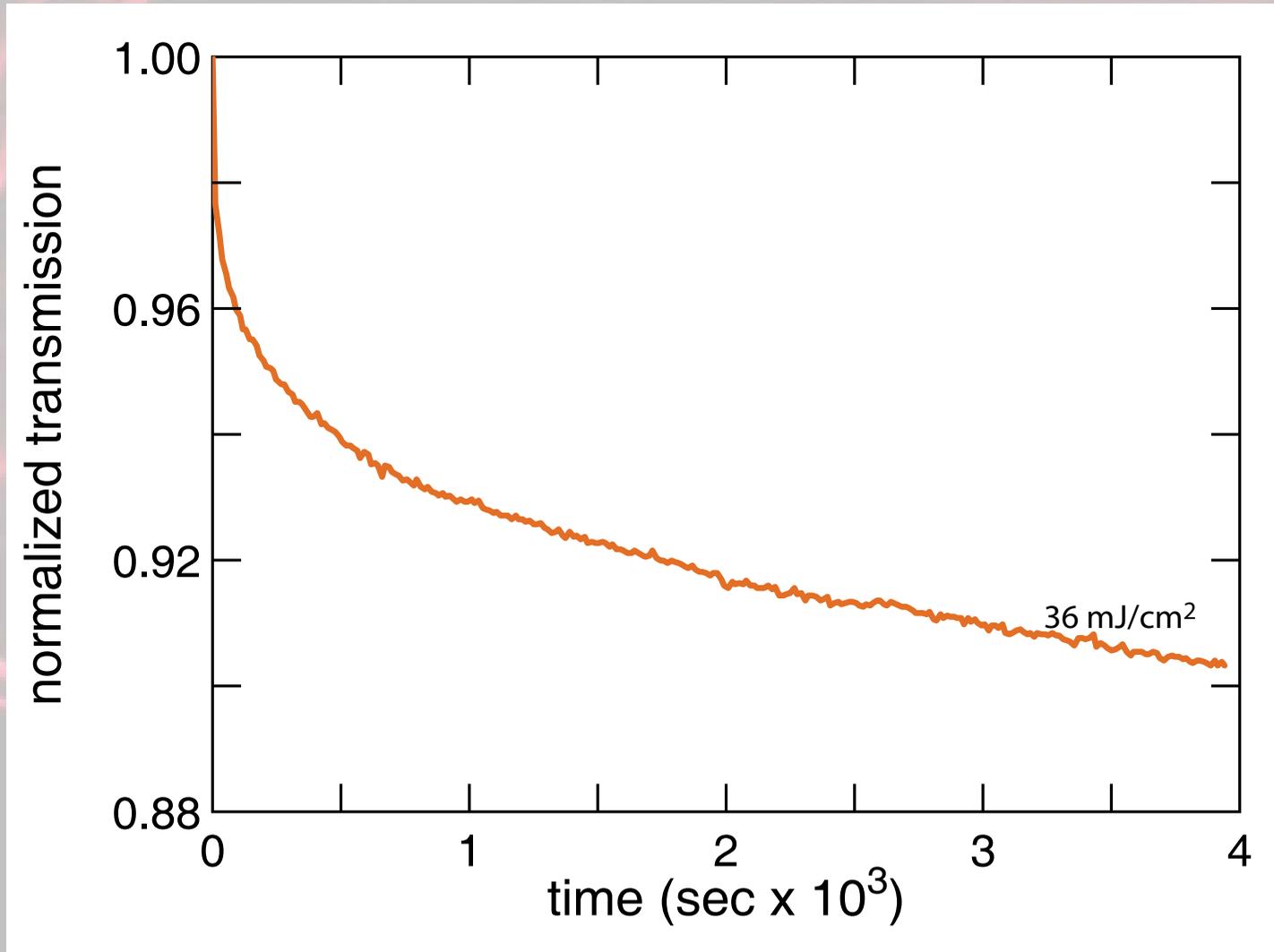
With  $\text{TiO}_2$  Film

versus

Without  $\text{TiO}_2$  Film

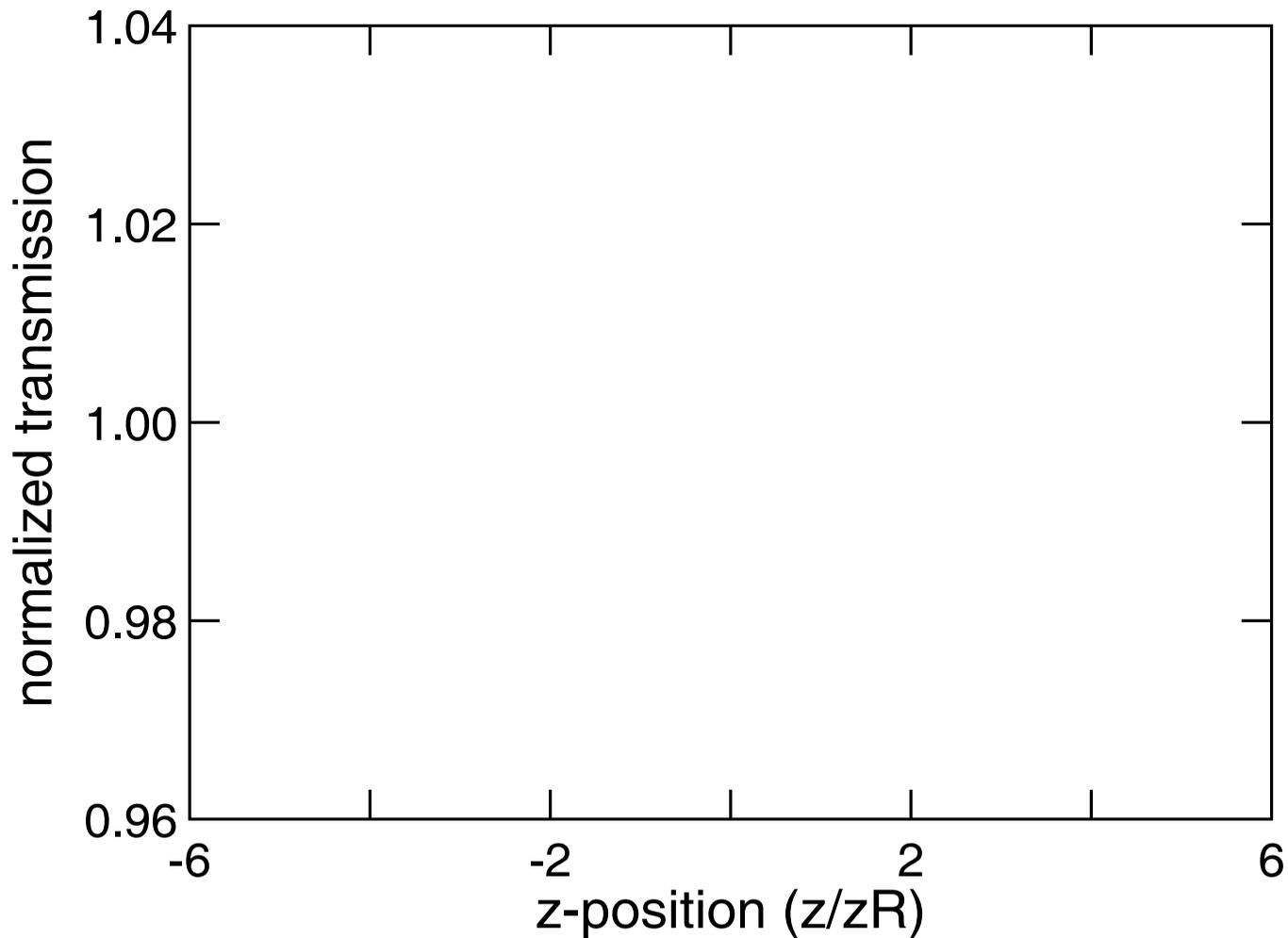
# Standard z-scan

Fluence used ( $\text{TiO}_2$ ):  $36 \text{ mJ/cm}^2$



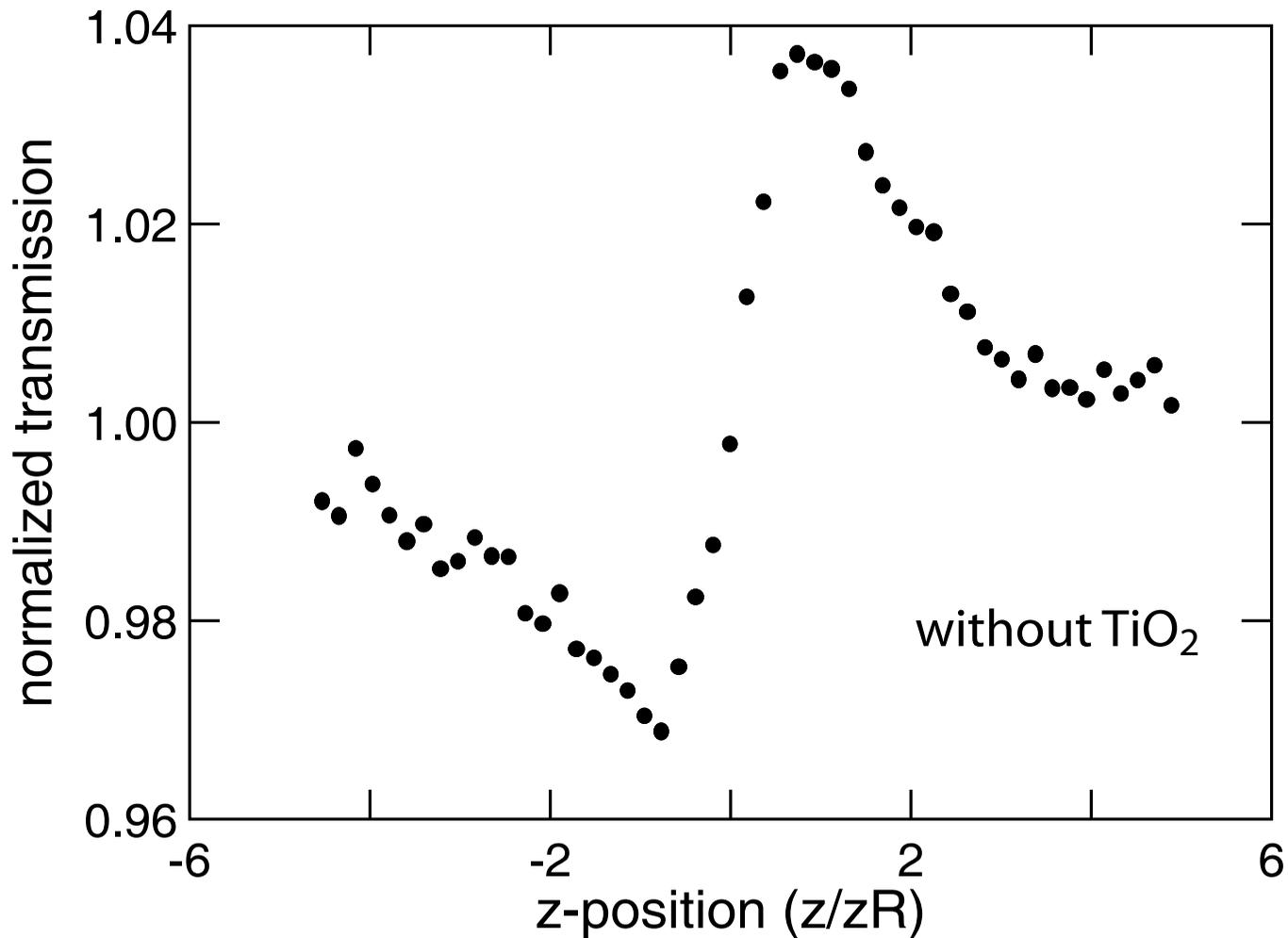
# Standard z-scan

Comparison with and without film



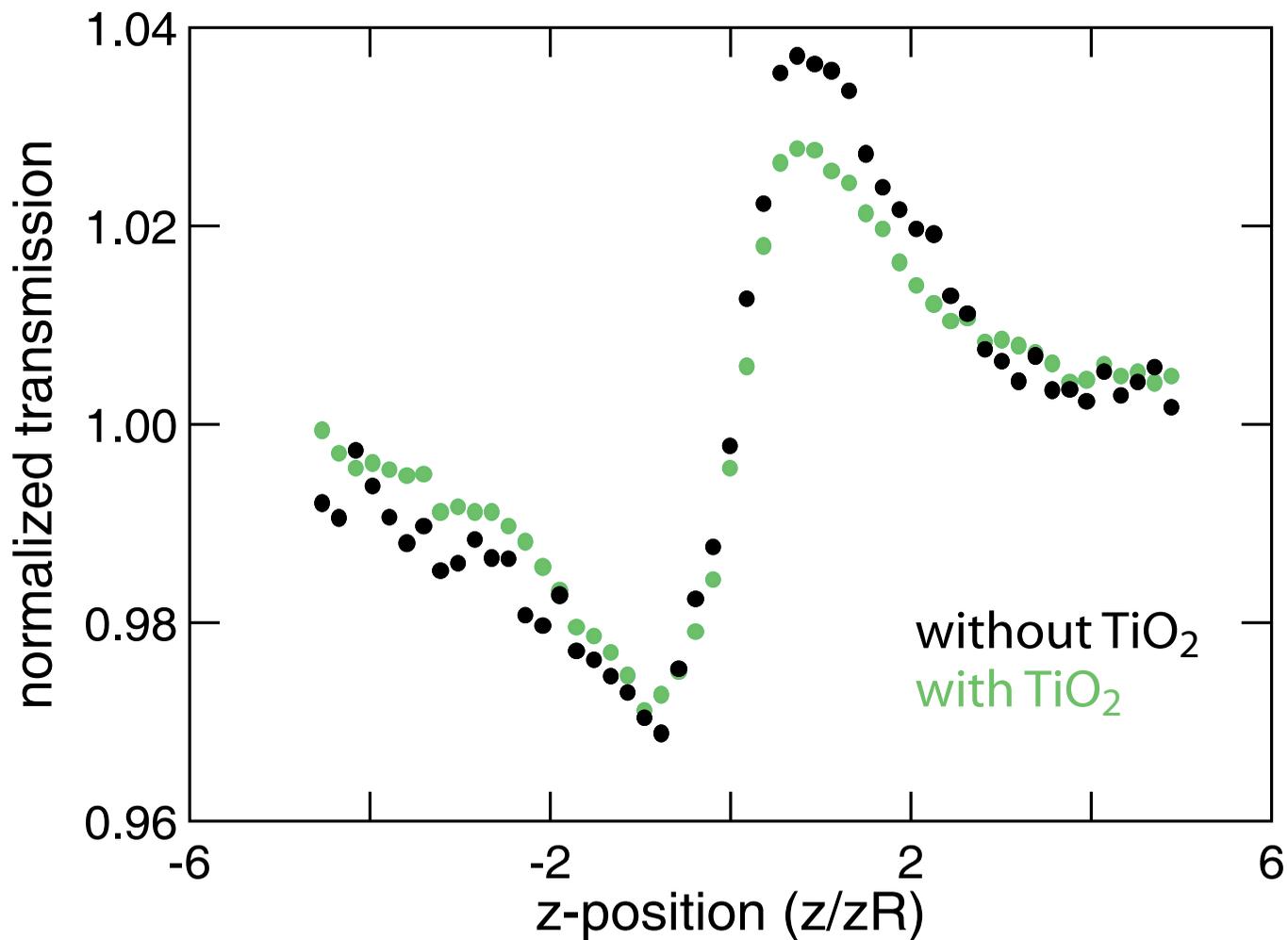
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Comparison with and without film



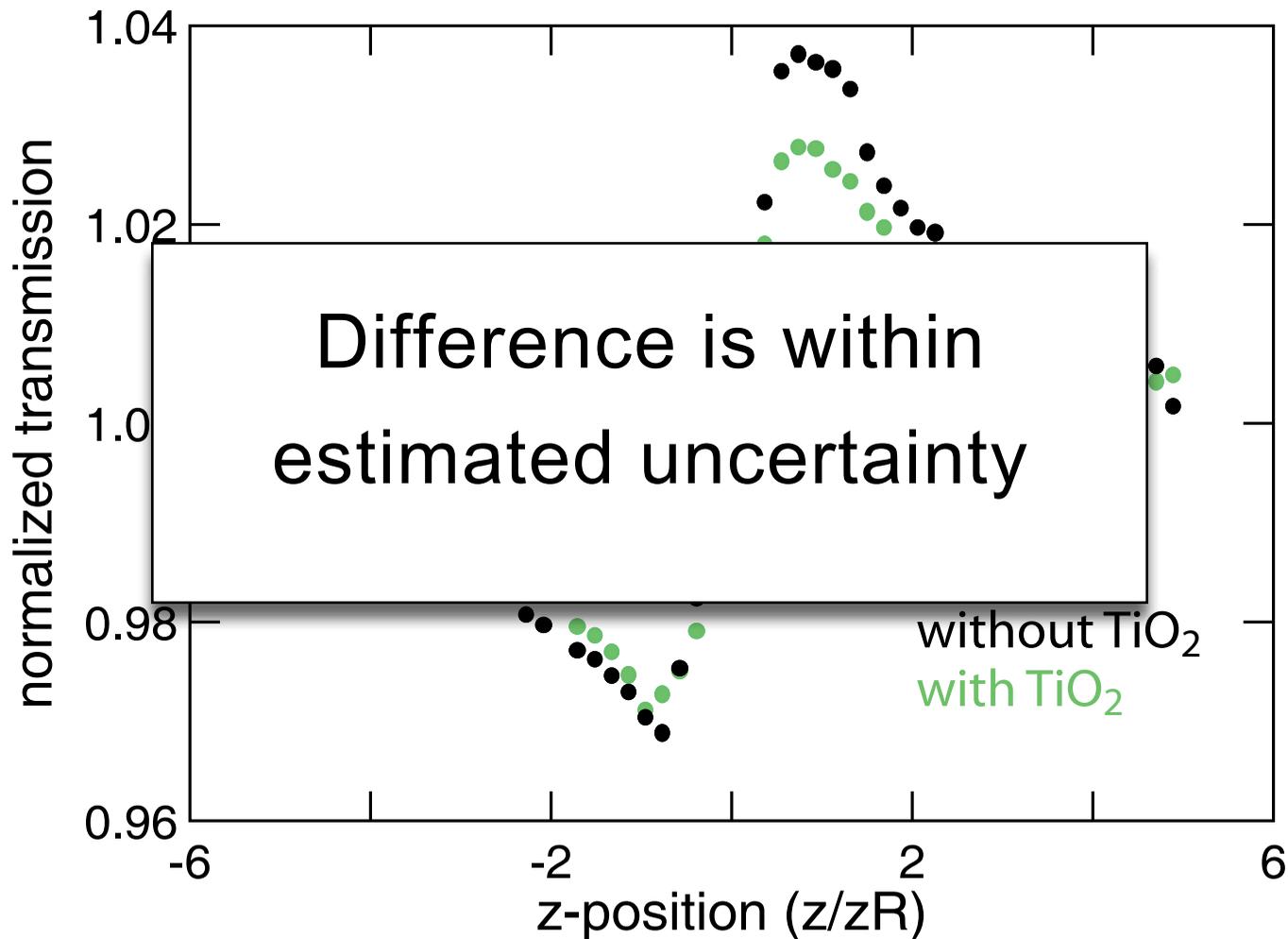
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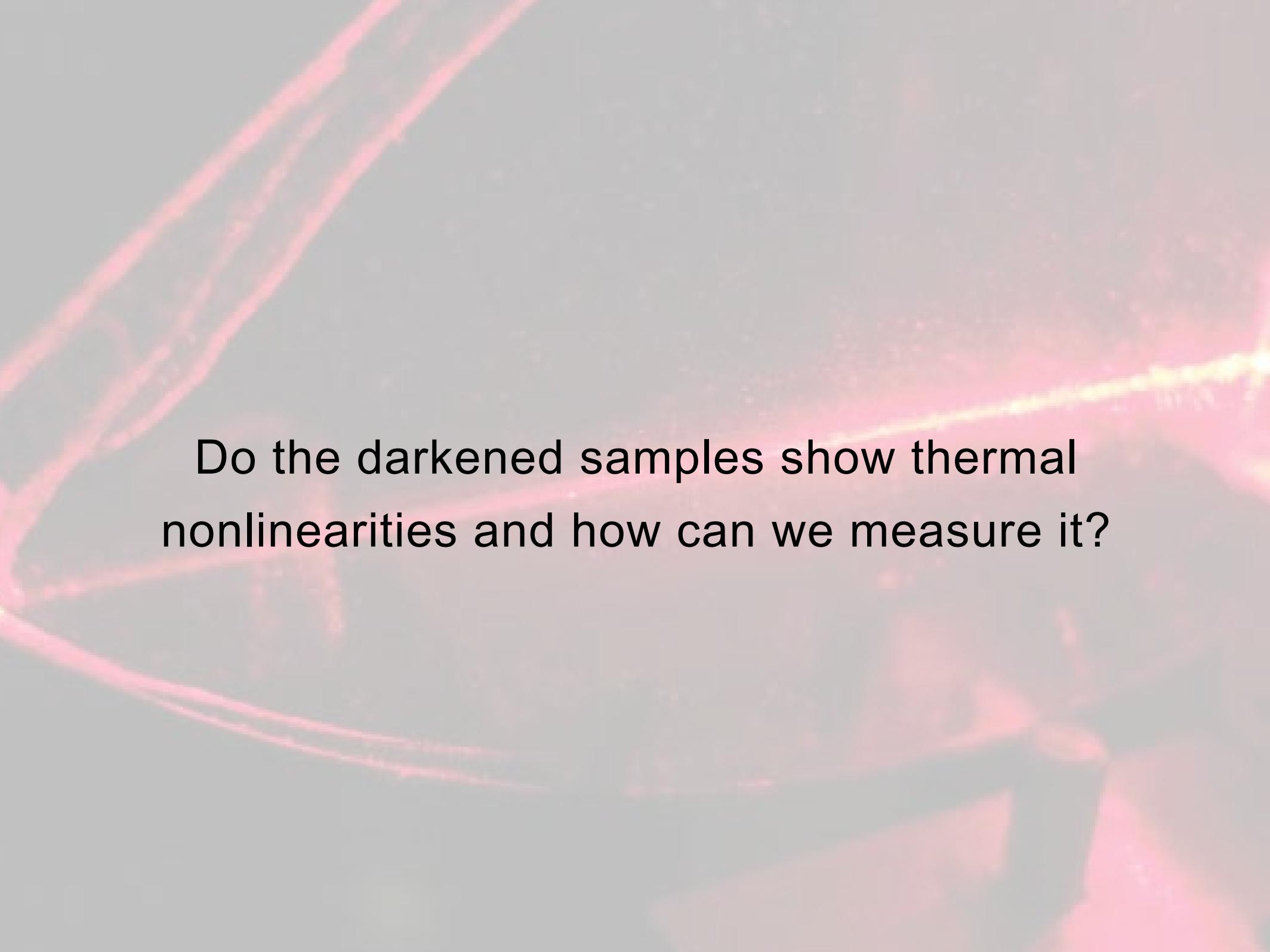
Comparison with and without film



# Standard z-scan

Comparison with and without film





Do the darkened samples show thermal nonlinearities and how can we measure it?

# Outline

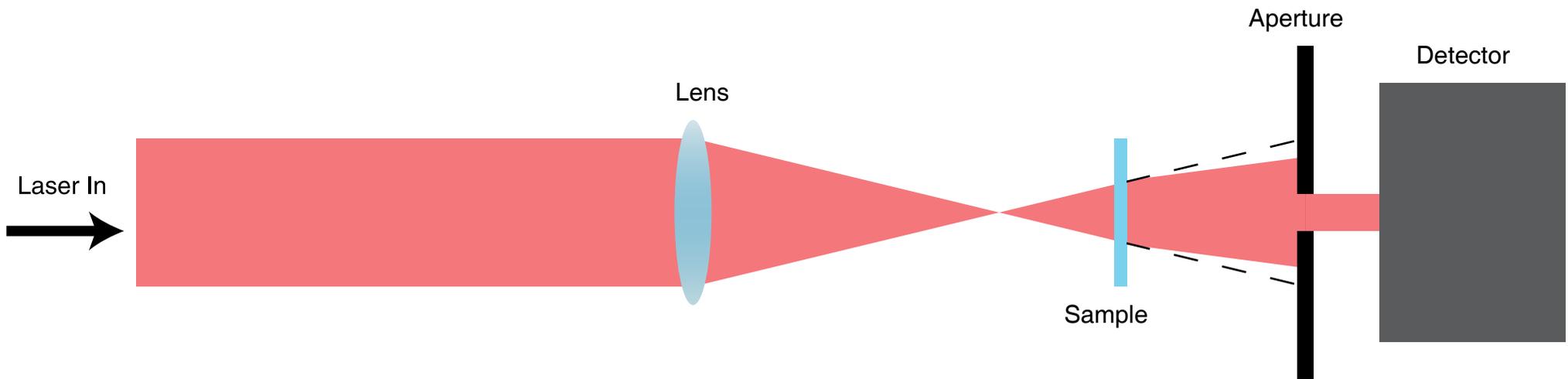
Introduction: amorphous TiO<sub>2</sub> films

Standard z-scan

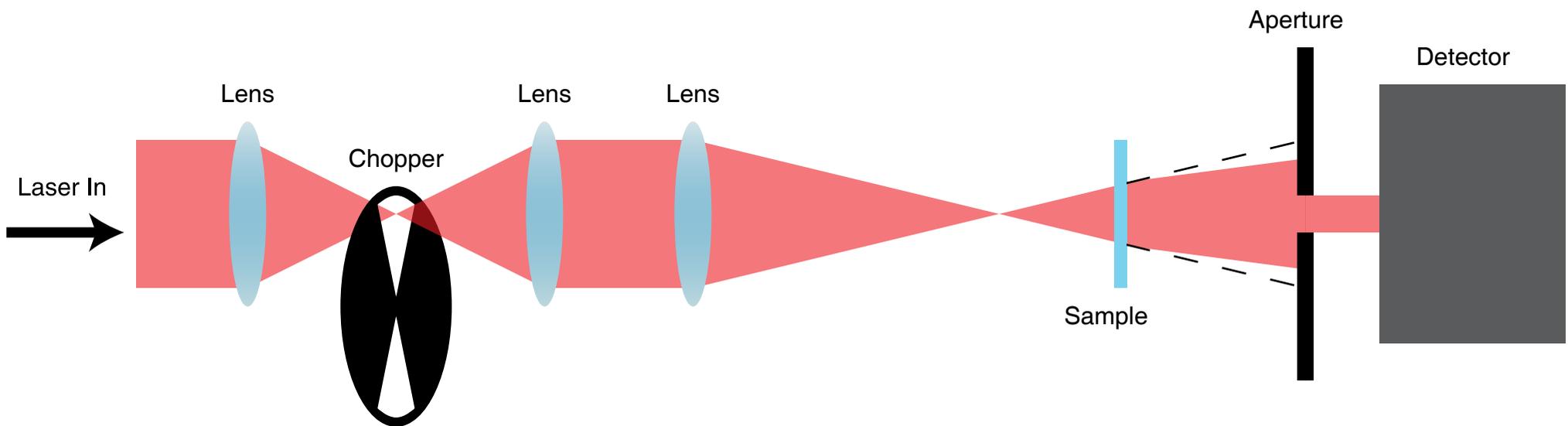
Thermally managed z-scan

Conclusions and Discussion

# Thermally Managed Z-Scan

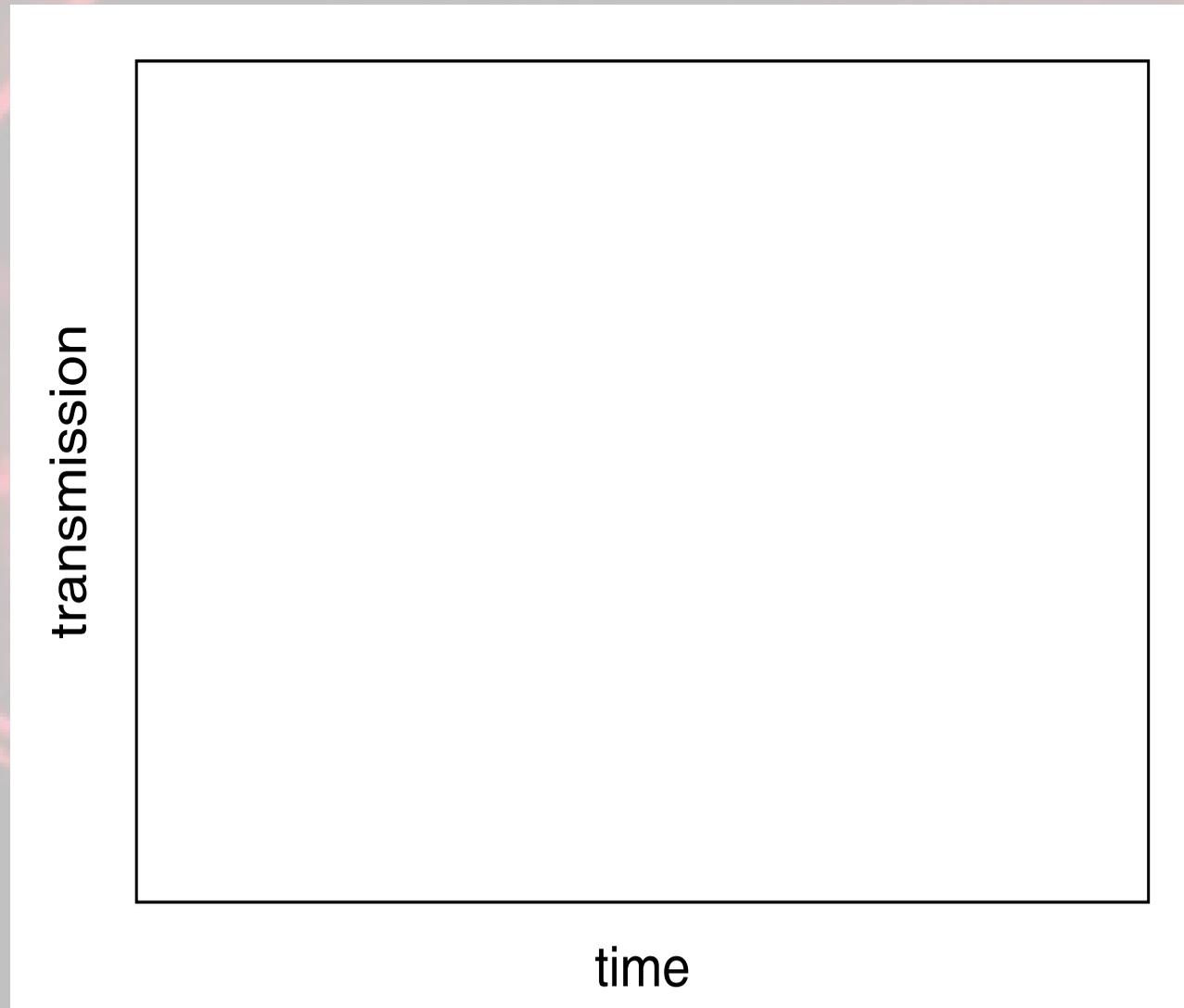


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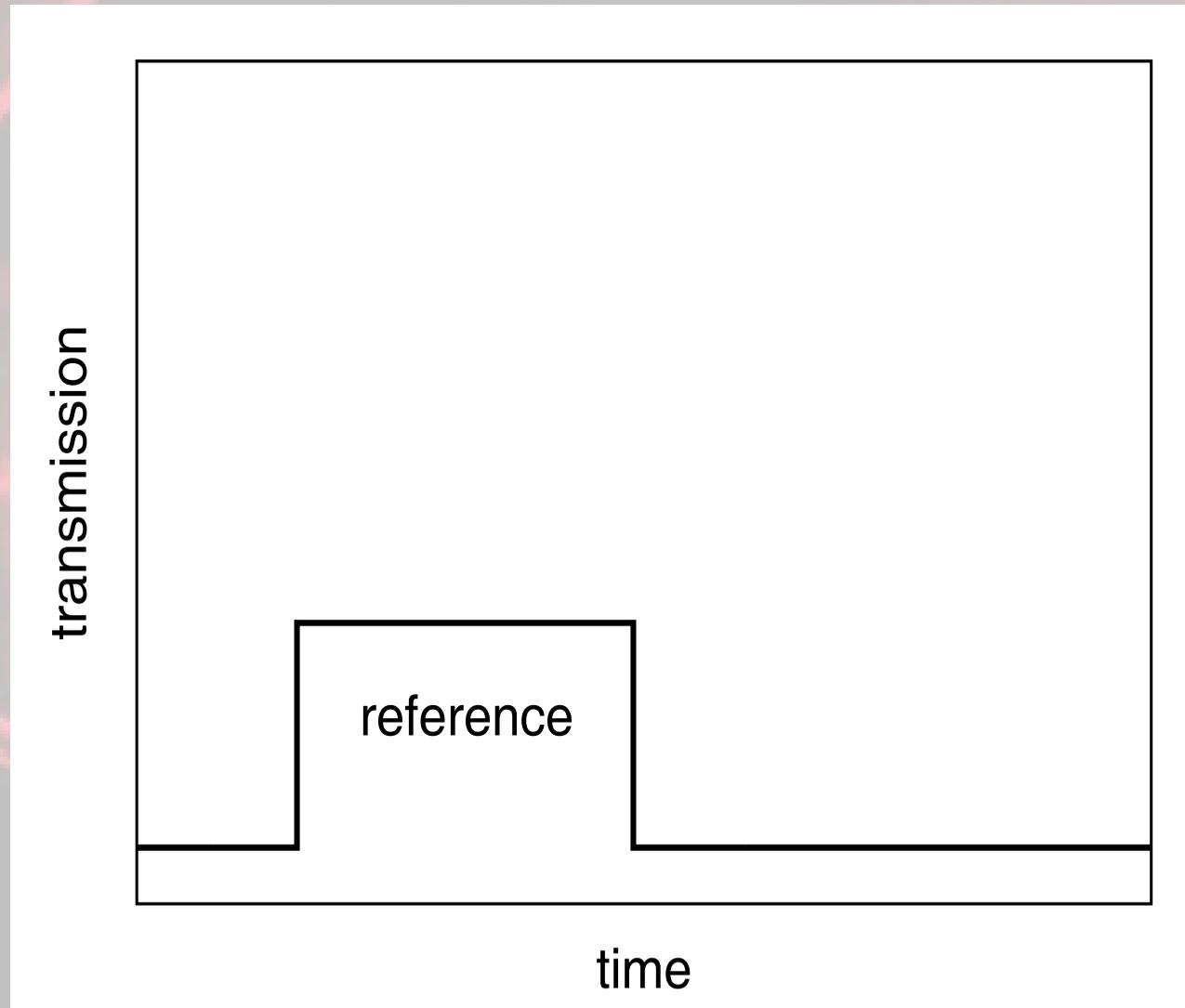
# Thermally Managed Z-Scan

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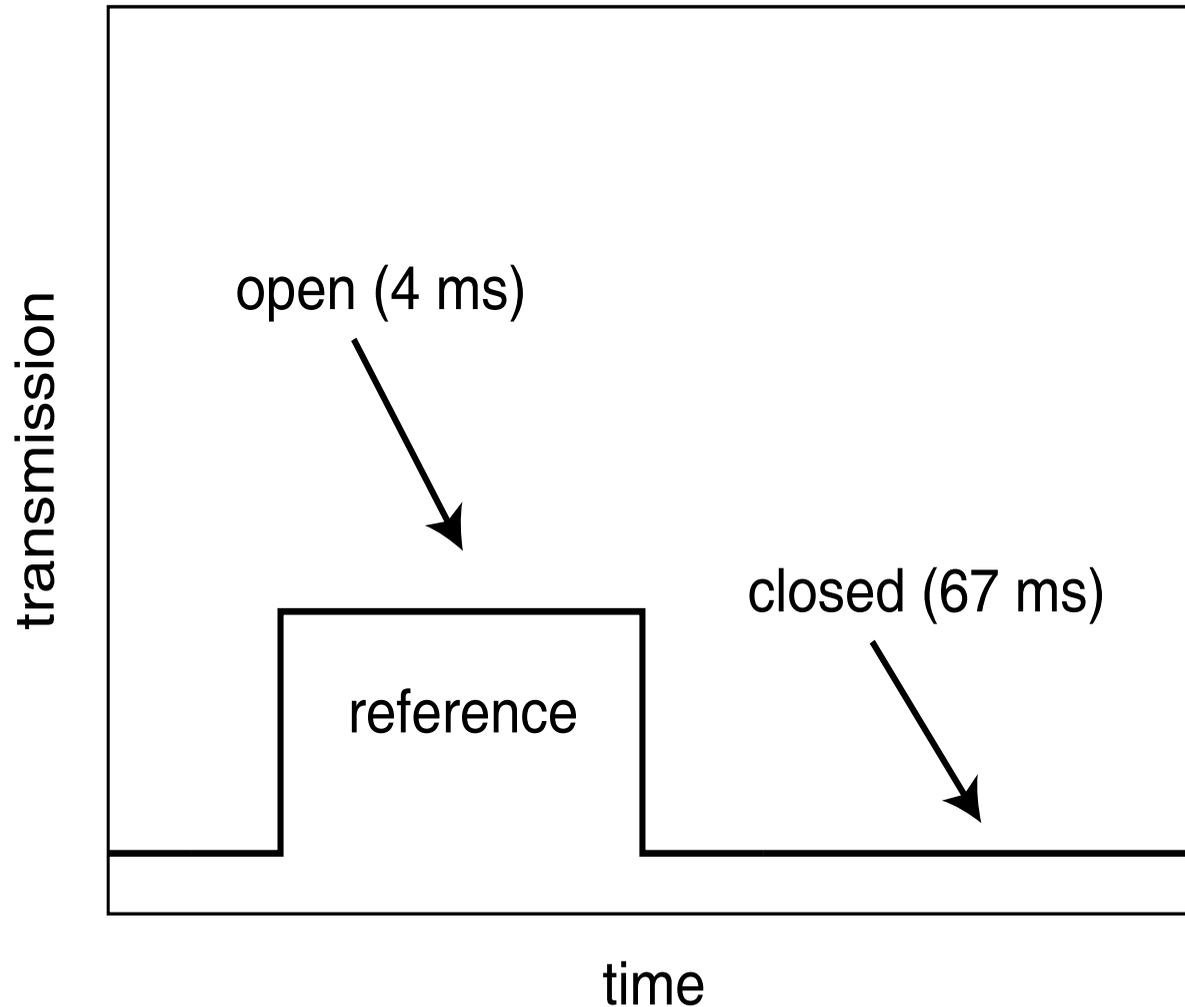
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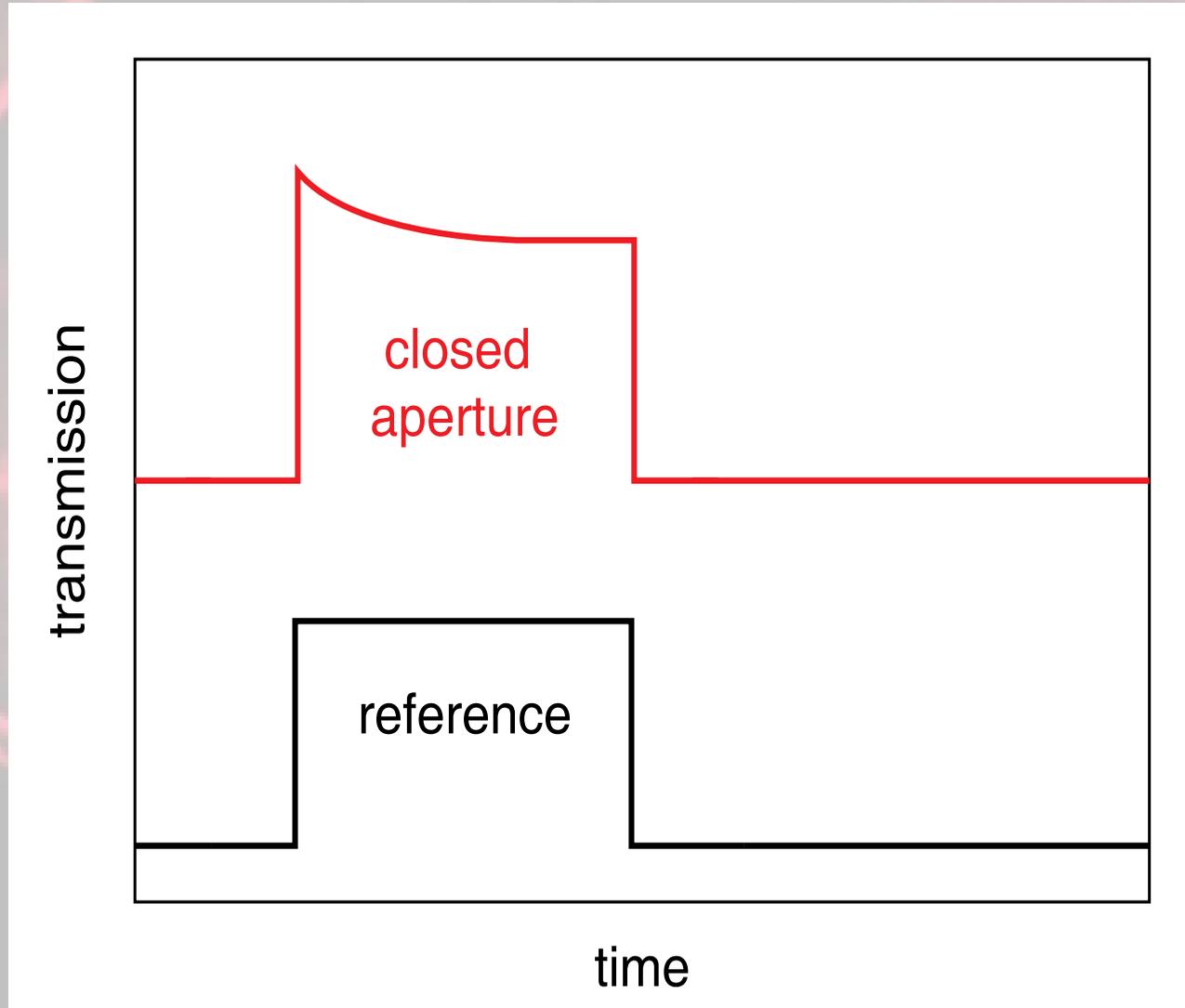
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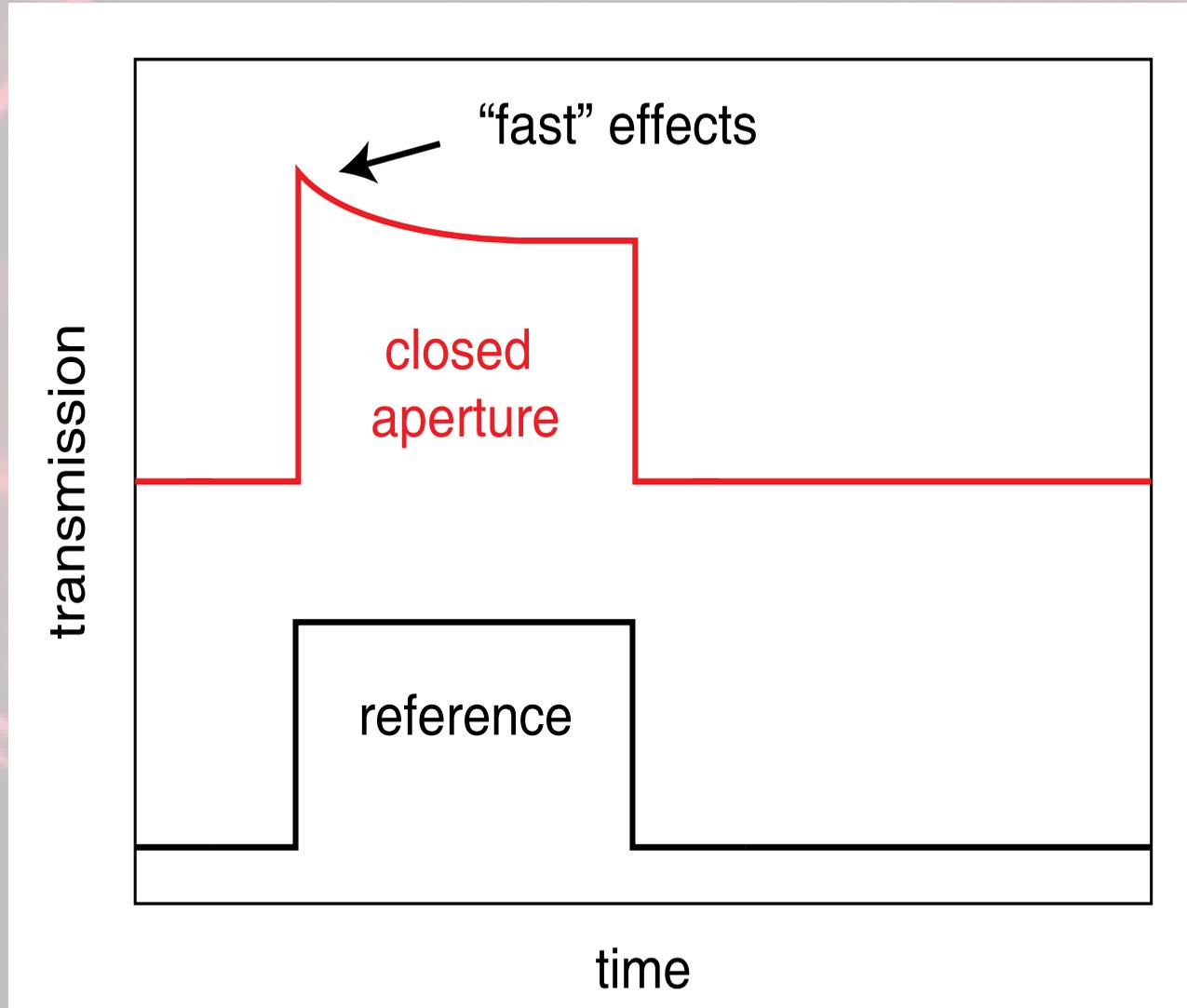
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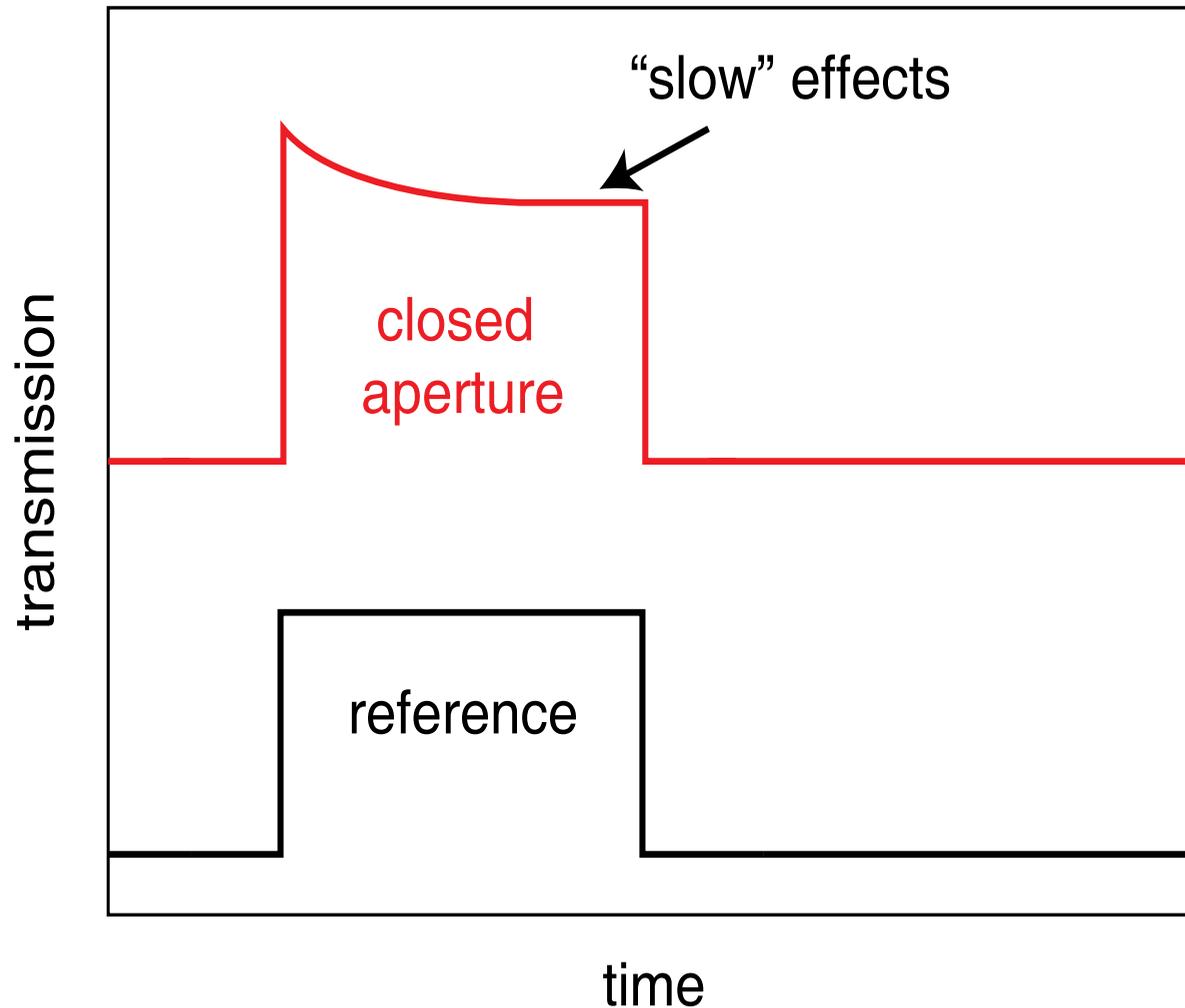
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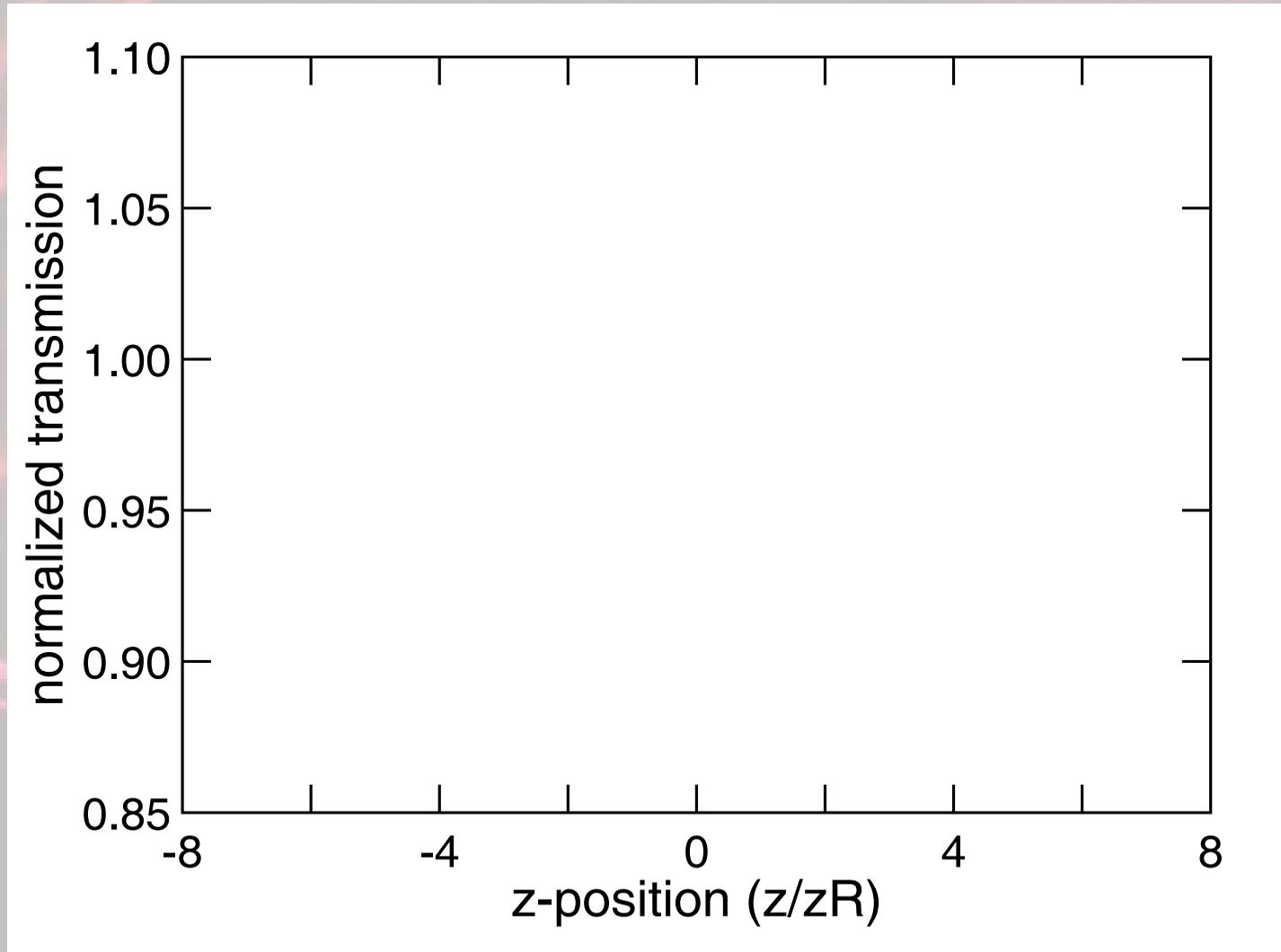
# Thermally Managed Z-Scan

## Laser Parameters

w0 (measured):	37 micron
zR (from fitting):	2.1 mm
Approximate M <sup>2</sup> :	1.8
<u>Repetition Rate:</u>	<u>250 kHz</u>
Pulse Duration:	100 fs
<u>Power Used:</u>	<u>300 mW</u>
Fluence:	0.06 J/cm <sup>2</sup>
S parameter:	0.016

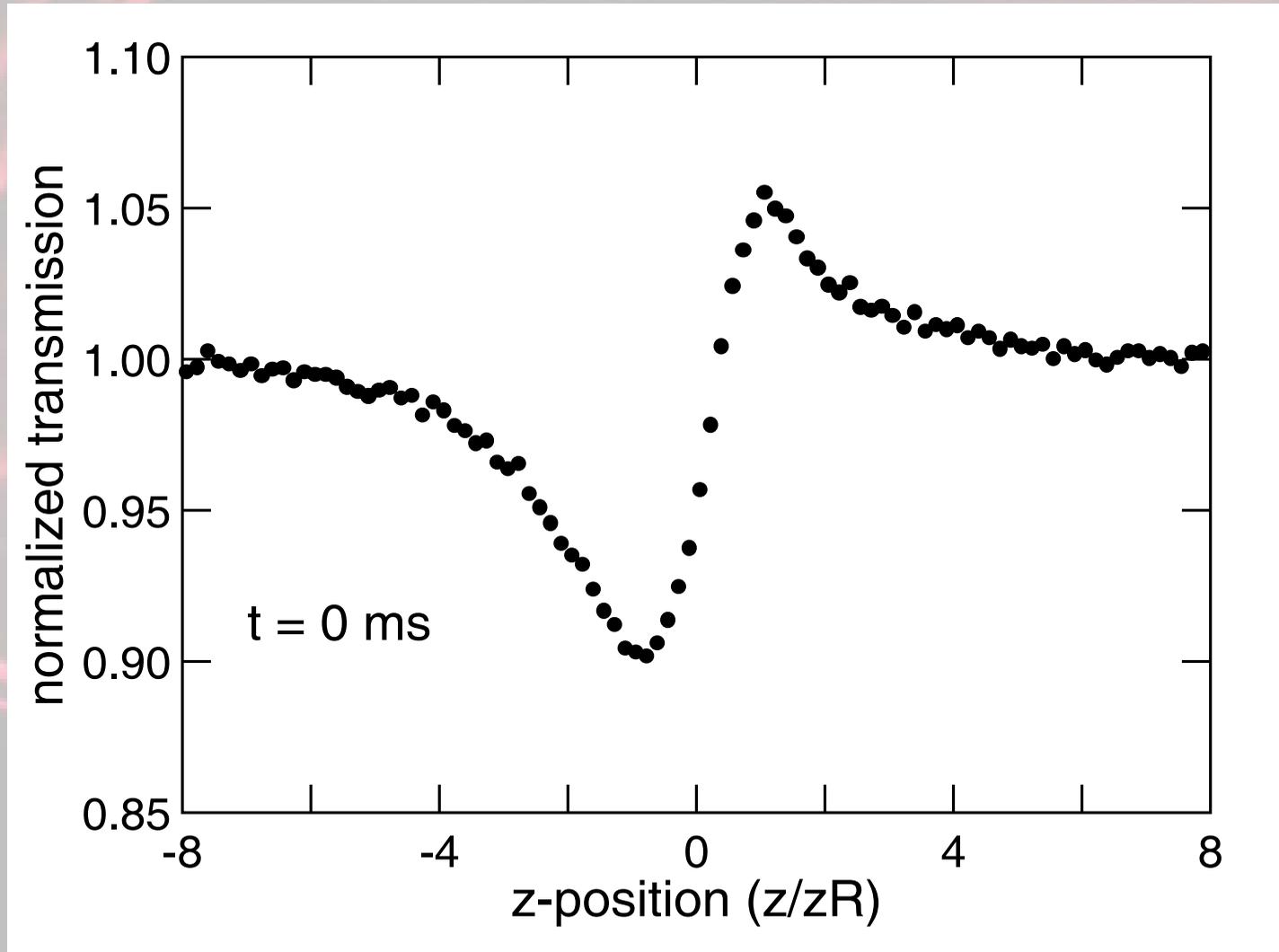
# Thermally Managed Z-Scan

Amorphous film at start of window



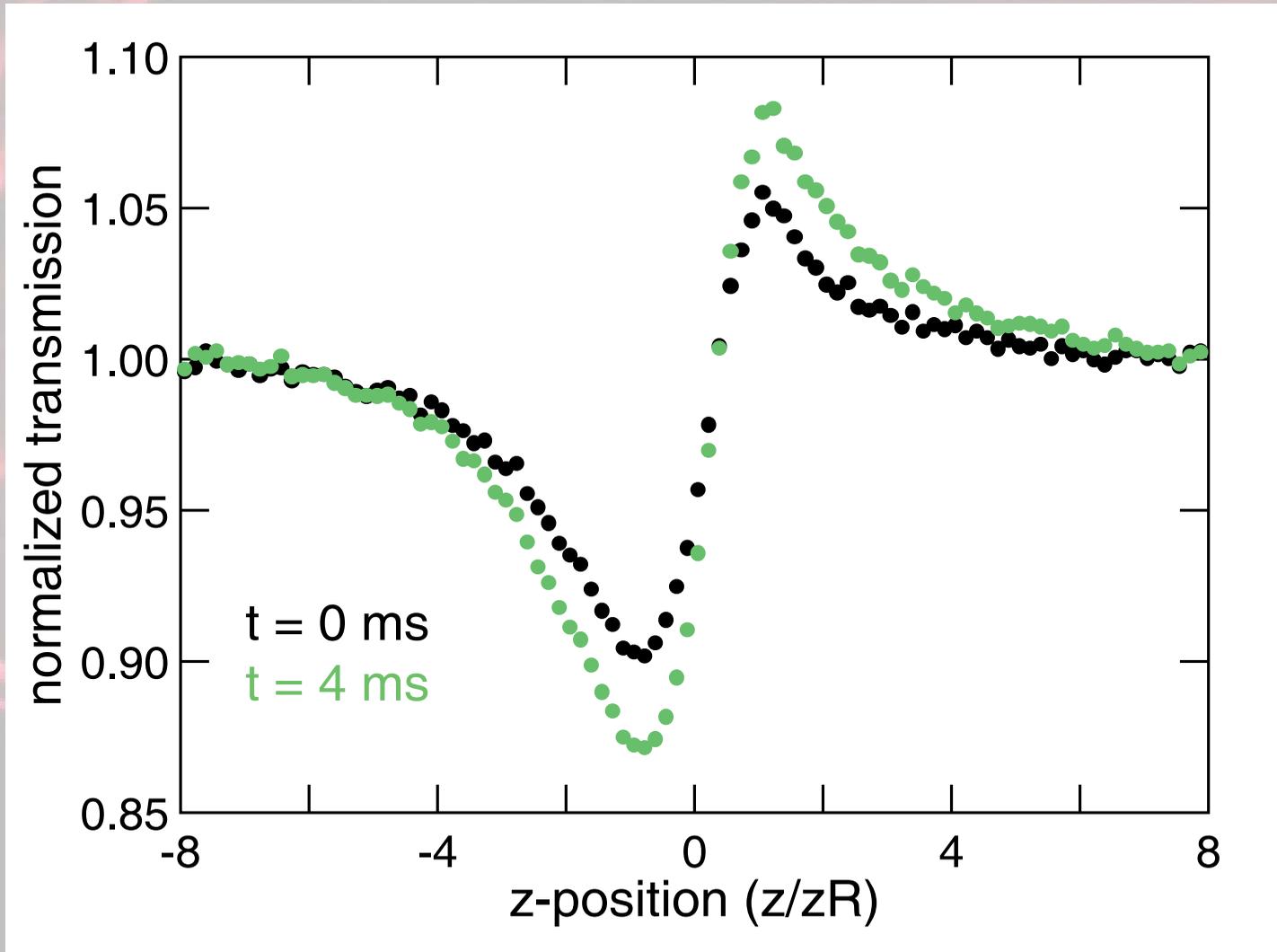
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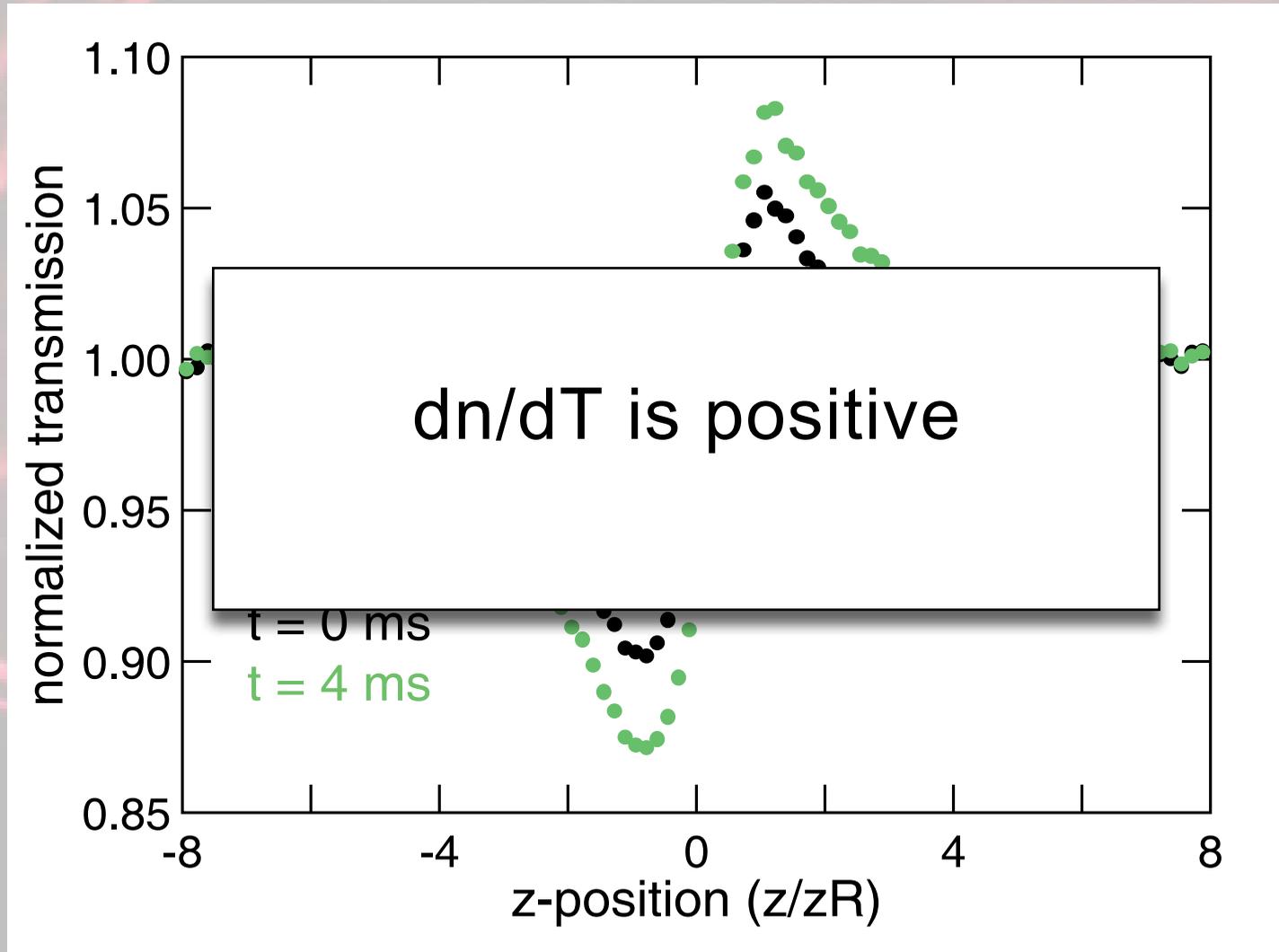
# Thermally Managed Z-Scan

Amorphous film at end of window



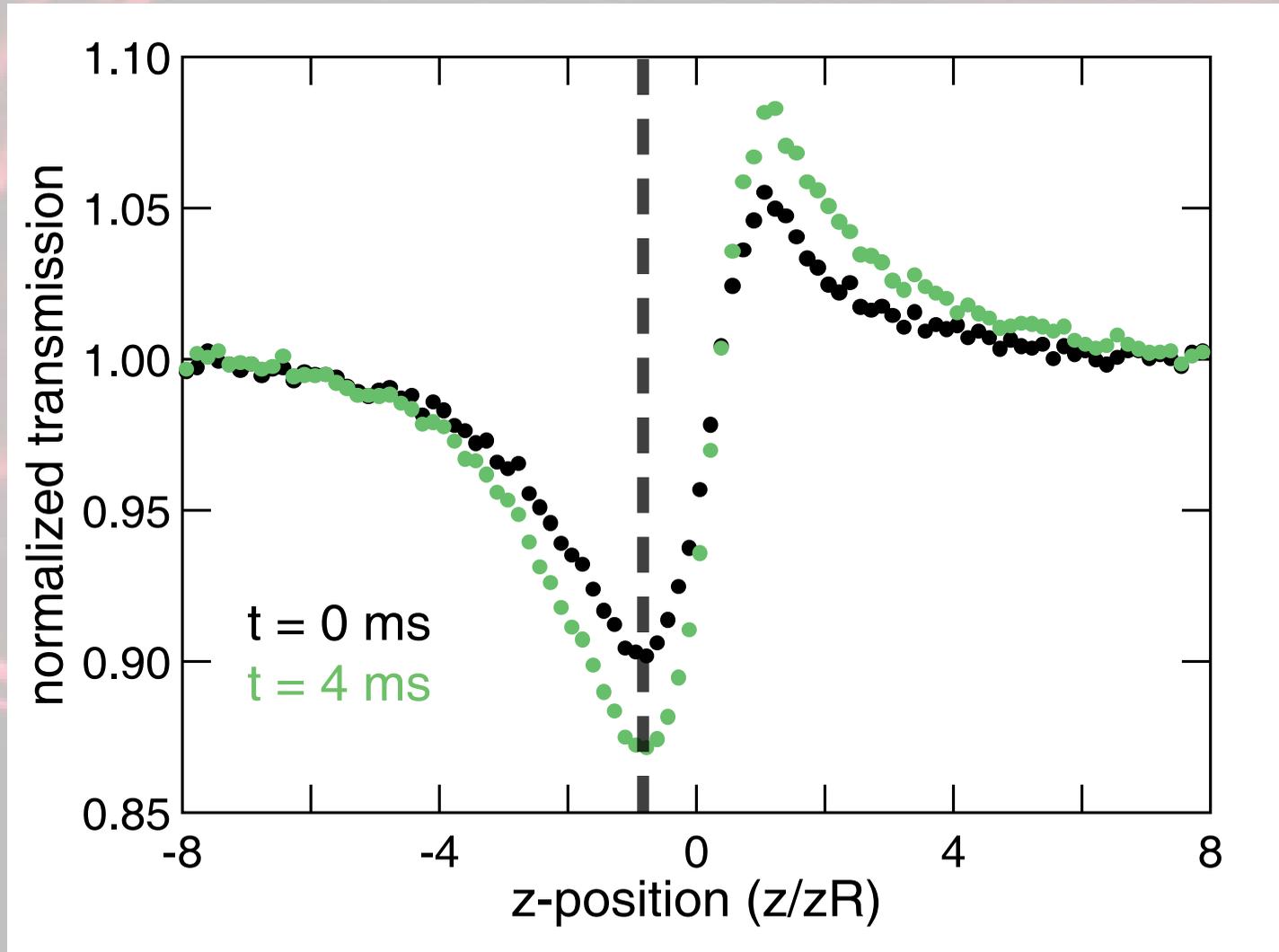
# Thermally Managed Z-Scan

Amorphous film at end of window



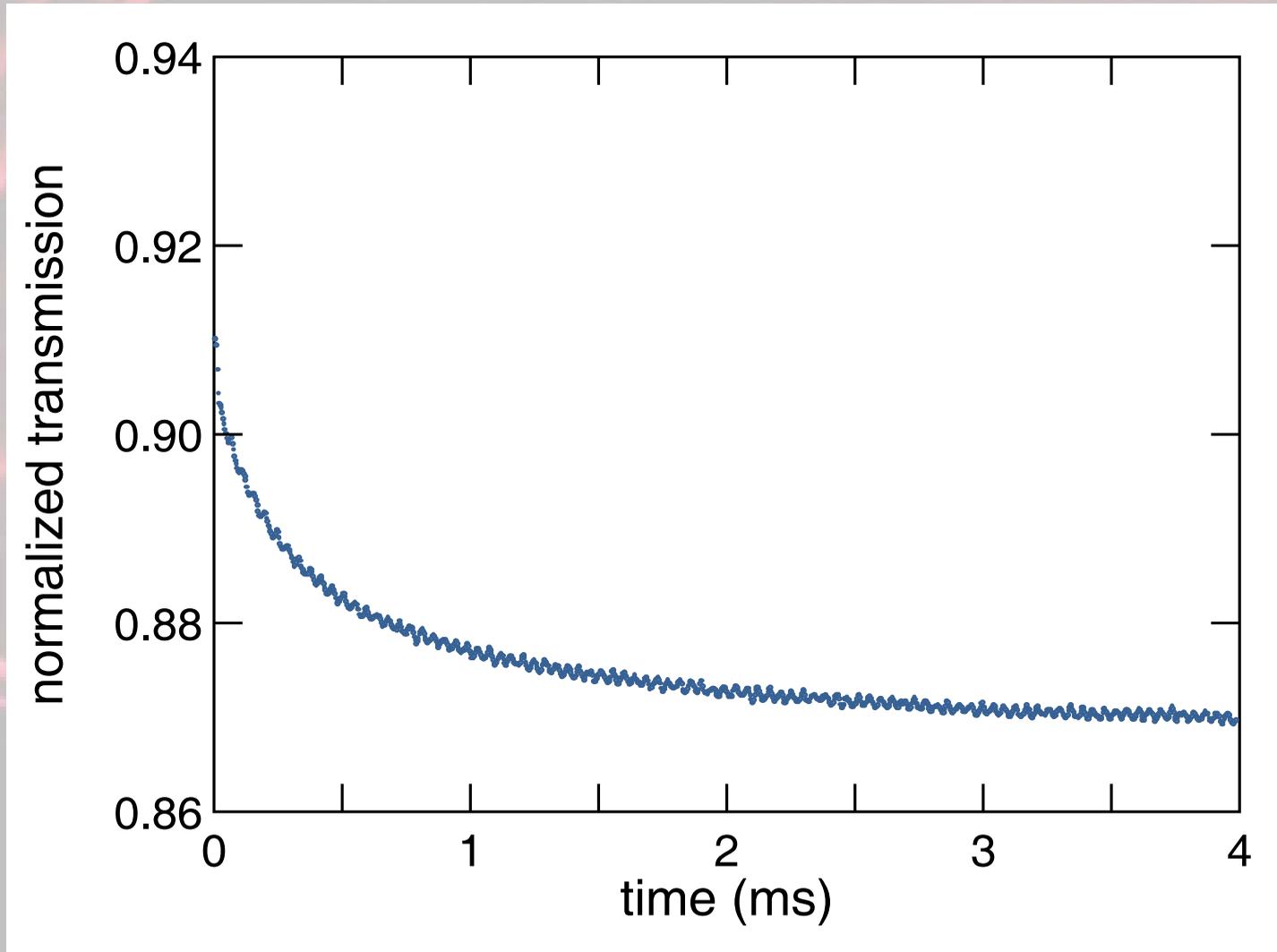
# Thermally Managed Z-Scan

## Prefocal Time Dependence



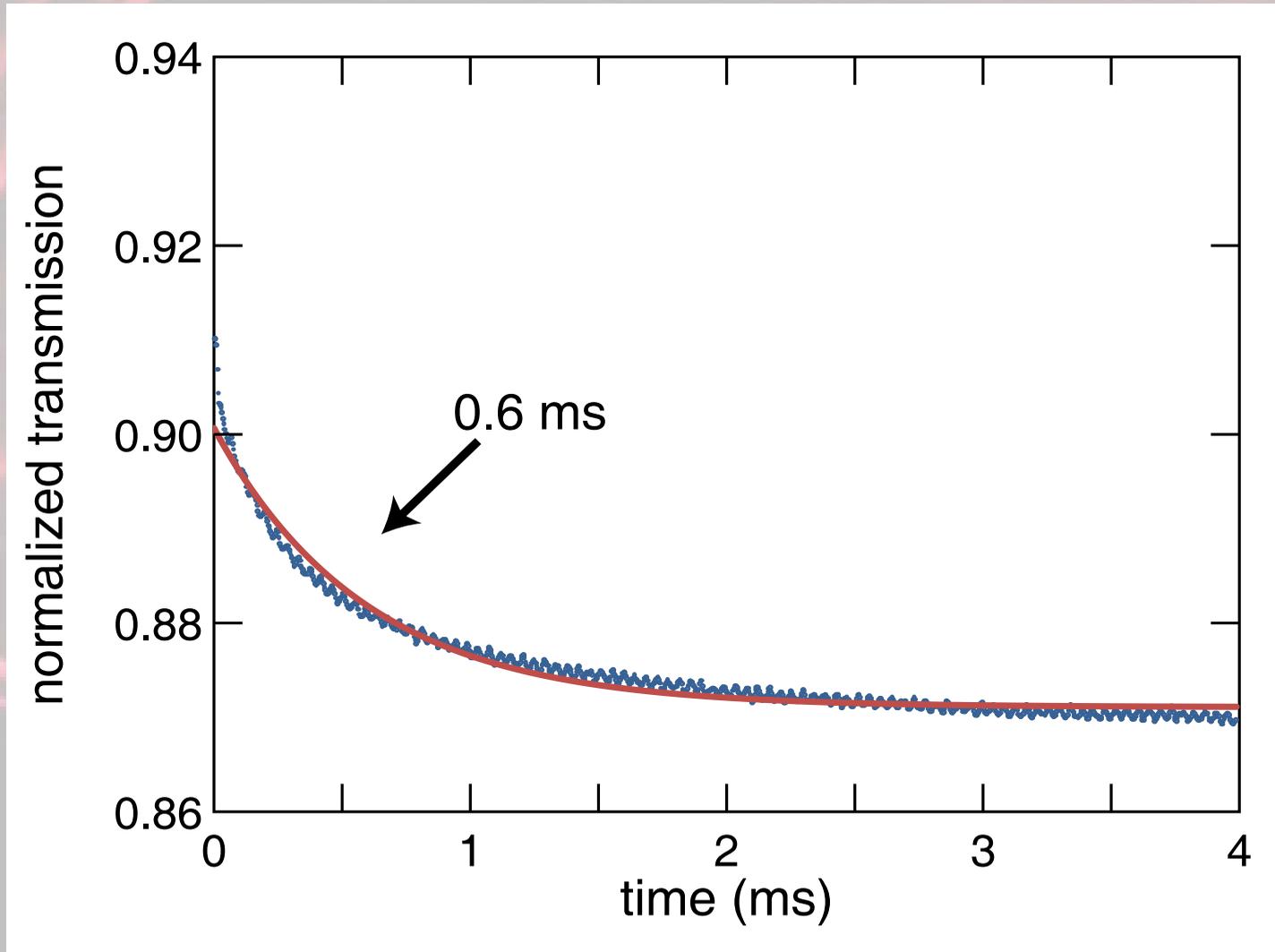
# Thermally Managed Z-Scan

## Prefocal Time Dependence



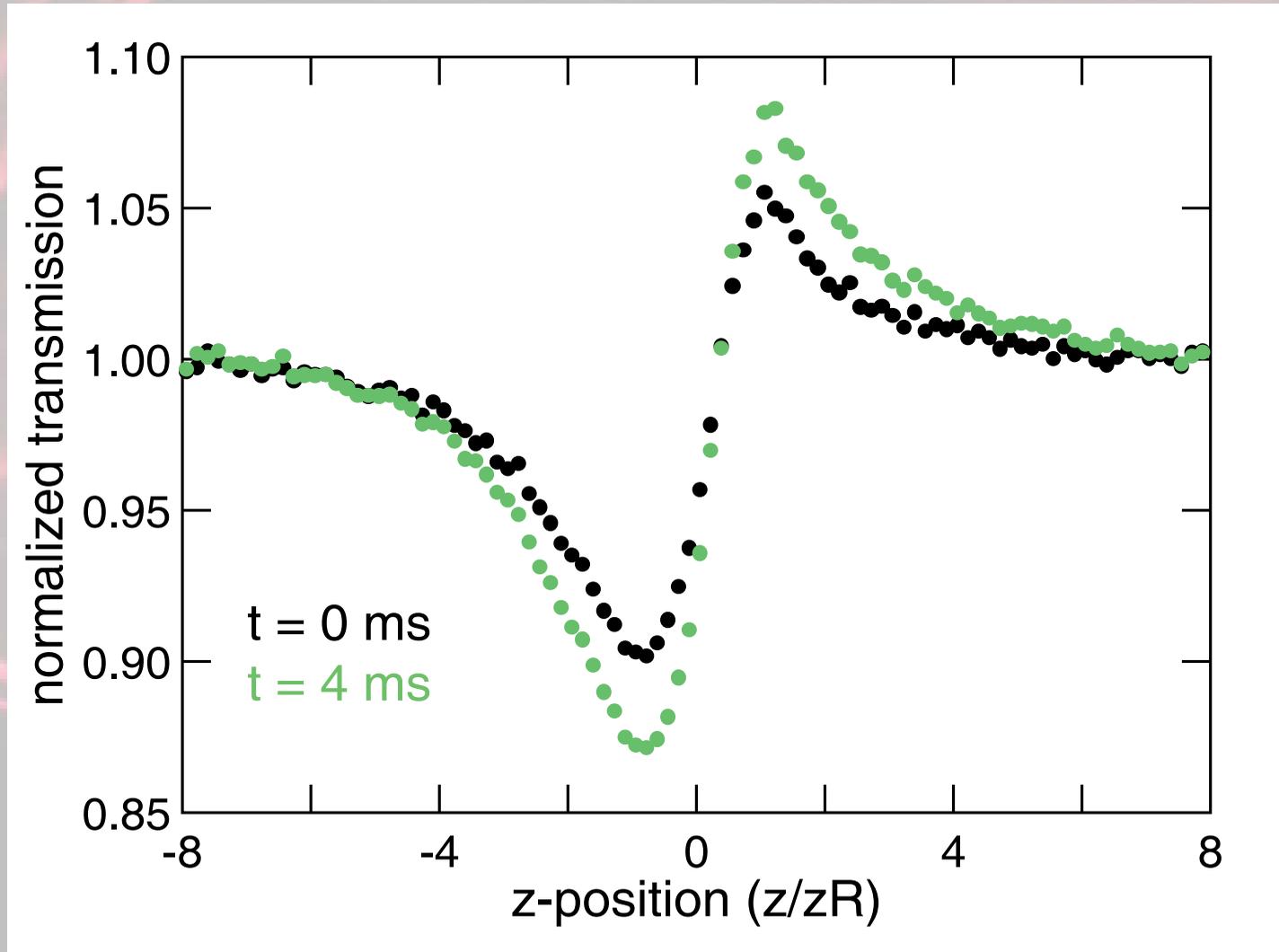
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## Prefocal Time Dependence



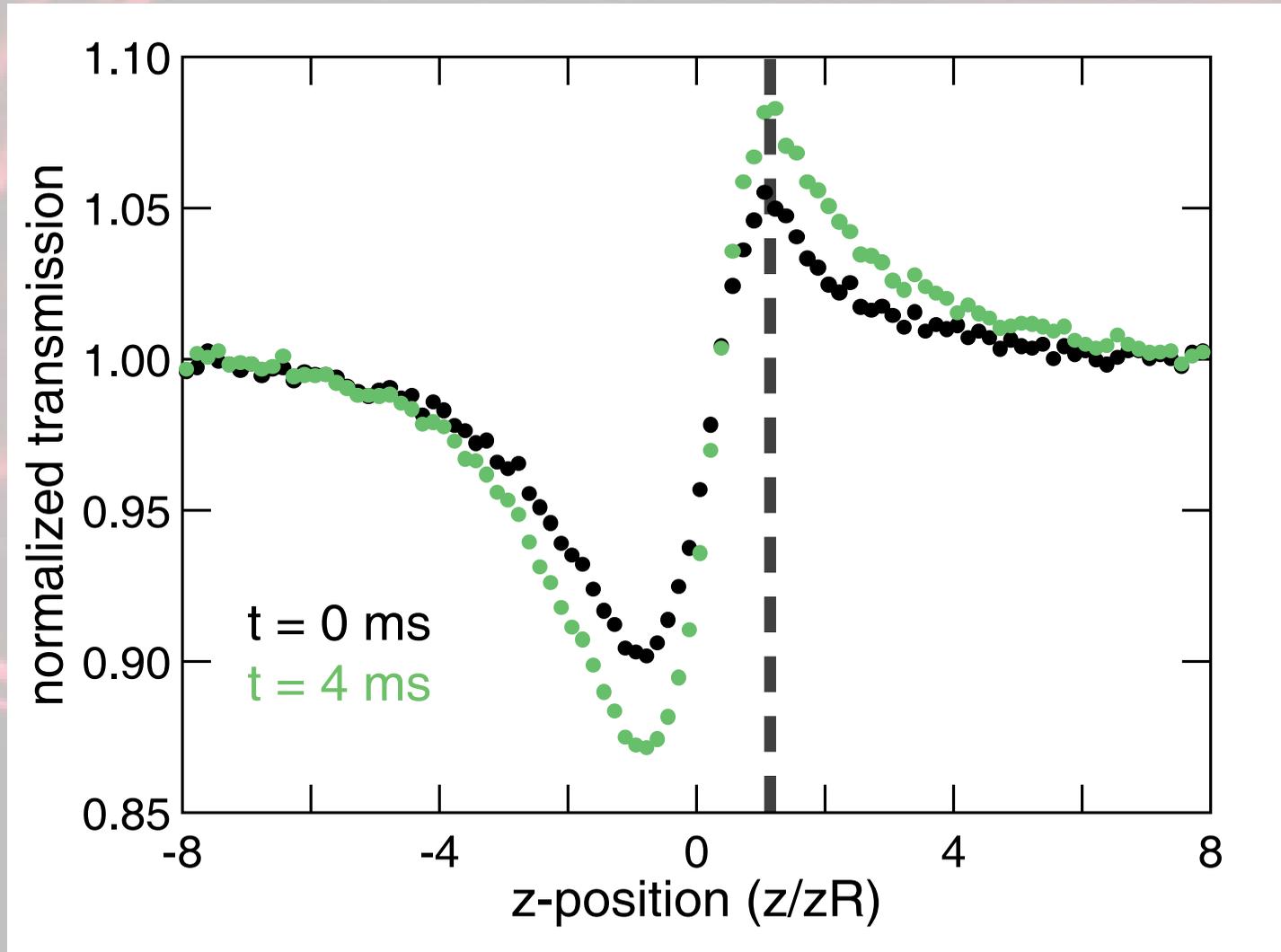
# Thermally Managed Z-Scan

## Postfocal Time Dependence



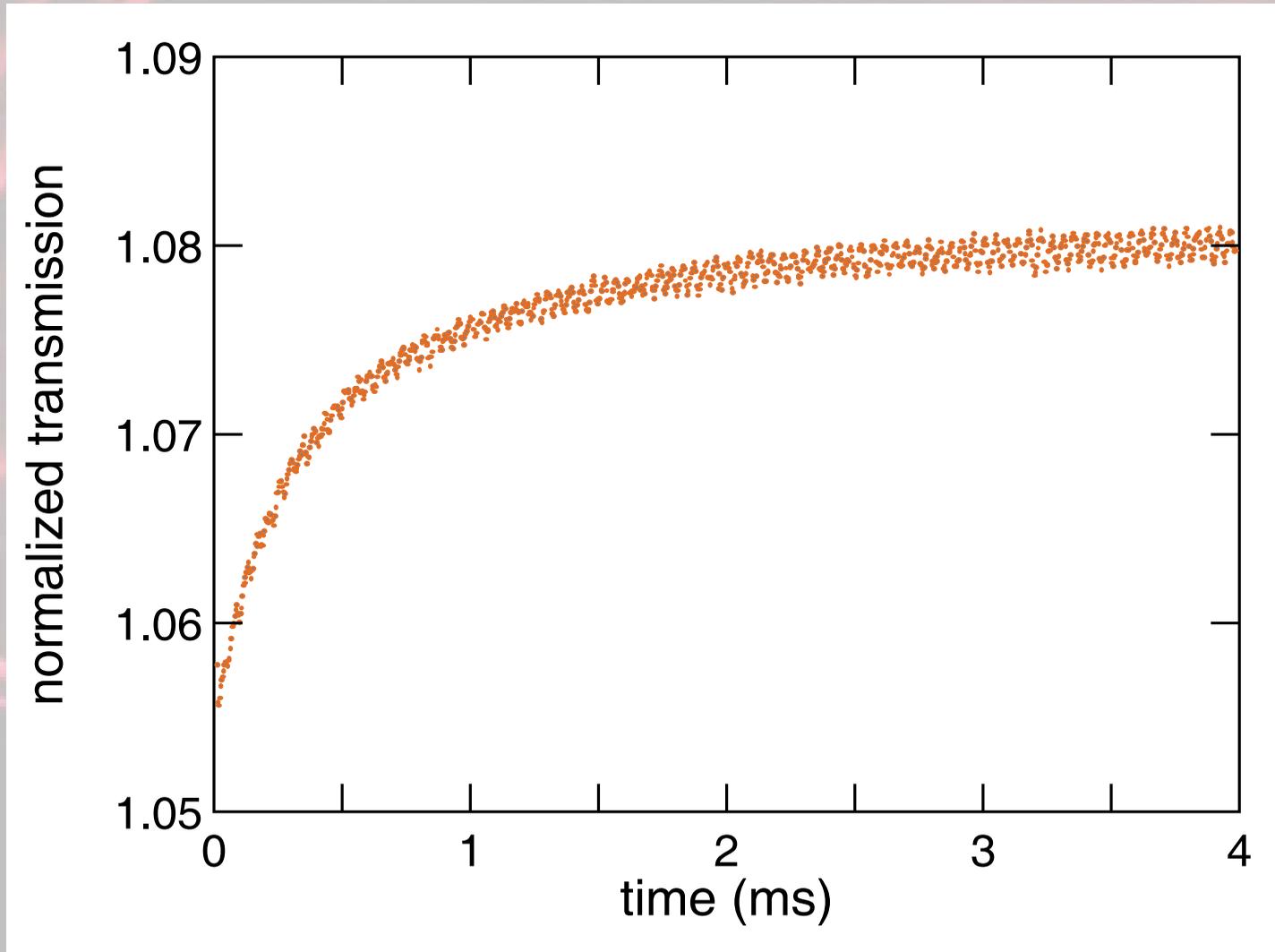
# Thermally Managed Z-Scan

## Postfocal Time Dependence



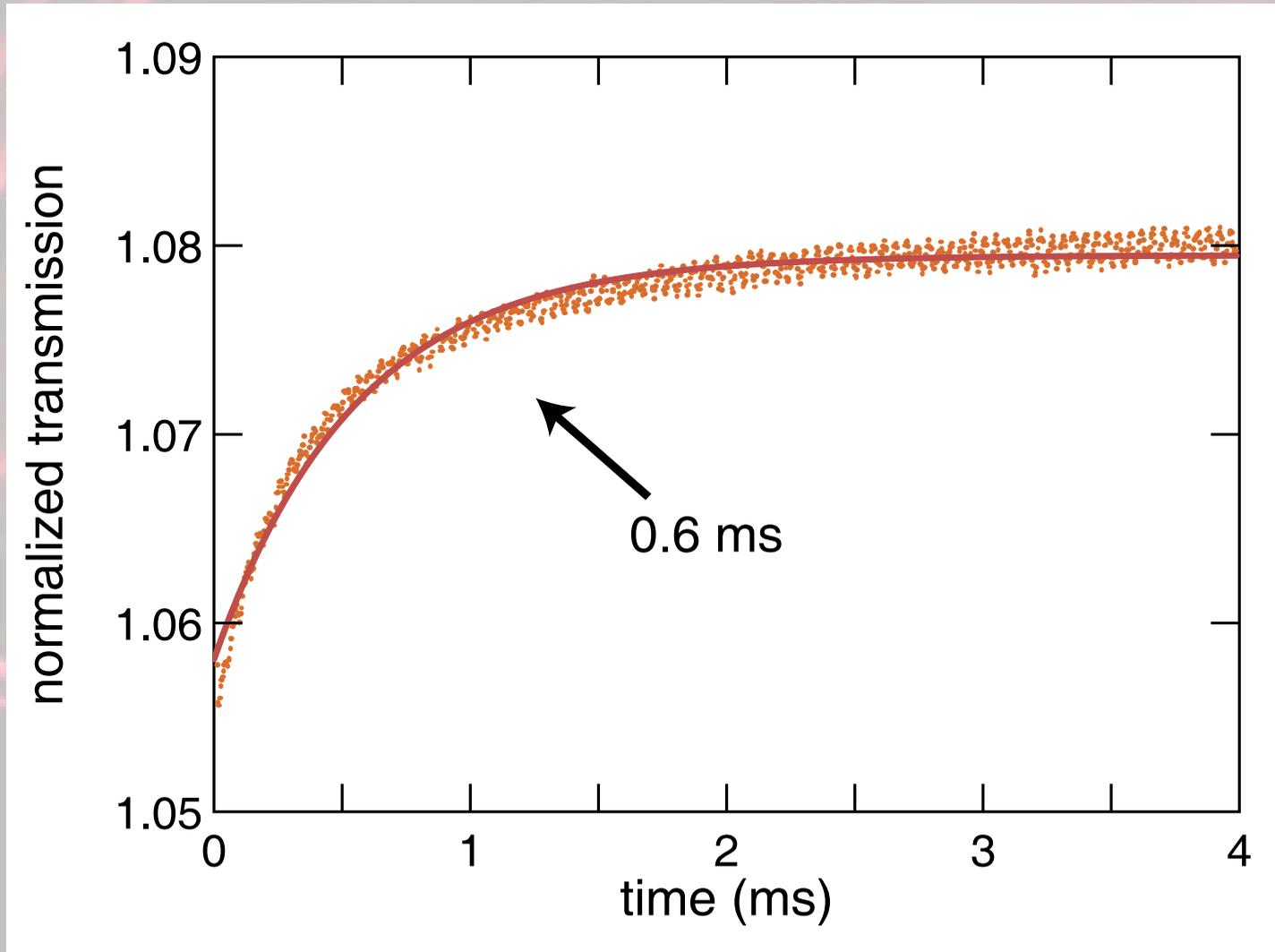
# Thermally Managed Z-Scan

## Postfocal Time Dependence



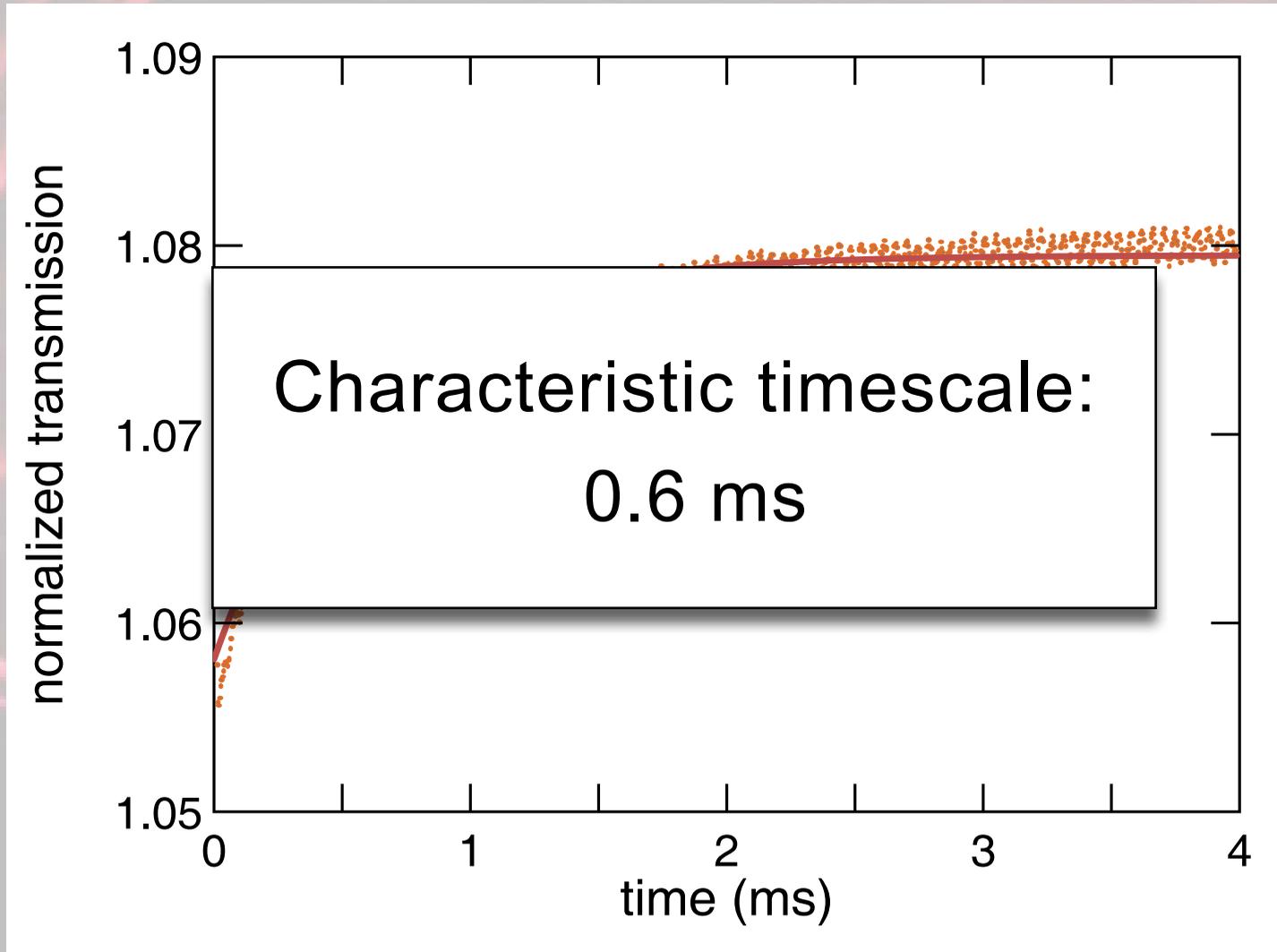
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## Postfocal Time Dependence



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## Postfocal Time Dependence



# Conclusions



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As-deposited Amorphous Films

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Short: 5.8 minutes

Longer: 32 hours

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Sensitive to light exposure

Darkening occurs on two time scale:

Short: 5.8 minutes

Longer: 32 hours

Does not recover after 12 hours

# Conclusions

Darkened Films



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## Darkened Films

Nonlinearity is within the uncertainty

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Thermal nonlinearity ( $dn/dT$ ) is positive

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## Darkened Films

Nonlinearity is within the uncertainty

Thermal nonlinearity ( $dn/dT$ ) is positive

Thermal response time is 0.6 ms

# Discussion

TiO<sub>2</sub> is a promising nonlinear material

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Amorphous films:

Adapted z-scan to measure  $n_2$

Processing to enhance/avoid darkening

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TiO<sub>2</sub> is a promising nonlinear material

Amorphous films:

- Adapted z-scan to measure  $n_2$

- Processing to enhance/avoid darkening

Darkened films require further study to:

- Understand process of darkening

- Explore properties of darkened samples

# Acknowledgements

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